FemtoClock® NG Octal Universal Frequency Translator

IDT8T49N282I

DATA SHEET

General Description

The IDT8T49N282I has two independent, fractional-feedback PLLs that can be used as jitter attenuators and frequency translators. It is equipped with six integer and two fractional output dividers, allowing the generation of up to eight different output frequencies, ranging from 8kHz to 1GHz. Four of these frequencies are completely independent of each other and the inputs. The other four are related frequencies. The eight outputs may select among LVPECL, LVDS or LVCMOS output levels.

This functionality makes it ideal to be used in any frequency translation application, including 1G, 10G, 40G and 100G Synchronous Ethernet, OTN, and SONET/SDH, including ITU-T G.709 (2009) FEC rates. The device may also behave as a frequency synthesizer.

The IDT8T49N282I accepts up to four differential or single-ended input clocks and a crystal input. Each of the two internal PLLs can lock to different input clocks which may be of independent frequencies. The other two input clocks are intended for redundant backup of the primary clocks and must be related in frequency to their primary.

The device supports hitless reference switching between input clocks. The device monitors all input clocks for Loss of Signal (LOS), and generates an alarm when an input clock failure is detected. Automatic and manual hitless reference switching options are supported. LOS behavior can be set to support gapped or un-gapped clocks.

The IDT8T49N282I supports holdover for each PLL. The holdover has an initial accuracy of ±50ppB from the point where the loss of all applicable input reference(s) has been detected. It maintains a historical average operating point for each PLL that may be returned to in holdover at a limited phase slope.

The device places no constraints on input to output frequency conversion, supporting all FEC rates, including the new revision of ITU-T Recommendation G.709 (2009), most with 0ppm conversion error.

Each PLL has a register-selectable loop bandwidth from 0.5Hz to 512Hz.

Each output supports individual phase delay settings to allow output-output alignment.

The device supports Output Enable inputs and Lock, Holdover and LOS status outputs.

The device is programmable through an I^2C interface. It also supports I^2C master capability to allow the register configuration to be read from an external EEPROM. The user may select whether the programming interface uses I^2C protocols or SPI protocols, however in SPI mode, read from the external EEPROM is not supported.

Applications

- OTN or SONET / SDH equipment Line cards (up to OC-192, and supporting FEC ratios)
- OTN de-mapping (Gapped Clock and DCO mode)
- Gigabit and Terabit IP switches / routers including support of Synchronous Ethernet
- Wireless base station baseband
- Data communications

Features

- Supports SDH/SONET and Synchronous Ethernet clocks including all FEC rate conversions
- Two differential outputs meet jitter limits for 100G Ethernet and STM-256/OC-768
  - <0.3ps RMS (including spurs): 12kHz to 20MHz
- All outputs <0.5ps RMS (including spurs) 12kHz to 20MHz
- Operating modes: locked to input signal, holdover and free-run
- Initial holdover accuracy of ±50ppb
- Accepts up to four LVPECL, LVDS, LVHSTL, HCSL or LVCMOS input clocks
  - Accepts frequencies ranging from 8kHz up to 875MHz
  - Auto and manual input clock selection with hitless switching
  - Clock input monitoring, including support for gapped clocks
- Phase-Slope Limiting and Fully Hitless Switching options to control output phase transients
- Operates from a 10MHz to 40MHz fundamental-mode crystal
- Generates eight LVPECL / LVDS or 16 LVCMOS output clocks
  - Output frequencies ranging from 8kHz up to 1.0GHz (diff)
  - Output frequencies ranging from 8kHz to 250MHz (LVCMOS)
- Eight General Purpose I/O pins with optional support for status and control
  - Eight Output Enable control inputs
  - Lock, Holdover and Loss-of-Signal status outputs
- Open-drain Interrupt pin
- Write-protect pin to prevent configuration registers being altered
- Programmable PLL bandwidth settings for each PLL:
  - 0.5Hz, 1Hz, 2Hz, 4Hz, 8Hz, 16Hz, 32Hz, 64Hz, 128Hz, 256Hz or 512Hz
  - Optional Fast Lock function
- Programmable output phase delays in steps as small as 16ps
- Register programmable through I^2C / SPI or via external I^2C EEPROM
- Bypass clock paths for system tests
- Power supply modes:
  V_{CC} / V_{CCA} / V_{CCO}
  3.3V / 3.3V / 3.3V
  3.3V / 3.3V / 2.5V
  3.3V / 3.3V / 1.8V (LVCMOS)
  2.5V / 2.5V / 3.3V
  2.5V / 2.5V / 2.5V
  2.5V / 2.5V / 1.8V (LVCMOS)
- Power down modes support consumption as low as 1.7W (see *Power Dissipation and Thermal Considerations section* for details)
- -40°C to 85°C ambient operating temperature
- Package: 72QFN, lead-free RoHs (6)

IDT8T49N282I Block Diagram

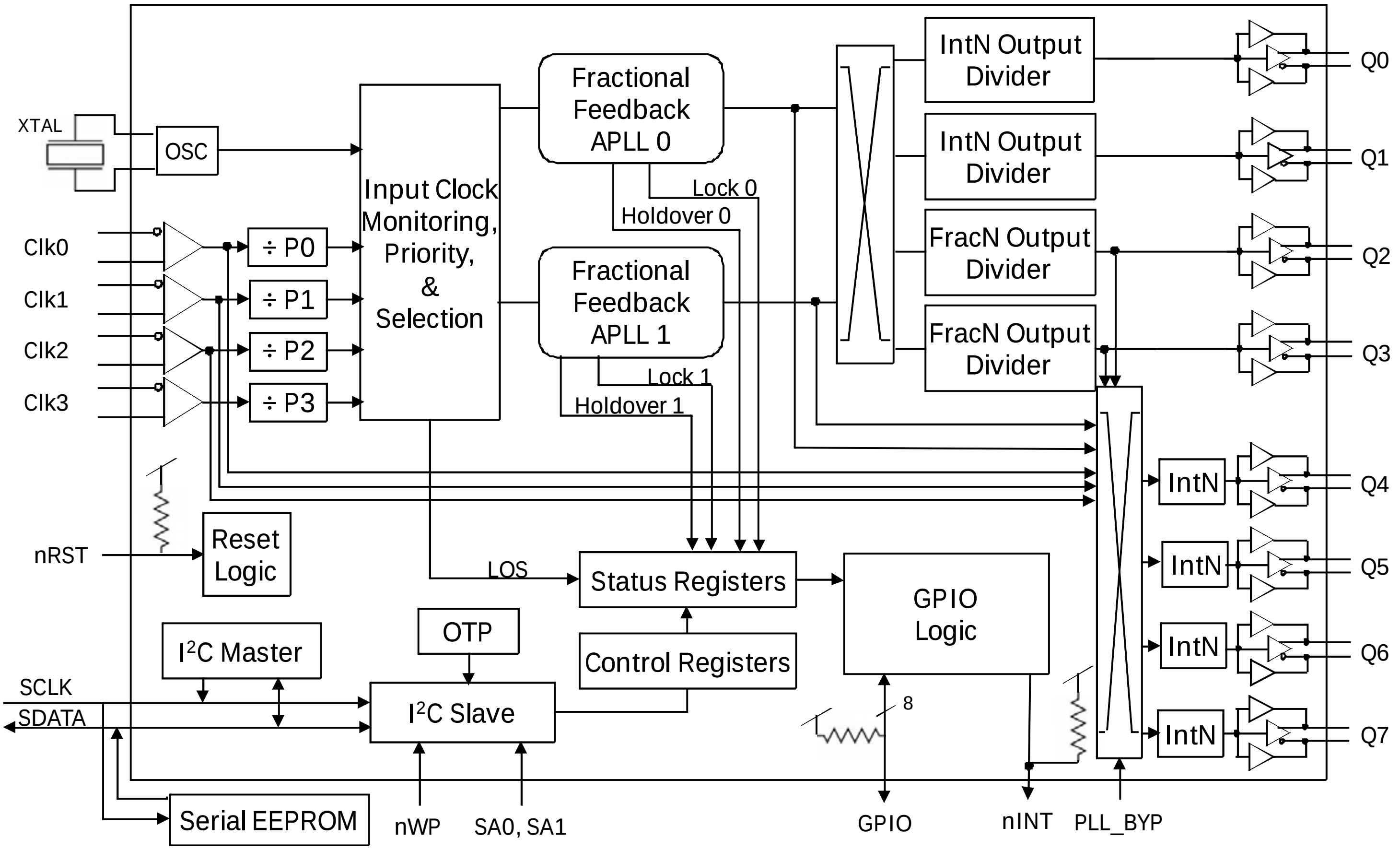


Figure 1. IDT8T49N282I Functional Block Diagram

Pin Assignment

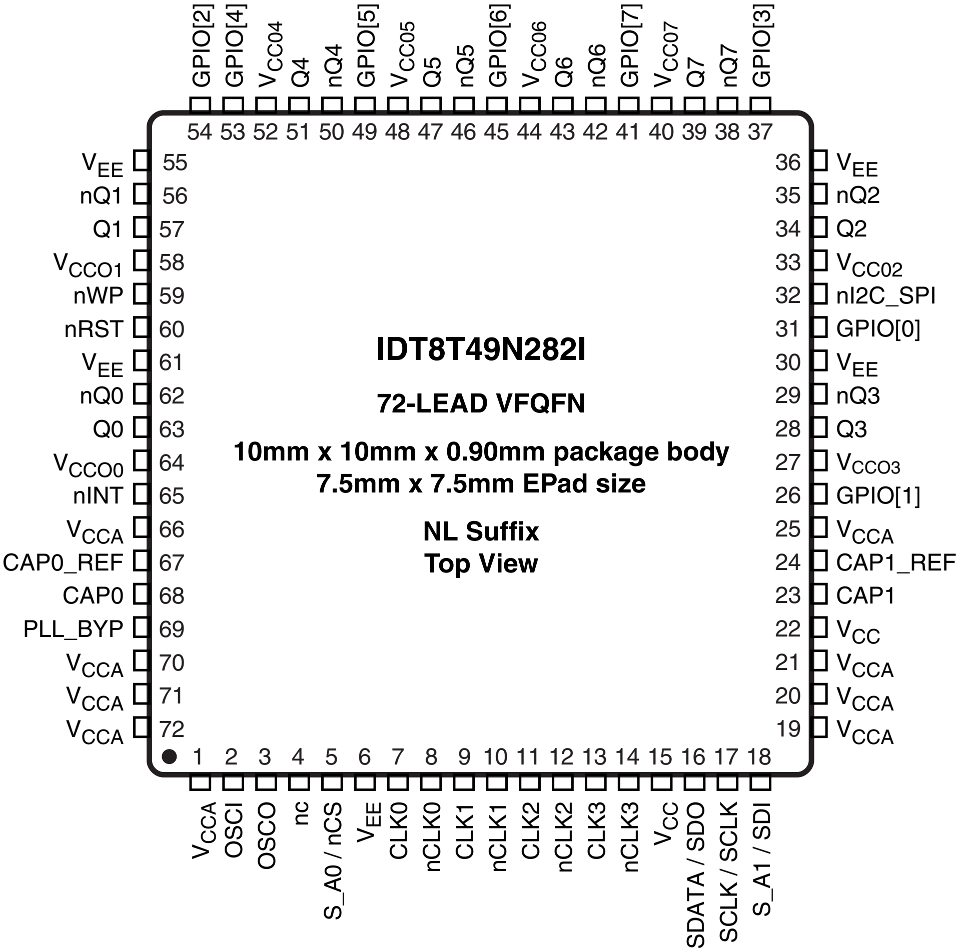


Figure 2. Pinout Drawing

Pin Description and Pin Characteristic Tables

Table 1. Pin Descriptions

Number	Name	Type		Description
2	OSCI	I		Crystal Input. Accepts a 10MHz-40MHz reference from a clock oscillator or a 12pF fundamental mode, parallel-resonant crystal.
3	OSCO	O		Crystal Output. This pin should be connected to a crystal. If an oscillator is connected to OSCI, then this pin must be left unconnected.
5	S_A0 / nCS	I	Pulldown	I^2C lower address bit A0 / SPI interface chip select signal.
16	SDATA / SDO	I/O	Pullup	I^2C interface bi-directional Data / SPI interface serial data output signal.
17	SCLK / SCLK	I/O	Pullup	I^2C interface bi-directional Clock / SPI interface clock input signal.
18	S_A1 / SDI	I	Pulldown	I^2C lower address bit A1 / SPI interface serial data input signal.
32	nI2C_SPI	I	Pulldown	Serial Interface Mode Selection. LVCMOS Input Levels: 0 = I^2C Mode 1 = SPI Mode
7	CLK0	I	Pulldown	Non-inverting differential clock input.
8	nCLK0	I	Pullup/ Pulldown	Inverting differential clock input. $V_{CC}/2$ when left floating (set by the internal pullup and pulldown resistors.)
9	CLK1	I	Pulldown	Non-inverting differential clock input.
10	nCLK1	I	Pullup/ Pulldown	Inverting differential clock input. $V_{CC}/2$ when left floating (set by the internal pullup and pulldown resistors.)
11	CLK2	I	Pulldown	Non-inverting differential clock input.
12	nCLK2	I	Pullup/ Pulldown	Inverting differential clock input. $V_{CC}/2$ when left floating (set by the internal pullup and pulldown resistors.)
13	CLK3	I	Pulldown	Non-inverting differential clock input.
14	nCLK3	I	Pullup/ Pulldown	Inverting differential clock input. $V_{CC}/2$ when left floating (set by the internal pullup and pulldown resistors.)
63, 62	Q0, nQ0	O	Universal	Output Clock 0. Please refer to the Output Drivers section for more details.
57, 56	Q1, nQ1	O	Universal	Output Clock 1. Please refer to the Output Drivers section for more details.
34, 35	Q2, nQ2	O	Universal	Output Clock 2. Please refer to the Output Drivers section for more details.
28, 29	Q3, nQ3	O	Universal	Output Clock 3. Please refer to the Output Drivers section for more details.
51, 50	Q4, nQ4	O	Universal	Output Clock 4. Please refer to the Output Drivers section for more details.
47, 46	Q5, nQ5	O	Universal	Output Clock 5. Please refer to the Output Drivers section for more details.
43, 42	Q6, nQ6	O	Universal	Output Clock 6. Please refer to the Output Drivers section for more details.
39, 38	Q7, nQ7	O	Universal	Output Clock 7. Please refer to the Output Drivers section for more details.
60	nRST	I	Pullup	Master Reset input. LVTTL / LVCMOS interface levels. 0 = All registers and state machines are reset to their default values 1 = Device runs normally
65	nINT	O	Open-drain with pullup	Interrupt output.
59	nWP	I	Pullup	Write protect input. LVTTL / LVCMOS interface levels: 0 = Write operations on the serial port will complete normally, but will have no effect except on interrupt registers 1 = Serial port writes may change any register.
41, 45, 49, 53, 37, 54, 26, 31	GPIO[7:0]	I/O	Pullup	General-purpose input-outputs. LVTTL / LVCMOS Input levels Open-drain output.Pulled-up with $5.1k\Omega$ resistor to V_{CC}.

Number	Name	Type		Description
69	PLL_BYP	I	Pulldown	Bypass Selection. Allow input references to bypass both PLLs. LVTTL / LVCMOS interface levels.
6, 30, 36, 55, 61, ePAD	V_{EE}	Power		Negative supply voltage. All V_{EE} pins and EPAD must be connected before any positive supply voltage is applied.
15	V_{CC}	Power		Core and digital function supply voltage.
22	V_{CC}	Power		Core and digital functions supply voltage.
1	V_{CCA}	Power		Analog function supply voltage for core analog functions.
19, 20, 21, 25	V_{CCA}	Power		Analog function supply voltage for analog functions associated with PLL1.
66, 70, 71, 72	V_{CCA}	Power		Analog function supply voltage for analog functions associated with PLL0.
64	V_{CCO0}	Power		High-speed output supply voltage for output pair Q0, nQ0.
58	V_{CCO1}	Power		High-speed output supply voltage for output pair Q1, nQ1.
33	V_{CCO2}	Power		High-speed output supply voltage for output pair Q2, nQ2.
27	V_{CCO3}	Power		High-speed output supply voltage for output pair Q3, nQ3.
52	V_{CCO4}	Power		High-speed output supply voltage for output pair Q4, nQ4.
48	V_{CCO5}	Power		High-speed output supply voltage for output pair Q5, nQ5.
44	V_{CCO6}	Power		High-speed output supply voltage for output pair Q6, nQ6.
40	V_{CCO7}	Power		High-speed output supply voltage for output pair Q7, nQ7.
68, 67	CAP0, CAP0_REF	Analog		PLL0 External Capacitance.
23, 24	CAP1, CAP1_REF	Analog		PLL1 External Capacitance.
4	nc	Unused		No connect.

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics,* for typical values.

Table 2. Pin Characteristics, $V_{CC} = V_{CCOX}$ = 3.3V±5% or 2.5V±5%

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
C_{IN}	Input Capacitance; NOTE 1				3.5		pF
R_{PULLUP}	Internal Pullup Resistor	nRST, nWP, SDATA / SDO, SCLK / SCLK			51		kΩ
		nINT			50		kΩ
		GPIO[7:0]			5.1		kΩ
$R_{PULLDOWN}$	Internal Pulldown Resistor				51		kΩ
C_{PD}	Power Dissipation Capacitance (per output pair)	LVCMOS Q[0:1], Q[4:7]	V_{CCOX} = 3.465V		14.5		pF
		LVCMOS Q[2:3]	V_{CCOX} = 3.465V		18.5		pF
		LVCMOS Q[0:1], Q[4:7]	V_{CCOX} = 2.625V		13		pF
		LVCMOS Q[2:3]	V_{CCOX} = 2.625V		17.5		pF
		LVCMOS Q[0:1], Q[4:7]	V_{CCOX} = 1.89V		12.5		pF
		LVCMOS Q[2:3]	V_{CCOX} = 1.89V		17		pF
		LVDS or LVPECL Q[0:1], Q[4:7]	V_{CCOx} = 3.465V or 2.625V		2		pF
		LVDS or LVPECL Q[2:3]	V_{CCOx} = 3.465V or 2.625V		4.5		pF
R_{OUT}	Output Impedance	GPIO[7:0]	Output HIGH		5.1		kΩ
			Output LOW		25		Ω
		LVCMOS Q[7:0], nQ[7:0]			20		Ω

NOTE: V_{CCOX} denotes: V_{CCO0} through V_{CCO7}.
NOTE 1: This specification does not apply to OSCI and OSCO pins.

Principles of Operation

The IDT8T49N282I has two PLLs that can each independently be locked to any of the input clocks and generate a wide range of synchronized output clocks.

It incorporates two completely independent PLLs. These could be used for example in the transmit and receive path of Synchronous Ethernet equipment. Any of the input clocks can be selected as the reference for either PLL. From the output of the two PLLs a wide range of output frequencies can be simultaneously generated.

The IDT8T49N282I accepts up to four differential input clocks ranging from 8kHz up to 875MHz. It generates up to eight output clocks ranging from 8kHz up to 1.0GHz.

Each PLL path within the IDT8T49N282I supports three states: Lock, Holdover and Free-run. Lock & holdover status may be monitored on register bits and pins. Each PLL also supports automatic and manual hitless reference switching. In the locked state, the PLL locks to a valid clock input and its output clocks have a frequency accuracy equal to the frequency accuracy of the input clock. In the Holdover state, the PLL will output a clock which is based on the selected holdover behavior. Each of the PLL paths within the IDT8T49N282I has an initial holdover frequency offset of ±50ppb. In the Free-run state, the PLL outputs a clock with the same frequency accuracy as the external crystal.

Upon power up, each PLL will enter Free-run state, in this state it generates output clocks with the same frequency accuracy as the external crystal. The IDT8T49N282I continuously monitors each input for activity (signal transitions).

In automatic reference switching, when an input clock has been validated the PLL will transition to the locked state. If the selected input clock fails and there are no other valid input clocks, the PLL will quickly detect that and go into holdover. In the Holdover state, the PLL will output a clock which is based on the selected holdover behavior. If the selected input clock fails and another input clock is available then the IDT8T49N282I will hitlessly switch to that input clock. The reference switch can be either revertive or non-revertive.

The device supports conversion of any input frequency to four different, independent output frequencies on the Q[0:3] outputs. Additionally, a further four output frequencies may be generated that are integer-related to the four independent frequencies. These additional four frequencies are on the Q[4:7] outputs.

The IDT8T49N282I has a programmable loop bandwidth from 0.5Hz to 512Hz.

The device monitors all input clocks and generates an alarm when an input clock failure is detected.

The device supports programmable individual output phase adjustments in order to allow control of input to output phase adjustments and output to output phase alignment.

The device is programmable through an I^2C or SPI interface and may also autonomously read its register settings from an internal One-Time Programmable (OTP) memory or an external serial I^2C EEPROM.

Bypass Path

For system test purposes, each of PLL0 and PLL1 may be bypassed. When PLL_BYP is asserted the CLK0 input reference will be presented to the Q4 dividers. The CLK1 input reference will be presented to the Q5 dividers.

Additionally, CLK0, CLK1 or CLK2 may be used as a clock source for the output dividers of Q4-Q7. This may only be done for input frequencies of 250MHz or less.

Input Clock Selection

The IDT8T49N282I accepts up to four input clocks with frequencies ranging from 8kHz up to 875MHz. Each input can accept LVPECL, LVDS, LVHSTL, HCSL or LVCMOS inputs using 1.8V, 2.5V or 3.3V logic levels. To use LVCMOS inputs, please refer to the Application Note, *Wiring the Differential Input to Accept Single-ended Levels* for biasing instructions.

The device has independent input clock selection control for each PLL. In Manual mode, only one of these inputs may be chosen per PLL and if that input fails that PLL will enter holdover.

Manual mode may be operated by directly selecting the desired input reference in the REFSEL register field. It may also operate via pin-selection of the desired input clock by selecting that mode in the REFSEL register field. In that case, GPIOs must be used as Clock Select inputs (CSELn[1:0]) for PLLn.

CSELn[1]	CSELn[0]	Selected Input Reference
0	0	CLK0
0	1	CLK1
1	0	CLK2
1	1	CLK3

In addition, the crystal frequency may be passed directly to the output dividers for Q[4:7] for use as a reference.

Inputs do not support transmission of spread-spectrum clocking sources. Since this family is intended for high-performance applications, it will assume input reference sources to have stabilities of ±100ppm or better.

If the PLL is working in automatic mode, then each of the input reference sources is assigned a priority of 1-4. At power-up or if the currently selected input reference fails, the PLL will switch to the highest priority input reference that is valid at that time (see Input Clock Monitor section for details).

Automatic mode has two sub-options: revertive or non-revertive. In revertive mode, the PLL will switch to a reference with a higher priority setting whenever one becomes valid. In non-revertive mode the PLL remains with the currently selected source as long as it remains valid.

The clock input selection is based on the input clock priority set by the Clock Input Priority control registers. It is recommended that all input references for a PLL be given different priority settings in the Clock Input Priority control registers for that PLL.

Input Clock Monitor

Each clock input is monitored for Loss of Signal (LOS). If no activity has been detected on the clock input within a user-selectable time period then the clock input is considered to be failed and an internal Loss-of-Signal status flag is set, which may cause an input switchover depending on other settings. The user-selectable time period has sufficient range to allow a gapped clock missing many consecutive edges to be considered a valid input.

User-selection of the clock monitor time-period is based on a counter driven by a monitor clock. The monitor clock is fixed at the frequency of PLL0's VCO divided by 8. With a VCO range of 3GHz - 4GHz, the monitor clock has a frequency range of 375MHz to 500MHz.

The monitor logic for each input reference will count the number of monitor clock edges indicated in the appropriate Monitor Control register. If an edge is received on the input reference being monitored, then the count resets and begins again. If the target edge count is reached before an input reference edge is received, then an internal soft alarm is raised and the count re-starts. During the soft alarm period, the PLL(s) tracking this input will not be adjusted. If an input reference edge is received before the count expires for the second time, then the soft alarm status is cleared and the PLL(s) will resume adjustments. If the count expires again without any input reference edge being received, then a Loss-of-Signal alarm is declared.

It is expected that for normal (non-gapped) clock operation, users will set the monitor clock count for each input reference to be slightly longer than the nominal period of that input reference. A margin of 2-3 monitor clock periods should give a reasonably quick reaction time and yet prevent false alarms.

For gapped clock operation, the user will set the monitor clock count to a few monitor clock periods longer than the longest expected clock gap period. The monitor count registers support 17-bit count values, which will support at least a gap length of two clock periods for any supported input reference frequency, with longer gaps being supported for faster input reference frequencies. Since gapped clocks usually occur on input reference frequencies above 100MHz, gap lengths of thousands of periods can be supported.

Using this configuration for a gapped clock, the PLL will continue to adjust while the normally expected gap is present, but will freeze once the expected gap length has been exceeded and alarm after twice the normal gap length has passed.

Once a LOS on any of the input clocks is detected, the appropriate internal LOS alarm will be asserted and it will remain asserted until that input clock returns and will be validated by the receipt of 8 rising clock edges on that input reference. If another error condition on the same input clock is detected during the validation time then the alarm remains asserted and the validation time starts over.

Each LOS flag may also be reflected on one of the GPIO[7:0] outputs. Changes in status of any reference can also generate an interrupt if not masked.

Holdover

IDT8T49N282I supports a small initial holdover frequency offset for each PLL path in non-gapped clock mode. When the input clock monitor is set to support gapped clock operation, this initial holdover frequency offset is indeterminate since the desired behavior with gapped clocks is for the PLL to continue to adjust itself even if clock edges are missing. In gapped clock mode, the PLL will not enter holdover until the input is missing for at least 2 LOS monitor periods.

The holdover performance characteristics of a clock are referred as its accuracy and stability, and are characterized in terms of the fractional frequency offset. The IDT8T49N282I can only control the initial frequency accuracy. Longer-term accuracy and stability are determined by the accuracy and stability of the external oscillator.

When a PLL loses all valid input references, it will enter the holdover state. In fast average mode, the PLL will initially maintain its most recent frequency offset setting and then transition at a rate dictated by its selected phase-slope limit setting to a frequency offset setting that is based on historical settings. This behavior is intended to compensate for any frequency drift that may have occurred on the input reference before it was detected to be lost.

The historical holdover value will have three options:

- Return to center of tuning range within the V_{CO} band
- Instantaneous mode - the holdover frequency will use the DPLL current frequency 100msec before it entered holdover. The accuracy is shown in the AC Table.
- Fast average mode - an internal IIR (Infinite Impulse Response) filter is employed to get the frequency offset. The IIR filter gives a 3dB attenuation point corresponding to a nominal period of 20 minutes. The accuracy is shown in the AC Table.

When entering holdover, each PLL will set a separate internal HOLD alarm internally. This alarm may be read from internal status register, appear on the appropriate GPIO pin and/or assert the nINT output.

While a PLL is in holdover, its frequency offset is now relative to the crystal input and so the output clocks derived from that PLL will be tracing their accuracy to the local oscillator or crystal. At some point in time, depending on the stability & accuracy of that source, the clock(s) derived from that PLL will have drifted outside of the limits of the holdover state and the system will be considered to be in a free-run state. Since this borderline is defined outside the PLL and dictated by the accuracy and stability of the external local crystal or oscillator, the IDT8T49N282I cannot know or influence when that transition occurs. As a result, the IDT8T49N282I will remain in the holdover state internally.

Input to Output Clock Frequency

The IDT8T49N282I is designed to accept any frequency within its input range and generate eight different output frequencies that are independent from the input frequencies. The internal architecture of the device ensures that most translations will result in the exact output frequency specified. Where exact frequency translation is not possible, the frequency translation error will be minimized.Please contact IDT for configuration software or other assistance in determining if a desired configuration will be supported exactly.

Synthesizer Mode Operation

The device may also act as a frequency synthesizer with either or both PLL's generating their operating frequency from just the crystal input. By setting the SYN_MODEn register bit and setting the STATEn[1:0] field to Freerun, no input clock references are required to generate the desired output frequencies.

Loop Filter and Bandwidth

When operating in Synthesizer Mode as described above, the IDT8T49N282I has a fixed loop bandwidth of approximately 200kHz. When operating in all other modes, the following information applies:

The IDT8T49N282I uses no external components to support a range of loop bandwidths: 0.5Hz, 1Hz, 2Hz, 4Hz, 8Hz, 16Hz, 32Hz, 64Hz, 128Hz, 256Hz or 512Hz. Each PLL shall support separate loop filter settings.

The device supports three different loop bandwidth settings for each PLL: acquisition, locked and tight-locked. These loop bandwidths are selected from the list of options described above. If enabled, the acquisition bandwidth is used while lock is being acquired to allow the PLL to `fast-lock'. Once locked the PLL will use the locked bandwidth setting. If the acquisition bandwidth setting is not used, the PLL will use the locked bandwidth setting at all times. The tight-locked setting may be used to lower phase noise in situations where the input reference only varies within a very narrow, register-programmed range.

Output Dividers and Mapping to PLLs

Each integer output divider block consists of two divider stages in a series to achieve the desired total output divider ratio. The first stage divider may be set to divide by 4, 5 or 6. The second stage of the divider may be bypassed (i.e. divide-by-1) or programmed to any even divider ratio from 2 to 131,070. The total divide ratios, settings and possible output frequencies are shown in Table 3.

In addition, the first divider stage for the Q4-Q7 outputs supports a bypass (i.e. divide-by-1) operation for some clock sources.

Table 3. Q0, Q1, Q[4:7] Output Divide Ratios

1st-Stage Divide	2nd-Stage Divide	Total Divide	Minimum F_{OUT} MHz	Maximum F_{OUT} MHz
4	1	4	750	1000
5	1	5	600	800
6	1	6	500	666.7
4	2	8	375	500
5	2	10	300	400
6	2	12	250	333.3
4	4	16	187.5	250
5	4	20	150	200
6	4	24	125	166.7
		...		
4	131,070	524,280	0.0057	0.0076
5	131,070	655,350	0.0046	0.0061
6	131,070	786,420	0.0038	0.0051

NOTE: Above frequency ranges for Q[4:7] apply when driven directly from PLL0 or PLL1.

Fractional Output Divider Programming (Q2, Q3 only)

For the FracN output dividers Q2-Q3, the output divide ratio is given by:

Output Divide Ratio = (N.F)x2

N = Integer Part: 4, 5, ...(2^{18}-1)

F = Fractional Part: [0, 1, 2, ...(2^{28}-1)]/(2^{28})

For integer operation of these outputs dividers, N = 3 is also supported.

Output Divider Frequency Sources

Output dividers associated with the Q[0:3] outputs can take their input frequencies from either PLL0 or PLL1.

Output dividers associated with the Q[4:7] outputs can take their input frequencies from PLL0, PLL1, Q2 or Q3 output dividers, the CLK0, CLK1 or CLK2 input reference frequencies or the crystal frequency.

Output Banks

Outputs of the IDT8T49N282I are divided into three banks for purposes of output skew measurement.

- Q0, nQ0, Q1, nQ1
- Q4, nQ4, Q5, nQ5
- Q6, nQ6, Q7, nQ7

Output Phase Control on Switchover

There are two options on how the output phase can be controlled when the IDT8T49N282I enters or leaves the holdover state, or either PLL switches between input references. Phase-slope limiting or fully hitless switching (sometimes called phase build-out) may be selected. The SWMODEn bit selects which behavior is to be followed for PLLn.

If fully hitless switching is selected, then the output phase will remain unchanged under any of these conditions. Note that fully hitless switching is not supported when external loopback is being used.

If phase-slope limiting is selected, then the output phase will adjust from its previous value until it is tracking the new condition at a rate dictated by the SLEWn[1:0] bits.

Output Phase Alignment

The device has a programmable output to output phase alignment for each of the eight output dividers. After power-up and the PLLs have achieved lock, the device will be in a state where the outputs are synchronized with a deterministic offset relative to each other.After synchronization, the output alignment will depend on the particular configuration of each output according to the following rules. The step size is defined as the period of the clock to that divider:

1) Only outputs derived from the same source will be aligned with each other. 'Source' means the reference selected to drive the output divider as controlled by the CLK_SELn bit for each output.

2) For integer dividers (Q0, Q1, Q4-7) when both divider stages are active, edges are aligned. This case is used as a baseline to compare the other cases here.

3) For integer dividers where the 1st-stage divider is bypassed (only Q4-Q7 support this), coarse delay adjustments can't be performed. The output phase will be one step earlier than in Case 2.

4) Fractional output dividers (Q2 or Q3) do not guarantee any specific phase on power-up or after a synchronization event.

5) Integer dividers using Q2 or Q3 as a source (Q4-Q7 support this option) will be aligned to their source divider's output (Q2 or Q3).

6) Phase alignments listed above may differ by the output-output skews in the AC Table.

Once the device is in operation, the outputs associated with each PLL may have their phase adjustments re-synced in one of two ways:

1) If the PLL becomes unlocked, the coarse phase adjustments will be reset and the fine phase adjustments will be re-loaded once it becomes locked again.

2) Toggling of PLLn_SYN bit may also be used to force a re-sync / re-load for outputs associated with that PLL.

The user may apply adjustments that are proportional to the period of the clock source driving each output divider. For example, if the divider associated with Output Q3 is running off PLL0, which has a VCO frequency of 4GHz, then the appropriate period would be 250ps. The output phase may be adjusted in these steps across the full period of the output.

- Coarse Adjustment: all Output Dividers may have their phase adjusted in steps of the source clock period. For example a 4GHz VCO gives a step size of 250ps. The user may request an adjustment of phase of up to 31 steps using a single register write. The phase will be adjusted by lengthening the period of the output by 250ps at a time. This process will be repeated every 4 output clock periods until the full requested adjustment has been achieved. A busy signal will remain asserted in the phase delay register until the requested adjustment is complete. Then a further adjustment may be setup and triggered by toggling the trigger bit.
- Fine Adjustment: For the Fractional Output Dividers associated with the Q2 and Q3 outputs, the phase of those outputs may be further adjusted with a granularity of 1/16th of the VCO period. For example a 4GHz VCO frequency gives a granularity of 16ps. This is performed by directly writing the required offset (from the nominal rising edge position) in units of $1/16^{th}$ of the output period into a register. Then the appropriate PLLn_SYN bit must be toggled to load the new value. Note that toggling this bit will clear all Coarse Delays for all outputs associated with that PLL, so Fine Delays should be set first, before Coarse Delays. The output will then jump directly to that new offset value. For this reason, this adjustment should be made as the input is initially programmed or in high-impedance.

Each output has the capability of being inverted (180 degree phase shift).

Jitter and Wander Tolerance

The IDT8T49N282I can be used as a line card device and therefore is expected to tolerate the jitter and wander output of a timing card PLL (e.g IDT82V3390).

Output Drivers

The Q0 to Q7 clock outputs are provided with register-controlled output drivers. By selecting the output drive type in the appropriate register, any of these outputs can support LVCMOS, LVPECL or LVDS logic levels.

The operating voltage ranges of each output is determined by its independent output power pin (V_{CCO}) and thus each can have different output voltage levels. Output voltage levels of 2.5V or 3.3V are supported for differential operation and LVCMOS operation. In addition, LVCMOS output operation supports 1.8V V_{CCO}.

Each output may be enabled or disabled by register bits and/or GPIO pins configured as Output Enables. The outputs will be enabled if the register bit and the associated OE pin are both asserted (high). When disabled an output will be in a high impedance state.

LVCMOS Operation

When a given output is configured to provide LVCMOS levels, then both the Q and nQ outputs will toggle at the selected output frequency. All the previously described configuration and control apply equally to both outputs. Frequency, phase alignment, voltage levels and enable / disable status apply to both the Q and nQ pins. When configured as LVCMOS, the Q and nQ outputs can be selected to be phase-aligned with each other or inverted relative to one another. Phase-aligned outputs will have increased simultaneous switching currents which can negatively affect phase noise performance and power consumption. It is recommended that use of this selection be kept to a minimum.

Power-Saving Modes

To allow the device to consume the least power possible for a given application, the following functions are included under register control:

- PLL1 may be shut down.
- Any unused output, including all output divider and phase adjustment logic, can be individually powered-off.
- Clock gating on logic that is not being used.

Status / Control Signals and Interrupts

General-Purpose I/Os & Interrupts

The IDT8T49N282I provides eight General Purpose Input / Output (GPIO) pins for miscellaneous status & control functions. Each GPIO may be configured as an input or an output. Each GPIO may be directly controlled from register bits or be used as a predefined function as shown in *Table 4*. Note that the default state prior to configuration being loaded from internal OTP or external EEPROM will be to set each GPIO to function as an Output Enable.

Table 4. GPIO Configuration

GPIO Pin	Configured as Input			Configured as Output	
	Fixed Function				
	Output Enable (default)	Clock Select	General Purpose	Fixed Function	General Purpose
7	OE[7]	CSEL1[1]	GPI[7]	LOS[3]	GPO[7]
6	OE[6]	CSEL0[1]	GPI[6]	LOS[2]	GPO[6]
5	OE[5]	-	GPI[5]	LOS[1]	GPO[5]
4	OE[4]	-	GPI[4]	HOLD[1]	GPO[4]
3	OE[3]	CSEL1[0]	GPI[3]	LOL[1]	GPO[3]
2	OE[2]	CSEL0[0]	GPI[2]	LOS[0]	GPO[2]
1	OE[1]	-	GPI[1]	HOLD[0]	GPO[1]
0	OE[0]	-	GPI[0]	LOL[0]	GPO[0]

If used in the Fixed Function mode of operation, the GPIO bits will reflect the real-time status of their respective status bits as shown in *Table 4*. Note that the LOL signal represents the lock status of the PLL. It does not account for the process of synchronization of the output dividers associated with that PLL. The output dividers programmed to operate from that PLL will automatically go through a re-synchronization process when the PLL locks or re-locks or if the user triggers a re-sync manually via register bit PLLn_SYN. This synchronization process may result in a period of instability on the affected outputs for a duration of up to 350ns after the re-lock (LOL de-asserts) or the PLLn_SYN bit is de-asserted.

Interrupt Functionality

Interrupt functionality includes an interrupt status flag for each of PLL Loss-of-Lock Status (LOL[1:0]), PLL Holdover Status (HOLD[1:0]) and Input Reference Status (LOS[3:0]) that is set whenever there is an alarm on any of those signals. The Status Flag will remain set until the alarm has been cleared and a ‘1’ has been written to the Status Flag’s register location or if a reset occurs. Each Status Flag will also have an Interrupt Enable bit that will determine if that Status Flag is allowed to cause the Interrupt Status to be affected (enabled) or not (disabled). All Interrupt Enable bits will be in the disabled state after reset. The Device Interrupt Status flag and nINT output pin are asserted if any of the enabled Interrupt Status flags are set.

Device Hardware Configuration

The IDT8T49N282I supports an internal One-Time Programmable (OTP) memory that can be pre-programmed at the factory with one complete device configuration. If the device is set to read a configuration from an external, serial EEPROM, then the values read will overwrite the OTP-defined values.

This configuration can be over-written using the serial interface once reset is complete. Any configuration written via the programming interface needs to be re-written after any power cycle or reset. Please contact IDT if a specific factory-programmed configuration is desired.

Device Start-up & Reset Behavior

The IDT8T49N282I has an internal power-up reset (POR) circuit and a Master Reset input pin nRST. If either is asserted, the device will be in the Reset State.

While in the reset state (nRST input asserted or POR active), the device will operate as follows:

- All registers will return to & be held in their default states as indicated in the applicable register description.
- All internal state machines will be in their reset conditions.
- The serial interface will not respond to read or write cycles.
- The GPIO signals will be configured as OE[7:0] inputs.
- All clock outputs will be disabled.
- All interrupt status and Interrupt Enable bits will be cleared, negating the nINT signal.

Upon the latter of the internal POR circuit expiring or the nRST input negating, the device will exit reset and begin self-configuration.

The device will load an initial block of its internal registers using the configuration stored in the internal One-Time Programmable (OTP) memory. Once this step is complete, the IDT8T49N282I will check the register settings to see if it should load the remainder of its configuration from an external I^2C EEPROM at a defined address or continue loading from OTP. See the section on I^2C Boot Initialization for details on how this is performed.

Once the full configuration has been loaded, the device will respond to accesses on the serial port and will attempt to lock both PLLs to the selected sources and begin operation. Once the PLLs are locked, all the outputs derived from a given PLL will be synchronized and output phase adjustments can then be applied if desired.

Serial Control Port Description

Serial Control Port Configuration Description

The device has a serial control port capable of responding as a slave in an I²C or SPI compatible configuration, to allow access to any of the internal registers for device programming or examination of internal status. All registers are configured to have default values. See the specifics for each register for details. Selection of I²C versus SPI protocol will be done via an input pin.

The device has the additional capability of becoming a master on the I²C bus only for the purpose of reading its initial register configurations from a serial EEPROM on the I²C bus. Writing of the configuration to the serial EEPROM must be performed by another device on the same I²C bus or pre-programmed into the device prior to assembly. This capability is unavailable if SPI protocols are selected for the programming interface.

SPI Mode Operation

In a read operation (R/$\overline{W}$ bit is '1') data on SDO will be clocked out on the falling edge of SCLK.

In a write operation (R/$\overline{W}$ bit is '0'), data on SDI will be clocked in on the rising edge of SCLK.

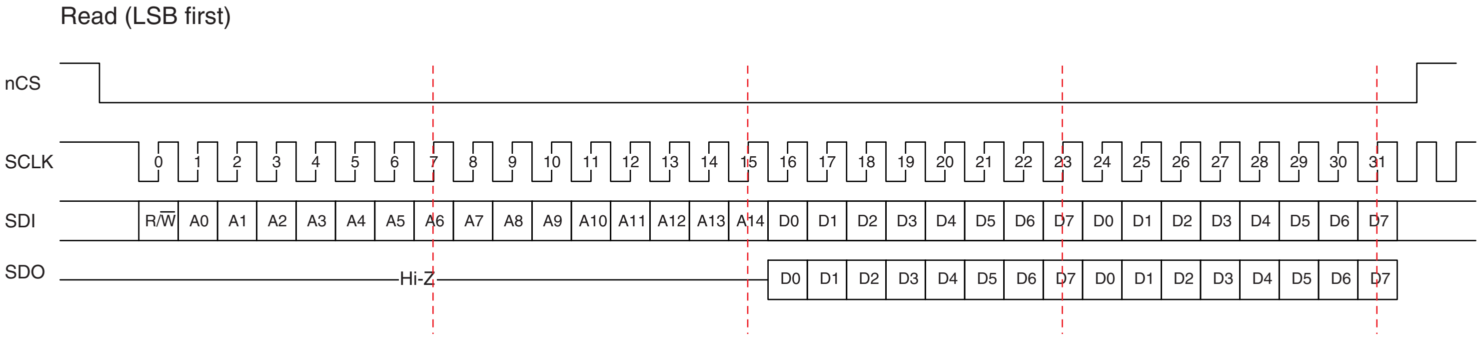


Figure 3. SPI Read Sequencing Diagram

During SPI Write operations, the user may continue to hold nCS low and provide further bytes of data for up to a total of 32,767 bytes in a single block write. Once nCS is driven high, then all data will be written into sequential registers starting at the address given.

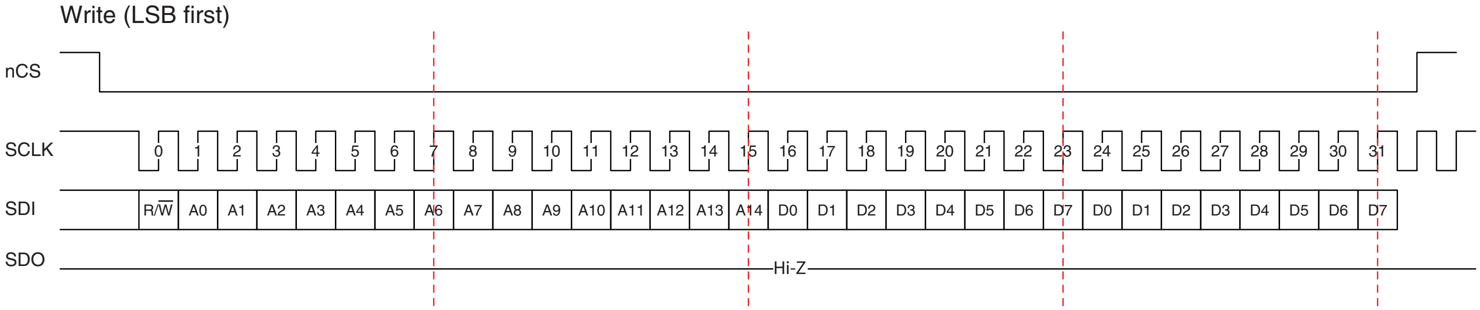


Figure 4. SPI Write Sequencing Diagram

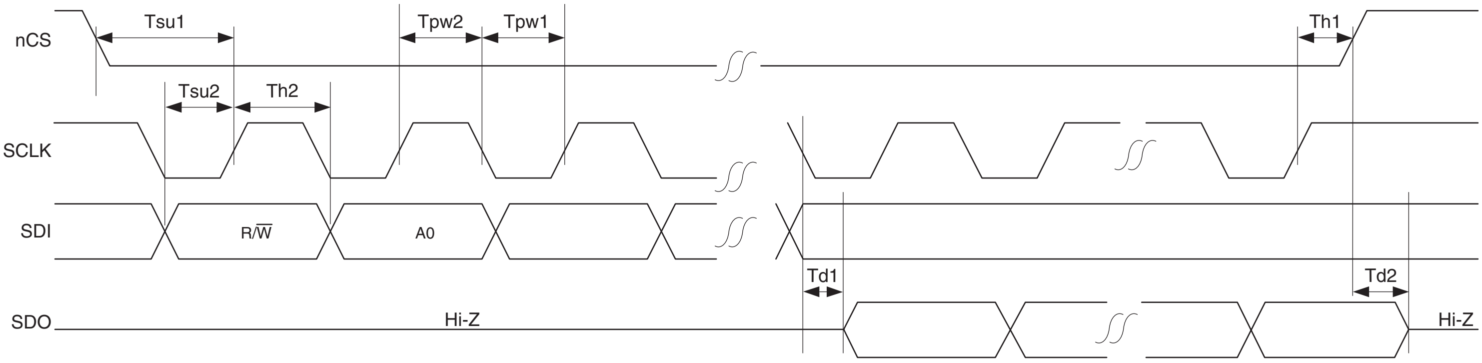


Figure 5. SPI Read/Write Timing Diagram

Table 5. Timing Characteristics in SPI Mode

Symbol	Parameter	Min	Typ	Max	Unit
T	Internal timing parameter used to calculate SPI timing specs	T = PLL0 period * 64			ns
t_{su1}	Valid nCS to SCLK rising setup time	2T			ns
t_{su2}	Valid SDI to SCLK rising setup time	5			ns
t_{d1}	SCLK falling to valid data delay time			4T + 5	ns
t_{d2}	nCS rising edge to SDO high impedance delay time			15	ns
t_{pw1}	SCLK pulse width low	5T			ns
t_{pw2}	SCLK pulse width high	5T			ns
t_{h1}	Valid nCS after valid SCLK hold time	2T			ns
t_{h2}	Valid SDI after valid SCLK hold time	3T			ns
t_{csh}	Time between consecutive Read-Read or Read-Write accesses (nCS rising edge to nCS falling edge)	3T			ns

NOTE: Specifications guaranteed by design and characterization.

I^{2}C Mode Operation

The I^{2}C interface is designed to fully support v1.2 of the I^{2}C Specification for Normal and Fast mode operation. The device acts as a slave device on the I^{2}C bus at 100kHz or 400kHz using the address defined in the Serial Interface Control register (0006h), as modified by the S_A0 & S_A1 input pin settings. The interface accepts byte-oriented block write and block read operations. Two address bytes specify the register address of the byte position of the first register to write or read. Data bytes (registers) are accessed in sequential order from the lowest to the highest byte (most significant bit first). Read and write block transfers can be stopped after any complete byte transfer. During a write operation, data will not be moved into the registers until the STOP bit is received, at which point, all data received in the block write will be written simultaneously.

For full electrical I^{2}C compliance, it is recommended to use external pull-up resistors for SDATA and SCLK. The internal pull-up resistors have a size of 51kΩ typical.

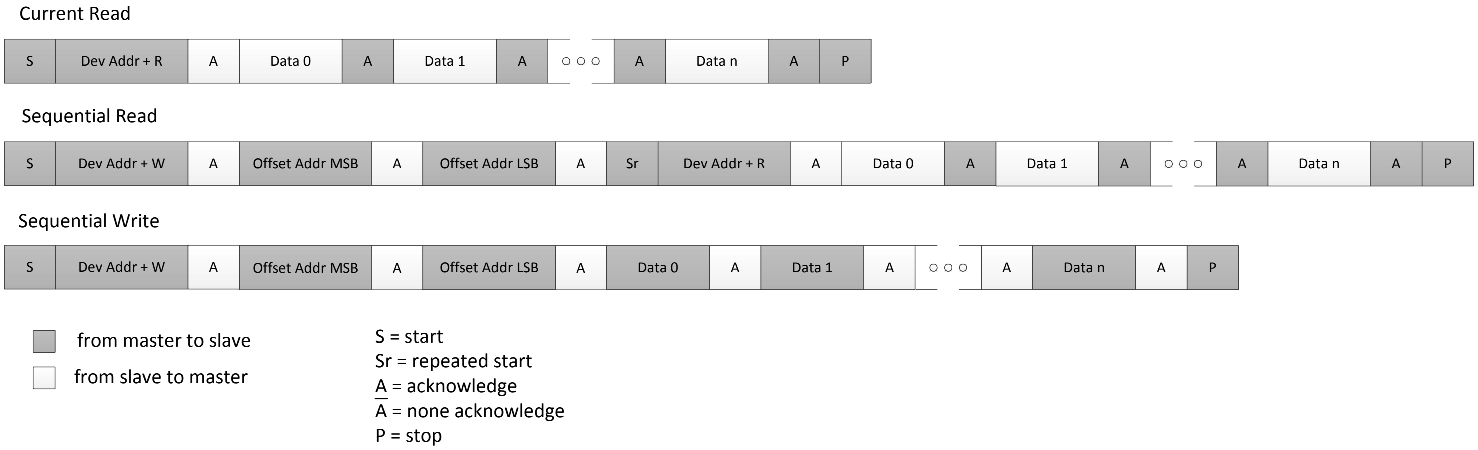


Figure 6. I^{2}C Slave Read and Write Cycle Sequencing

I^2C Master Mode

When operating in I^2C mode, the IDT8T49N282I has the capability to become a bus master on the I^2C bus for the purposes of reading its configuration from an external I^2C EEPROM. Only a block read cycle will be supported.

As an I^2C bus master, the IDT8T49N282I will support the following functions:

- 7-bit addressing mode
- Base address register for EEPROM
- Validation of the read block via CCITT-8 CRC check against value stored in last byte (E0h) of EEPROM
- Support for 100kHz and 400kHz operation with speed negotiation. If bit d0 is set at Byte address 05h in the EEPROM, this will shift from 100kHz operation to 400kHz operation
- Support for 1- or 2-byte addressing mode
- Master arbitration with programmable number of retries
- Fixed-period cycle response timer to prevent permanently hanging the I^2C bus.
- Read will abort with an alarm (BOOTFAIL) if any of the following conditions occur: Slave NACK, Arbitration Fail, Collision during Address Phase, CRC failure, Slave Response time-out

The IDT8T49N282I will not support the following functions:

- I^2C General Call
- Slave clock stretching
- I^2C Start Byte protocol
- EEPROM Chaining
- CBUS compatibility
- Responding to its own slave address when acting as a master
- Writing to external I^2C devices including the external EEPROM used for booting

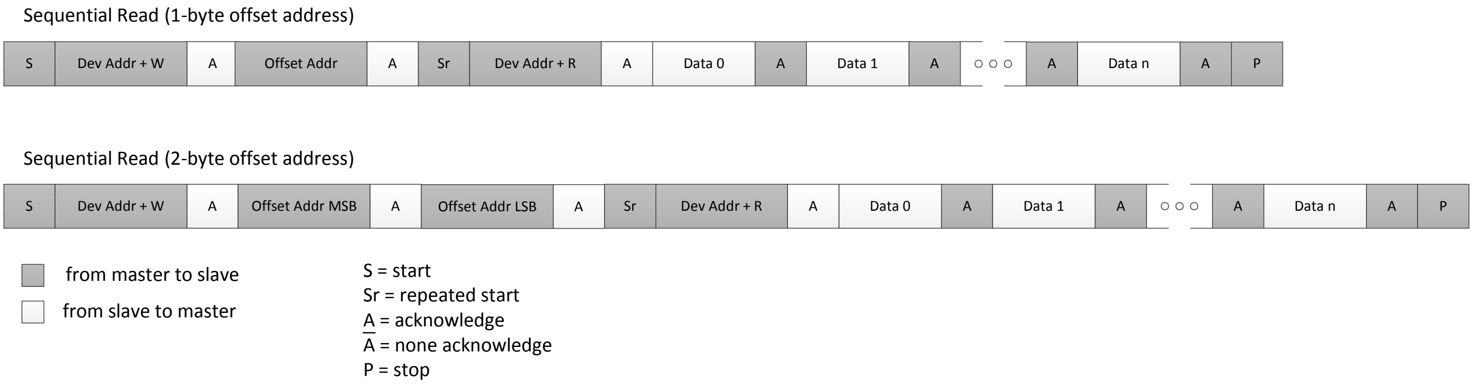


Figure 7. I^2C Master Read Cycle Sequencing

I^{2}C Boot-up Initialization Mode

If enabled (via the BOOT_EEP bit in the Startup register), once the nRST input has been deasserted (high) and its internal power-up reset sequence has completed, the device will contend for ownership of the I^{2}C bus to read its initial register settings from a memory location on the I^{2}C bus. The address of that memory location is kept in non-volatile memory in the Startup register. During the boot-up process, the device will not respond to serial control port accesses. Once the initialization process is complete, the contents of any of the device's registers can be altered. It is the responsibility of the user to make any desired adjustments in initial values directly in the serial bus memory.

If a NACK is received to any of the read cycles performed by the device during the initialization process, or if the CRC does not match the one stored in address E0h of the EEPROM the process will be aborted and any uninitialized registers will remain with their default values. The BOOTFAIL bit (021Eh) in the Global Interrupt Status register will also be set in this event.

If the BOOTFAIL bit is set, then both LOL[n] indicators will be set.

Contents of the EEPROM should be as shown in *Table 6*.

Table 6. External Serial EEPROM Contents

EEPROM Offset (Hex)	Contents							
	D7	D6	D5	D4	D3	D2	D1	D0
00	1	1	1	1	1	1	1	1
01	1	1	1	1	1	1	1	1
02	1	1	1	1	1	1	1	1
03	1	1	1	1	1	1	1	1
04	1	1	1	1	1	1	1	1
05	1	1	1	1	1	1	1	Serial EEPROM Speed Select 0 = 100kHz 1 = 400kHz
06	1	IDT8T49N282I Device I^{2}C Address [6:2]					1	1
07	0	0	0	0	0	0	0	0
08 - DF	Desired contents of Device Registers 08h - DFh							
E0	Serial EEPROM CRC							
E1 - FF	Unused							

Register Descriptions

Table 7A. Register Blocks

Register Ranges Offset (Hex)	Register Block Description
0000 - 0001	Startup Control Registers
0002 - 0005	Device ID Control Registers
0006 - 0007	Serial Interface Control Registers
0008 - 003A	Digital PLL0 Control Registers
003B - 006D	Digital PLL1 Control Registers
006E - 0076	GPIO Control Registers
0077 - 00AB	Output Clock Control Registers
00AC - 00AF	Analog PLL0 Control Registers
00B0 - 00B3	Analog PLL1 Control Registers
00B4 - 00B8	Power-Down Control Registers
00B9 - 00C6	Input Monitor Control Registers
00C7 - 00C8	Interrupt Enable Registers
00C9 - 01FF	Reserved
0200 - 0203	Interrupt Status Registers
0204	Output Phase Adjustment Status Register
0205 - 020E	Digital PLL0 Status Registers
020F - 0218	Digital PLL1 Status Registers
0219	General-Purpose Input Status Register
021A - 21F	Global Interrupt and Boot Status Register
0220 - 3FF	Reserved

Table 7B. Startup Control Register Bit Field Locations and Descriptions

Startup Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0000	EEP_RTY[4:0]					Rsvd	nBOOT_OTP	nBOOT_EEP
0001	EEP_A15	EEP_ADDR[6:0]						

Startup Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
EEP_RTY[4:0]	R/W	00001b	Select number of times arbitration for the I^{2}C bus to read the serial EEPROM will be retried before being aborted. Note that this number does not include the original try.
nBOOT_OTP	R/W	NOTE 1	Internal One-Time Programmable (OTP) memory usage on power-up: 0 = Load power-up configuration from OTP 1 = Only load 1st eight bytes from OTP
nBOOT_EEP	R/W	NOTE 1	External EEPROM usage on power-up: 0 = Load power-up configuration from external serial EEPROM (overwrites OTP values) 1 = Don’t use external EEPROM
EEP_A15	R/W	NOTE 1	Serial EEPROM supports 15-bit addressing mode (multiple pages).
EEP_ADDR[6:0]	R/W	NOTE 1	I^{2}C base address for serial EEPROM.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

NOTE 1: These values are specific to the device configuration 'dash-code'. Please refer to the FemtoClock NG Universal Frequency Translator Ordering Product Information guide for exact default values.

Table 7C. Device ID Control Register Bit Field Locations and Descriptions

Device ID Register Control Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0002	REV_ID[3:0]				DEV_ID[15:12]			
0003	DEV_ID[11:4]							
0004	DEV_ID[3:0]				DASH_CODE[10:7]			
0005	DASH_CODE[6:0]							1

Device ID Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
REV_ID[3:0]	R/W	0010b	Device revision.
DEV_ID[15:0]	R/W	0600h	Device ID code.
DASH_CODE [10:0]	R/W	NOTE 1	Device Dash Code Decimal value assigned by IDT to identify the configuration loaded at the factory. May be over-written by users at any time. Refer to *FemtoClock NG Universal Frequency Translator Ordering Product Information* to identify major configuration parameters associated with this Dash Code value.

NOTE 1: These values are specific to the device configuration 'dash-code'. Please refer to the FemtoClock NG Universal Frequency Translator Ordering Product Information guide for exact default values.

Table 7D. Serial Interface Control Register Bit Field Locations and Descriptions

Serial Interface Control Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0006	SPI_SEL	UFTADD[6:2]					UFTADD[1]	UFTADD[0]
0007	Rsvd							1

Device ID Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
SPI_SEL	R/O	0b	Select Mode for serial interface as read from the nI2C_SPI pin: 0 = I^2C 1 = SPI
UFTADD[6:2]	R/W	NOTE 1	Configurable portion of I^2C Base Address (bits 6:2) for this device.
UFTADD[1]	R/O	0b	I^2C Base Address bit 1. This address bit reflects the status of the S_A1 / SDI external input pin. See Table 1, Pin Descriptions.
UFTADD[0]	R/O	0b	I^2C Base Address bit 0. This address bit reflects the status of the S_A0 / nCS external input pin. See Table 1, Pin Descriptions.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

NOTE 1: These values are specific to the device configuration 'dash-code'. Please refer to the FemtoClock NG Universal Frequency Translator Ordering Product Information guide for exact default values.

Table 7E. Digital PLL0 Input Control Register Bit Field Locations and Descriptions

Digital PLL0 Input Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0008	REFSEL0[2:0]			FBSEL0[2:0]			RVRT0	SWMODE0
0009	PRI0_3[1:0]		PRI0_2[1:0]		PRI0_1[1:0]		PRI0_0[1:0]	
000A	REFDIS0_3	REFDIS0_2	REFDIS0_1	REFDIS0_0	Rsvd	Rsvd	STATE0[1:0]	
000B	Rsvd			PRE0_0[20:16]				

Digital PLL0 Input Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
000C	PRE0_0[15:8]							
000D	PRE0_0[7:0]							
000E	Rsvd			PRE0_1[20:16]				
000F	PRE0_1[15:8]							
0010	PRE0_1[7:0]							
0011	Rsvd			PRE0_2[20:16]				
0012	PRE0_2[15:8]							
0013	PRE0_2[7:0]							
0014	Rsvd			PRE0_3[20:16]				
0015	PRE0_3[15:8]							
0016	PRE0_3[7:0]							

Digital PLL0 Input Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
REFSEL0[2:0]	R/W	000b	Input reference selection for Digital PLL0: 000 = Automatic selection 001 = Manual selection by GPIO inputs 010 through 011 = Reserved 100 = Force selection of Input Reference 0 101 = Force selection of Input Reference 1 110 = Force selection of Input Reference 2 111 = Force selection of Input Reference 3
FBSEL0[2:0]	R/W	000b	Feedback mode selection for Digital PLL0: 000 - 011 = internal feedback divider 100 = external feedback from Input Reference 0 101 = external feedback from Input Reference 1 110 = external feedback from Input Reference 2 111 = external feedback from Input Reference 3
RVRT0	R/W	1b	Automatic switching mode for Digital PLL0: 0 = non-revertive switching 1 = revertive switching
SWMODE0	R/W	1b	Controls how Digital PLL0 adjusts output phase when switching between input references: 0 = Absorb any phase differences between old & new input references 1 = Track to follow new input reference’s phase using phase-slope limiting
PRI0_0[1:0]	R/W	00b	Switchover priority for Input Reference 0 when used by Digital PLL0: 00 = 1st priority 01 = 2nd priority 10 = 3rd priority 11 = 4th priority
PRI0_1[1:0]	R/W	01b	Switchover priority for Input Reference 1 when used by Digital PLL0: 00 = 1st priority 01 = 2nd priority 10 = 3rd priority 11 = 4th priority
PRI0_2[1:0]	R/W	10b	Switchover priority for Input Reference 2 when used by Digital PLL0: 00 = 1st priority 01 = 2nd priority 10 = 3rd priority 11 = 4th priority

Digital PLL0 Input Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
PRI0_3[1:0]	R/W	11b	Switchover priority for Input Reference 3 when used by Digital PLL0: 00 = 1st priority 01 = 2nd priority 10 = 3rd priority 11 = 4th priority
REFDIS0_0	R/W	0b	Input Reference 0 Switching Selection Disable for Digital PLL0: 0 = Input Reference 0 is included in the switchover sequence for Digital PLL0 1 = Input Reference 0 is not included in the switchover sequence for Digital PLL0
REFDIS0_1	R/W	0b	Input Reference 1 Switching Selection Disable for Digital PLL0: 0 = Input Reference 1 is included in the switchover sequence for Digital PLL0 1 = Input Reference 1 is not included in the switchover sequence for Digital PLL0
REFDIS0_2	R/W	0b	Input Reference 2 Switching Selection Disable for Digital PLL0: 0 = Input Reference 2 is included in the switchover sequence for Digital PLL0 1 = Input Reference 2 is not included in the switchover sequence for Digital PLL0
REFDIS0_3	R/W	0b	Input Reference 3 Switching Selection Disable for Digital PLL0: 0 = Input Reference 3 is included in the switchover sequence for Digital PLL0 1 = Input Reference 3 is not included in the switchover sequence for Digital PLL0
STATE0[1:0]	R/W	00b	Digital PLL0 State Machine Control: 00 = Run automatically 01 = Force FREERUN state - set this if in Synthesizer Mode for PLL0. 10 = Force NORMAL state 11 = Force HOLDOVER state
PRE0_0[20:0]	R/W	000000h	Pre-divider ratio for Input Reference 0 when used by Digital PLL0.
PRE0_1[20:0]	R/W	000000h	Pre-divider ratio for Input Reference 1 when used by Digital PLL0.
PRE0_2[20:0]	R/W	000000h	Pre-divider ratio for Input Reference 2 when used by Digital PLL0.
PRE0_3[20:0]	R/W	000000h	Pre-divider ratio for Input Reference 3 when used by Digital PLL0.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7F. Digital PLL0 Feedback Control Register Bit Field Locations and Descriptions

<table>
<tr><th colspan="9">Digital PLL0 Feedback Control Register Block Field Locations</th></tr>
<tr><th>Address (Hex)</th><th>D7</th><th>D6</th><th>D5</th><th>D4</th><th>D3</th><th>D2</th><th>D1</th><th>D0</th></tr>
<tr><td>0017</td><td colspan="8">M1_0_0[23:16]</td></tr>
<tr><td>0018</td><td colspan="8">M1_0_0[15:8]</td></tr>
<tr><td>0019</td><td colspan="8">M1_0_0[7:0]</td></tr>
<tr><td>001A</td><td colspan="8">M1_0_1[23:16]</td></tr>
<tr><td>001B</td><td colspan="8">M1_0_1[15:8]</td></tr>
<tr><td>001C</td><td colspan="8">M1_0_1[7:0]</td></tr>
<tr><td>001D</td><td colspan="8">M1_0_2[23:16]</td></tr>
<tr><td>001E</td><td colspan="8">M1_0_2[15:8]</td></tr>
<tr><td>001F</td><td colspan="8">M1_0_2[7:0]</td></tr>
<tr><td>0020</td><td colspan="8">M1_0_3[23:16]</td></tr>
<tr><td>0021</td><td colspan="8">M1_0_3[15:8]</td></tr>
<tr><td>0022</td><td colspan="8">M1_0_3[7:0]</td></tr>
<tr><td>0023</td><td colspan="4">LCKBW0[3:0]</td><td colspan="4">ACQBW0[3:0]</td></tr>
<tr><td>0024</td><td colspan="3">LCKDAMP0[2:0]</td><td colspan="3">ACQDAMP0[2:0]</td><td colspan="2">PLLGAIN0[1:0]</td></tr>
<tr><td>0025</td><td colspan="3">TGLCKDMP0[2:0]</td><td>TGLCKHYS0</td><td colspan="3">TGLCKBW0[2:0]</td><td>Rsvd</td></tr>
</table>

Digital PLL0 Feedback Control Register Block Field Locations

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0
0026	Rsvd							
0027	Rsvd							
0028	TGLCKTHR0[6:0]							Rsvd
0029	Rsvd							
002A	Rsvd							
002B	FFh							
002C	FFh							
002D	FFh							
002E	FFh							
002F	SLEW0[1:0]		Rsvd	HOLD0[1:0]		Rsvd	HOLDAVG0	FASTLCK0
0030	LOCK0[7:0]							
0031	Rsvd							DSM_INT0[8]
0032	DSM_INT0[7:0]							
0033	Rsvd			DSMFRAC0[20:16]				
0034	DSMFRAC0[15:8]							
0035	DSMFRAC0[7:0]							
0036	Rsvd							
0037	Rsvd							
0038	Rsvd							
0039	Rsvd							
003A	DSM_ORD0[1:0]		DCXOGAIN0[1:0]		Rsvd	DITHGAIN0[2:0]		

Digital PLL0 Feedback Configuration Register Block Field Descriptions

Bit Field Name	Field Type	Default Value	Description
M1_0_0[23:0]	R/W	070000h	M1 Feedback divider ratio for Input Reference 0 when used by Digital PLL0.
M1_0_1[23:0]	R/W	070000h	M1 Feedback divider ratio for Input Reference 1 when used by Digital PLL0.
M1_0_2[23:0]	R/W	070000h	M1 Feedback divider ratio for Input Reference 2 when used by Digital PLL0.
M1_0_3[23:0]	R/W	070000h	M1 Feedback divider ratio for Input Reference 3 when used by Digital PLL0.
LCKBW0[3:0]	R/W	0111b	Digital PLL0 Loop Bandwidth while locked: 0000 = 512mHz 0001 = 1Hz 0010 = 2Hz 0011 = 4Hz 0100 = 8Hz 0101 = 16Hz 0110 = 32Hz 0111 = 64Hz 1000 = 12 8Hz 1001 = 26Hz 1010 = 512Hz 1011 = Reserved 1100 through 1111 = Reserved

Digital PLL0 Feedback Configuration Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
ACQBW0[3:0]	R/W	0111b	Digital PLL0 Loop Bandwidth while in acquisition (not-locked): 0000 = 512mHz 0001 = 1Hz 0010 = 2Hz 0011 = 4Hz 0100 = 8Hz 0101 = 16Hz 0110 = 32Hz 0111 = 64Hz 1000 = 128Hz 1001 = 256Hz 1010 = 512Hz 1011 = Reserved 1100 through 1111 = Reserved
LCKDAMP0[2:0]	R/W	011b	Damping factor for Digital PLL0 while locked: 000 = Reserved 001 = 1 010 = 2 011 = 5 100 = 10 101 = 20 110 = Reserved 111 = Reserved
ACQDAMP0[2:0]	R/W	011b	Damping factor for Digital PLL0 while in acquisition (not locked): 000 = Reserved 001 = 1 010 = 2 011 = 5 100 = 10 101 = 20 110 = Reserved 111 = Reserved
PLLGAIN0[1:0]	R/W	01b	Digital Loop Filter Gain Settings for Digital PLL0: 00 = 0.5 01 = 1 10 = 1.5 11 = 2
TGLCKBW0[2:0]	R/W	011b	Loop Bandwidth Setting used when PLL0 is in tight lock and phase error is very close to 0: 000 = Off (use Loop Bandwidth LCKBW0[3:0]) 001 = 1Hz 010 = 2Hz 011 = 4Hz 100 = 8Hz 101 = 16Hz 110 = 32Hz 111 = 64Hz

Digital PLL0 Feedback Configuration Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
TGLCKDMP0[2:0]	R/W	000b	Tight Lock Operation Damping Factor for PLL0 000 = Off (Use Locked Damping Factor LCKDAMP0[2:0]) 001 = 1 010 = 2 011 = 5 100 = 10 101 = 20 110 = Reserved 111 = Reserved
TGLCKHYS0	R/W	0b	Tight Lock Hysteresis Enable for PLL0. Indicates when Tight Lock Operation is entered / exited. 0 = Non-hysteresis - enter & exit when phase error crosses threshold in TGLCKTHR0[6:0] 1 = Hysteresis - enter when phase error less than 5nsec and exit when larger than TGLCKTHR0[6:0]
TGLCKTHR0[6:0]	R/W	00h	Tight Lock Threshold for PLL0, used to decide when to enter / exit Tight Lock operation. Effective value = (entered value + 2) * (PLL0 period * 8 = 2.0-2.67nsec). Range is 4-345nsec.
SLEW0[1:0]	R/W	00b	Phase-slope control for Digital PLL0: 00 = no limit - controlled by loop bandwidth of Digital PLL0, NOTE1. 01 = 193 µsec/sec 10 = 24 µsec/sec 11 = Reserved
HOLD0[1:0]	R/W	00b	Holdover Averaging mode selection for Digital PLL0: 00 = Instantaneous mode - uses historical value 100ms prior to entering holdover 01 = Fast Average Mode 10 = Reserved 11 = Set VCO control voltage to $V_{CC}/2$
HOLDAVG0	R/W	0b	Holdover Averaging Enable for Digital PLL0: 0 = Holdover averaging disabled 1 = Holdover averaging enabled as defined in HOLD0[1:0]
FASTLCK0	R/W	0b	Enables Fast Lock operation for Digital PLL0: 0 = Normal locking using LCKBW0 & LCKDAMP0 fields in all cases 1 = Fast Lock mode using ACQBW0 & ACQDAMP0 when not phase locked and LCKBW0 & LCKDAMP0 once phase locked
LOCK0[7:0]	R/W	3Fh	Lock window size for Digital PLL0. Unsigned 2’s complement binary number in steps of 2.5ns, giving a total range of 640ns. Do not program to 0.
DSM_INT0[8:0]	R/W	02Dh	Integer portion of the Delta-Sigma Modulator value.
DSMFRAC0[20:0]	R/W	000000h	Fractional portion of Delta-Sigma Modulator value. Divide this number by 2^{21} to determine the actual fraction.
DSM_ORD0[1:0]	R/W	11b	Delta-Sigma Modulator Order for Digital PLL0: 00 = Delta-Sigma Modulator disabled 01 = 1st order modulation 10 = 2nd order modulation 11 = 3rd order modulation

Digital PLL0 Feedback Configuration Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
DCXOGAIN0[1:0]	R/W	01b	Multiplier applied to instantaneous frequency error before it is applied to the Digitally Controlled Oscillator in Digital PLL0: 00 = 0.5 01 = 1 10 = 2 11 = 4
DITHGAIN0[2:0]	R/W	000b	Dither Gain setting for Digital PLL0: 000 = no dither 001 = Least Significant Bit (LSB) only 010 = 2 LSBs 011 = 4 LSBs 100 = 8 LSBs 101 = 16 LSBs 110 = 32 LSBs 111 = 64 LSBs
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

NOTE 1: Settings other than “00” may result in a significant increase in initial lock time.

Table 7G. Digital PLL1 Input Control Register Bit Field Locations and Descriptions

Digital PLL1 Input Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
003B	REFSEL1[2:0]			FBSEL1[2:0]			RVRT1	SWMODE1
003C	PRI1_3[1:0]		PRI1_2[1:0]		PRI1_1[1:0]		PRI1_0[1:0]	
003D	REFDIS1_3	REFDIS1_2	REFDIS1_1	REFDIS1_0	Rsvd	Rsvd	STATE1[1:0]	
003E	Rsvd			PRE1_0[20:16]				
003F	PRE1_0[15:8]							
0040	PRE1_0[7:0]							
0041	Rsvd			PRE1_1[20:16]				
0042	PRE1_1[15:8]							
0043	PRE1_1[7:0]							
0044	Rsvd			PRE1_2[20:16]				
0045	PRE1_2[15:8]							
0046	PRE1_2[7:0]							
0047	Rsvd			PRE1_3[20:16]				
0048	PRE1_3[15:8]							
0049	PRE1_3[7:0]							

Digital PLL1 Input Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
REFSEL1[2:0]	R/W	000b	Input reference selection for Digital PLL1: 000 = Automatic selection 001 = Manual selection by GPIO inputs 010 through 011 = Reserved 100 = Force selection of Input Reference 0 101 = Force selection of Input Reference 1 110 = Force selection of Input Reference 2 111 = Force selection of Input Reference 3
FBSEL1[2:0]	R/W	000b	Feedback mode selection for Digital PLL1: 000 through 011 = internal feedback divider 100 = external feedback from Input Reference 0 101 = external feedback from Input Reference 1 110 = external feedback from Input Reference 2 111 = external feedback from Input Reference 3
RVRT1	R/W	1b	Automatic switching mode for Digital PLL1: 0 = non-revertive switching 1 = revertive switching
SWMODE1	R/W	1b	Controls how Digital PLL1 adjusts output phase when switching between input references: 0 = Absorb any phase differences between old & new input references 1 = Track to follow new input reference’s phase using phase-slope limiting
PRI1_0[1:0]	R/W	00b	Switchover priority for Input Reference 0 when used by Digital PLL1: 00 = 1st priority 01 = 2nd priority 10 = 3rd priority 11 = 4th priority
PRI1_1[1:0]	R/W	01b	Switchover priority for Input Reference 1 when used by Digital PLL1: 00 = 1st priority 01 = 2nd priority 10 = 3rd priority 11 = 4th priority
PRI1_2[1:0]	R/W	10b	Switchover priority for Input Reference 2 when used by Digital PLL1: 00 = 1st priority 01 = 2nd priority 10 = 3rd priority 11 = 4th priority
PRI1_3[1:0]	R/W	11b	Switchover priority for Input Reference 3 when used by Digital PLL1: 00 = 1st priority 01 = 2nd priority 10 = 3rd priority 11 = 4th priority
REFDIS1_0	R/W	0b	Input Reference 0 Switching Selection Disable for Digital PLL1: 0 = Input Reference 0 is included in the switchover sequence for Digital PLL1 1 = Input Reference 0 is not included in the switchover sequence for Digital PLL1
REFDIS1_1	R/W	0b	Input Reference 1 Switching Selection Disable for Digital PLL1: 0 = Input Reference 1 is included in the switchover sequence for Digital PLL1 1 = Input Reference 1 is not included in the switchover sequence for Digital PLL1
REFDIS1_2	R/W	0b	Input Reference 2 Switching Selection Disable for Digital PLL1: 0 = Input Reference 2 is included in the switchover sequence for Digital PLL1 1 = Input Reference 2 is not included in the switchover sequence for Digital PLL1
REFDIS1_3	R/W	0b	Input Reference 3 Switching Selection Disable for Digital PLL1: 0 = Input Reference 3 is included in the switchover sequence for Digital PLL1 1 = Input Reference 3 is not included in the switchover sequence for Digital PLL1

Digital PLL1 Input Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
STATE1[1:0]	R/W	00b	Digital PLL1 State Machine Control: 00 = Run automatically 01 = Force FREERUN state - set this if in Synthesizer Mode for PLL1 10 = Force NORMAL state 11 = Force HOLDOVER state
PRE1_0[20:0]	R/W	000000h	Pre-divider ratio for Input Reference 0 when used by Digital PLL1.
PRE1_1[20:0]	R/W	000000h	Pre-divider ratio for Input Reference 1 when used by Digital PLL1.
PRE1_2[20:0]	R/W	000000h	Pre-divider ratio for Input Reference 2 when used by Digital PLL1.
PRE1_3[20:0]	R/W	000000h	Pre-divider ratio for Input Reference 3 when used by Digital PLL1.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7H. Digital PLL1 Feedback Control Register Bit Field Locations and Descriptions

Digital PLL1 Feedback Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
004A	M1_1_0[23:16]							
004B	M1_1_0[15:8]							
004C	M1_1_0[7:0]							
004D	M1_1_1[23:16]							
004E	M1_1_1[15:8]							
004F	M1_1_1[7:0]							
0050	M1_1_2[23:16]							
0051	M1_1_2[15:8]							
0052	M1_1_2[7:0]							
0053	M1_1_3[23:16]							
0054	M1_1_3[15:8]							
0055	M1_1_3[7:0]							
0056	LCKBW1[3:0]				ACQBW1[3:0]			
0057	LCKDAMP1[2:0]			ACQDAMP1[2:0]			PLLGAIN1[1:0]	
0058	TGLCKDMP1[2:0]			TGLCKHYS1	TGLCKBW1[2:0]			Rsvd
0059	Rsvd							
005A	Rsvd							
005B	TGLCKTHR1[6:0]							Rsvd
005C	Rsvd							
005D	Rsvd							
005E	FFh							
005F	FFh							
0060	FFh							
0061	FFh							
0062	SLEW1[1:0]		Rsvd	HOLD1[1:0]		Rsvd	HOLDAVG1	FASTLCK1
0063	LOCK1[7:0]							
0064	Rsvd							DSM_INT1[8]
0065	DSM_INT1[7:0]							
0066	Rsvd			DSMFRAC1[20:16]				

Digital PLL1 Feedback Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0067	DSMFRAC1[15:8]							
0068	DSMFRAC1[7:0]							
0069	Rsvd							
006A	Rsvd							
006B	Rsvd							
006C	Rsvd							
006D	DSM_ORD1[1:0]		DCXOGAIN1[1:0]		Rsvd	DITHGAIN1[2:0]		

Digital PLL1 Feedback Configuration Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
M1_1_0[23:0]	R/W	070000h	M1 Feedback divider ratio for Input Reference 0 when used by Digital PLL1.
M1_1_1[23:0]	R/W	070000h	M1 Feedback divider ratio for Input Reference 1 when used by Digital PLL1.
M1_1_2[23:0]	R/W	070000h	M1 Feedback divider ratio for Input Reference 2 when used by Digital PLL1.
M1_1_3[23:0]	R/W	070000h	M1 Feedback divider ratio for Input Reference 3 when used by Digital PLL1.
LCKBW1[3:0]	R/W	0111b	Digital PLL1 Loop Bandwidth while locked: 0000 = 512mHz 0001 = 1Hz 0010 = 2Hz 0011 = 4Hz 0100 = 8Hz 0101 = 16Hz 0110 = 32Hz 0111 = 64Hz 1000 = 128Hz 1001 = 256Hz 1010 = 512Hz 1011 = Reserved 1100 through 1111 = Reserved
ACQBW1[3:0]	R/W	0111b	Digital PLL1 Loop Bandwidth while in acquisition (not-locked): 0000 = 512mHz 0001 = 1Hz 0010 = 2Hz 0011 = 4Hz 0100 = 8Hz 0101 = 16Hz 0110 = 32Hz 0111 = 64Hz 1000 = 128Hz 1001 = 256Hz 1010 = 512Hz 1011 = Reserved 1100 through 1111 = Reserved
LCKDAMP1[2:0]	R/W	011b	Damping factor for Digital PLL1 while locked: 000 = Reserved 001 = 1 010 = 2 011 = 5 100 = 10 101 = 20 110 = Reserved 111 = Reserved

Digital PLL1 Feedback Configuration Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
ACQDAMP1[2:0]	R/W	011b	Damping factor for Digital PLL1 while in acquisition (not locked): 000 = Reserved 001 = 1 010 = 2 011 = 5 100 = 10 101 = 20 110 = Reserved 111 = Reserved
PLLGAIN1[1:0]	R/W	01b	Digital Loop Filter Gain Settings for Digital PLL1: 00 = 0.5 01 = 1.0 10 = 1.5 11 = 2.0
TGLCKBW1[2:0]	R/W	011b	Loop Bandwidth Setting used when PLL1 is in tight lock and phase error is very close to 0: 000 = Off (Use Locked loop bandwidth LCKBW1[3:0]) 001 = 1Hz 010 = 2Hz 011 = 4Hz 100 = 8Hz 101 = 16Hz 110 = 32Hz 111 = 64Hz
TGLCKDMP1[2:0]	R/W	000b	Tight Lock Operation Damping Factor for PLL1 000 = Off (Use Locked Damping Factor LCKDAMP1[2:0]) 001 = 1 010 = 2 011 = 5 100 = 10 101 = 20 110 = Reserved 111 = Reserved
TGLCKHYS1	R/W	0b	Tight Lock Hysteresis Enable for PLL1. Indicates when Tight Lock Operation is entered / exited. 0 = Non-hysteresis - enter & exit when phase error crosses threshold in TGLCKTHR1[6:0] 1 = Hysteresis - enter when phase error less than 5nsec and exit when larger than TGLCKTHR1[6:0]
TGLCKTHR1[6:0]	R/W	00h	Tight Lock Threshold for PLL1, used to decide when to enter / exit Tight Lock operation. Effective value = (entered value + 2) * (PLL0 period * 8 = 2.0-2.67nsec). Range is 4-345nsec.
SLEW1[1:0]	R/W	00b	Phase-slope control for Digital PLL1: 00 = no limit - controlled by loop bandwidth of Digital PLL1, NOTE 1. 01 = 193µsec/sec 10 = 24µsec/sec 11 = Reserved
HOLD1[1:0]	R/W	00b	Holdover Averaging mode selection for Digital PLL1: 00 = Instantaneous mode - uses historical value 100ms prior to entering holdover 01 = Fast Average Mode 10 = Reserved 11 = Set VCO control voltage to $V_{CC}/2$

Digital PLL1 Feedback Configuration Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
HOLDAVG1	R/W	0b	Holdover Averaging Enable for Digital PLL1: 0 = Holdover averaging disabled 1 = Holdover averaging enabled as defined in HOLD1[1:0]
FASTLCK1	R/W	0b	Enables Fast Lock operation for Digital PLL1: 0 = Normal locking using LCKBW1 & LCKDAMP1 fields in all cases 1 = Fast Lock mode using ACQBW1 & ACQDAMP1 when not phase locked and LCKBW1 & LCKDAMP1 once phase locked
LOCK1[7:0]	R/W	3Fh	Lock window size for Digital PLL1. Unsigned 2's complement binary number in steps of 2.5ns, giving a total range of 640ns. Do not program to 0.
DSM_INT1[8:0]	R/W	02Dh	Integer portion of the Delta-Sigma Modulator value.
DSMFRAC1[20:0]	R/W	000000h	Fractional portion of Delta-Sigma Modulator value. Divide this number by 2^{21} to determine the actual fraction.
DSM_ORD1[1:0]	R/W	11b	Delta-Sigma Modulator Order for Digital PLL1. 00 = Delta-Sigma Modulator disabled 01 = 1st order modulation 10 = 2nd order modulation 11 = 3rd order modulation
DCXOGAIN1[1:0]	R/W	01b	Multiplier applied to instantaneous frequency error before it is applied to the Digitally Controlled Oscillator in Digital PLL1. 00 = 0.5 01 = 1.0 10 = 2.0 11 = 4.0
DITHGAIN1[2:0]	R/W	000b	Dither Gain setting for Digital PLL1. 000 = no dither 001 = Least Significant Bit (LSB) only 010 = 2 LSBs 011 = 4 LSBs 100 = 8 LSBs 101 = 16 LSBs 110 = 32 LSBs 111 = 64 LSBs
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

NOTE 1: Settings other than “00” may result in a significant increase in initial lock time.

Table 7I. GPIO Control Register Bit Field Locations and Descriptions

The values observed on any GPIO pins that are used as general purpose inputs are visible in the GPI[7:0] register that is located at location 0219h near a number of other read-only registers.

GPIO Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
006E	GPIO_DIR[7:0]							
006F	GPI7SEL[2]	GPI6SEL[2]	GPI5SEL[2]	GPI4SEL[2]	GPI3SEL[2]	GPI2SEL[2]	GPI1SEL[2]	GPI0SEL[2]
0070	GPI7SEL[1]	GPI6SEL[1]	GPI5SEL[1]	GPI4SEL[1]	GPI3SEL[1]	GPI2SEL[1]	GPI1SEL[1]	GPI0SEL[1]
0071	GPI7SEL[0]	GPI6SEL[0]	GPI5SEL[0]	GPI4SEL[0]	GPI3SEL[0]	GPI2SEL[0]	GPI1SEL[0]	GPI0SEL[0]
0072	GPO7SEL[2]	GPO6SEL[2]	GPO5SEL[2]	GPO4SEL[2]	GPO3SEL[2]	GPO2SEL[2]	GPO1SEL[2]	GPO0SEL[2]
0073	GPO7SEL[1]	GPO6SEL[1]	GPO5SEL[1]	GPO4SEL[1]	GPO3SEL[1]	GPO2SEL[1]	GPO1SEL[1]	GPO0SEL[1]

GPIO Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0074	GPO7SEL[0]	GPO6SEL[0]	GPO5SEL[0]	GPO4SEL[0]	GPO3SEL[0]	GPO2SEL[0]	GPO1SEL[0]	GPO0SEL[0]
0075	Rsvd							
0076	GPO[7:0]							

GPIO Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
GPIO_DIR[7:0]	R/W	00h	Direction control for General-Purpose I/O Pins GPIO[7:0]: 0 = input mode 1 = output mode
GPI0SEL[2:0]	R/W	000b	Function of GPIO[0] pin when set to input mode by GPIO_DIR[0] register bit: 000 = General Purpose Input (value on GPIO[0] pin directly reflected in GPI[0] register bit) 001 = Output Enable control for output Q0 010 = reserved 011 = reserved 100 through 111 = reserved
GPI1SEL[2:0]	R/W	000b	Function of GPIO[1] pin when set to input mode by GPIO_DIR[1] register bit: 000 = General Purpose Input (value on GPIO[1] pin directly reflected in GPI[1] register bit) 001 = Output Enable control for output Q1 010 = reserved 011 through 111 = reserved
GPI2SEL[2:0]	R/W	000b	Function of GPIO[2] pin when set to input mode by GPIO_DIR[2] register bit: 000 = General Purpose Input (value on GPIO[2] pin directly reflected in GPI[2] register bit) 001 = Output Enable control for output Q2 010 = reserved 011 = reserved 100 = reserved 101 = CSEL0[0]: Manual Clock Select Input 0 for PLL0 110 through 111 = reserved
GPI3SEL[2:0]	R/W	000b	Function of GPIO[3] pin when set to input mode by GPIO_DIR[3] register bit: 000 = General Purpose Input (value on GPIO[3] pin directly reflected in GPI[3] register bit) 001 = Output Enable control for output Q3 010 = reserved 011 = reserved 101 = CSEL1[0]: Manual Clock Select Input 0 for PLL1 100, 110, 111 = reserved
GPI4SEL[2:0]	R/W	000b	Function of GPIO[4] pin when set to input mode by GPIO_DIR[4] register bit: 000 = General Purpose Input (value on GPIO[4] pin directly reflected in GPI[4] register bit) 001 = Output Enable control for output Q4 010 through 111 = reserved
GPI5SEL[2:0]	R/W	000b	Function of GPIO[5] pin when set to input mode by GPIO_DIR[5] register bit: 000 = General Purpose Input (value on GPIO[5] pin directly reflected in GPI[5] register bit 001 = Output Enable control for output Q5 010 through 111 = reserved
GPI6SEL[2:0]	R/W	000b	Function of GPIO[6] pin when set to input mode by GPIO_DIR[6] register bit: 000 = General Purpose Input (value on GPIO[6] pin directly reflected in GPI[6] register bit 001 = Output Enable control for output Q6 101 = CSEL0[1]: Manual Clock Select Input 1 for PLL0 010, 011, 100, 110, 111 = reserved
GPI7SEL[2:0]	R/W	000b	Function of GPIO[7] pin when set to input mode by GPIO_DIR[7] register bit: 000 = General Purpose Input (value on GPIO[7] pin directly reflected in GPI[7] register bit 001 = Output Enable control for output Q7 101 = CSEL1[1]: Manual Clock Select Input 1 for PLL1 010, 011, 100, 110, 111 = reserved

GPIO Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
GPO0SEL[2:0]	R/W	000b	Function of GPIO[0] pin when set to output mode by GPIO_DIR[0] register bit: 000 = General Purpose Output (value in GPO[0] register bit driven on GPIO[0] pin 001 = Loss-of-Lock Status Flag for Digital PLL0 reflected on GPIO[0] pin 010 = Loss-of-Lock Status Flag for Digital PLL1 reflected on GPIO[0] pin 011 = reserved 100 = reserved 101 = reserved 110 through 111 = reserved
GPO1SEL[2:0]	R/W	000b	Function of GPIO[1] pin when set to output mode by GPIO_DIR[1] register bit: 000 = General Purpose Output (value in GPO[1] register bit driven on GPIO[1] pin 001 = Holdover Status Flag for Digital PLL0 reflected on GPIO[1] pin 010 = Holdover Status Flag for Digital PLL1 reflected on GPIO[1] pin 011 = reserved 100 = reserved 101 = reserved 110 = reserved 111 = reserved
GPO2SEL[2:0]	R/W	000b	Function of GPIO[2] pin when set to output mode by GPIO_DIR[2] register bit: 000 = General Purpose Output (value in GPO[2] register bit driven on GPIO[2] pin 001 = Loss-of-Signal Flag for Input Reference 0 reflected on GPIO[2] pin 010 = reserved 011 = reserved 100 = reserved 101 through 111 = reserved
GPO3SEL[2:0]	R/W	000b	Function of GPIO[3] pin when set to output mode by GPIO_DIR[3] register bit: 000 = General Purpose Output (value in GPO[3] register bit driven on GPIO[3] pin 001 = Loss-of-Lock Status Flag for Digital PLL1 reflected on GPIO[3] pin 010 = Loss-of-Signal Status Flag for Input Reference 1 reflected on GPIO[3] pin 011 = reserved 100 = reserved 101 through 111 = reserved
GPO4SEL[2:0]	R/W	000b	Function of GPIO[4] pin when set to output mode by GPIO_DIR[4] register bit: 000 = General Purpose Output (value in GPO[4] register bit driven on GPIO[4] pin 001 = Holdover Status Flag for Digital PLL1 reflected on GPIO[4] pin 010 through 111 = reserved
GPO5SEL[2:0]	R/W	000b	Function of GPIO[5] pin when set to output mode by GPIO_DIR[5] register bit: 000 = General Purpose Output (value in GPO[5] register bit driven on GPIO[5] pin 001 = Loss-of-Signal Status Flag for Input Reference 1 reflected on GPIO[5] pin 010 through 111 = reserved
GPO6SEL[2:0]	R/W	000b	Function of GPIO[6] pin when set to output mode by GPIO_DIR[6] register bit: 000 = General Purpose Output (value in GPO[6] register bit driven on GPIO[6] pin 001 = Loss-of-Signal Status Flag for Input Reference 2 reflected on GPIO[6] pin 010 through 111 = reserved
GPO7SEL[2:0]	R/W	000b	Function of GPIO[7] pin when set to output mode by GPIO_DIR[7] register bit: 000 = General Purpose Output (value in GPO[7] register bit driven on GPIO[7] pin 001 = Loss-of-Signal Status Flag for Input Reference 3 reflected on GPIO[7] pin 010 through 111 = reserved
GPO[7:0]	R/W	00h	Output Values reflect on pin GPIO[7:0] when General-Purpose Output Mode selected.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7J. Output Driver Control Register Bit Field Locations and Descriptions

Output Driver Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0077	OUTEN[7:0]							
0078	POL_Q[7:0]							
0079	OUTMODE7[2:0]			SE_MODE7	OUTMODE6[2:0]			SE_MODE6
007A	OUTMODE5[2:0]			SE_MODE5	OUTMODE4[2:0]			SE_MODE4
007B	OUTMODE3[2:0]			SE_MODE3	OUTMODE2[2:0]			SE_MODE2
007C	OUTMODE1[2:0]			SE_MODE1	OUTMODE0[2:0]			SE_MODE0

Output Driver Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
OUTEN[7:0]	R/W	00h	Output Enable control for Clock Outputs Q[7:0], nQ[7:0]: 0 = Qn is in a high-impedance state 1 = Qn is enabled as indicated in appropriate OUTMODEn[2:0] register field
POL_Q[7:0]	R/W	00h	Polarity of Clock Outputs Q[7:0], nQ[7:0]: 0 = normal polarity 1 = inverted polarity
OUTMODEm [2:0]	R/W	001b	Output Driver Mode of Operation for Clock Output Pair Qm, nQm: 000 = High-impedance 001 = LVPECL 010 = LVDS 011 = LVCMOS 100 = reserved 101 - 111 = reserved
SE_MODEm	R/W	0b	Behavior of Output Pair Qm, nQm when LVCMOS operation is selected (Must be 0 if LVDS or LVPECL output style is selected): 0 = Qm and nQm are both the same frequency but inverted in phase 1 = Qm and nQm are both the same frequency and phase

Table 7K. Output Divider Control Register Bit Field Locations and Descriptions

Output Divider Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
007D	Rsvd						NS1_Q0[1:0]	
007E	NS2_Q0[15:8]							
007F	NS2_Q0[7:0]							
0080	Rsvd						NS1_Q1[1:0]	
0081	NS2_Q1[15:8]							
0082	NS2_Q1[7:0]							
0083	Rsvd						N_Q2[17:16]	
0084	N_Q2[15:8]							
0085	N_Q2[7:0]							
0086	Rsvd						N_Q3[17:16]	
0087	N_Q3[15:8]							
0088	N_Q3[7:0]							
0089	Rsvd						NS1_Q4[1:0]	
008A	NS2_Q4[15:8]							
008B	NS2_Q4[7:0]							

Output Divider Control Register Block Field Locations

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0
008C	Rsvd						NS1_Q5[1:0]	
008D	NS2_Q5[15:8]							
008E	NS2_Q5[7:0]							
008F	Rsvd						NS1_Q6[1:0]	
0090	NS2_Q6[15:8]							
0091	NS2_Q6[7:0]							
0092	Rsvd						NS1_Q7[1:0]	
0093	NS2_Q7[15:8]							
0094	NS2_Q7[7:0]							
0095	Rsvd				NFRAC_Q2[27:24]			
0096	NFRAC_Q2[23:16]							
0097	NFRAC_Q2[15:8]							
0098	NFRAC_Q2[7:0]							
0099	Rsvd				NFRAC_Q3[27:24]			
009A	NFRAC_Q3[23:16]							
009B	NFRAC_Q3[15:8]							
009C	NFRAC_Q3[7:0]							

Output Divider Control Register Block Field Descriptions

Bit Field Name	Field Type	Default Value	Description
NS1_Qm[1:0] (m = 0,1)	R/W	10b	1st Stage Output Divider Ratio for Output Clock Qm, nQm (m = 0,1): 00 = /5 01 = /6 10 = /4 11 = Output Qm, nQm not switching
NS1_Qm[1:0] (m = 4, 5, 6, 7)	R/W	10b	1st Stage Output Divider Ratio for Output Clock Qm, nQm (m = 4, 5, 6, 7): 00 = /5 01 = /6 10 = /4 11 = /1 (Do not use this selection if PLL0 or PLL1 are the source since the 2nd-stage divider has a limit of 1GHz).
NS2_Qm[15:0]	R/W	0002h	2nd Stage Output Divider Ratio for Output Clock Qm, nQm (m = 0, 1, 4, 5, 6, 7): Actual divider ratio is 2x the value written here. A value of 0 in this register will bypass the second stage of the divider.
N_Qm[17:0]	R/W	00008h	Integer Portion of Output Divider Ratio for Output Clock Qm, nQm (m = 2, 3): Values of 0, 1 or 2 cannot be written to this register. Actual integer portion is 2x the value written here.
NFRAC_Qm[27:0]	R/W	0000000h	Fractional Portion of Output Divider Ratio for Output Clock Qm, nQm (m = 2, 3): Actual fractional portion is 2x the value written here. Fraction = (NFRAC_Qm * 2) * 2^{-28}
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7L. Output Clock Phase Adjustment Control Register Bit Field Locations and Descriptions

Output Clock Phase Adjustment Control Control Register Block Field Locations

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0
009D	CRSE_TRG[7:0]							
009E	Rsvd			COARSE0[4:0]				
009F	Rsvd			COARSE1[4:0]				
00A0	Rsvd			COARSE2[4:0]				
00A1	Rsvd			COARSE3[4:0]				
00A2	Rsvd			COARSE4[4:0]				
00A3	Rsvd			COARSE5[4:0]				
00A4	Rsvd			COARSE6[4:0]				
00A5	Rsvd			COARSE7[4:0]				
00A6	Rsvd				FINE2[3:0]			
00A7	Rsvd				FINE3[3:0]			

Output Clock Phase Adjustment Control Register Block Field Descriptions

Bit Field Name	Field Type	Default Value	Description
CRSE_TRG[7:0]	R/W	00h	Trigger Coarse Phase Adjustment for output Qm, nQm by amount specified in COARSEm[4:0] register upon 0→1 transition of this Trigger register bit. Please ensure the PA_BUSYm status bit is 0 before triggering another adjustment cycle on that particular output. Trigger bit must be returned to 0 before another delay cycle can be triggered.
COARSEm[4:0]	R/W	00000b	Number of periods to be inserted when Trigger happens. Relevant clock period is determined by the clock source selected for output Qm, nQm in its CLK_SELm register field.
FINEm[3:0]	R/W	0000b	Number of 1/16ths of the relevant clock period to add to the phase of output Qm, nQm (m = 2, 3). Relevant clock period is determined by the clock source selected for output Qm, nQm in its CLK_SELm register field. The PLLn_SYN bit for the PLL driving the output divider for the output in question must be toggled to make this value take effect. Note that toggling the PLLn_SYN bit will clear all Coarse delay values and so Fine delay should be set first.
Rsvd	R/W	-	Always write a 0 to this bit location. Read values are not defined.

Table 7M. Output Clock Source Control Register Bit Field Locations and Descriptions

Output Clock Source Control Register Block Field Locations

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0
00A8	Rsvd		PLL1_SYN	PLL0_SYN	CLK_SEL3	CLK_SEL2	CLK_SEL1	CLK_SEL0
00A9	Rsvd	CLK_SEL5[2:0]			Rsvd	CLK_SEL4[2:0]		
00AA	Rsvd	CLK_SEL7[2:0]			Rsvd	CLK_SEL6[2:0]		
00AB	10		10		Rsvd		Rsvd	

Output Clock Source Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
PLL1_SYN	R/W	0b	Output Synchronization Control for Outputs Derived from PLL1. Setting this bit from 0→1 will cause the output divider(s) for the affected outputs to be held in reset. Setting this bit from 1→0 will release all the output divider(s) for the affected outputs to run from the same point in time with the coarse output phase adjustment reset to 0.
PLL0_SYN	R/W	0b	Output Synchronization Control for Outputs Derived from PLL0. Setting this bit from 0→1 will cause the output divider(s) for the affected outputs to be held in reset. Setting this bit from 1→0 will release all the output divider(s) for the affected outputs to run from the same point in time with the coarse output phase adjustment reset to 0.
CLK_SEL0	R/W	0b	Clock Source Selection for output Q0, nQ0: 0 = PLL0 1 = PLL1
CLK_SEL1	R/W	1b	Clock Source Selection for output Q1, nQ1: 0 = PLL0 1 = PLL1
CLK_SEL2	R/W	0b	Clock Source Selection for output Q2, nQ2: 0 = PLL0 1 = PLL1
CLK_SEL3	R/W	1b	Clock Source Selection for output Q3, nQ3: 0 = PLL0 1 = PLL1
CLK_SEL4[2:0]	R/W	000b	Clock Source Selection for output Q4, nQ4: Do not select Input Reference 0, 1 or 2 if that input is faster than 250MHz: 000 = PLL0 001 = PLL1 010 = Output Q2, nQ2 011 = Output Q3, nQ3 100 = Input Reference 0 (CLK0) 101 = Input Reference 1 (CLK1) 110 = Input Reference 2 (CLK2) 111 = Crystal Input
CLK_SEL5[2:0]	R/W	010b	Clock Source Selection for output Q5, nQ5: Do not select Input Reference 0, 1 or 2 if that input is faster than 250MHz: 000 = PLL0 001 = PLL1 010 = Output Q2, nQ2 011 = Output Q3, nQ3 100 = Input Reference 0 (CLK0) 101 = Input Reference 1 (CLK1) 110 = Input Reference 2 (CLK2) 111 = Crystal Input

Output Clock Source Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
CLK_SEL6[2:0]	R/W	110b	Clock Source Selection for output Q6, nQ6: Do not select Input Reference 0, 1 or 2 if that input is faster than 250MHz: 000 = PLL0 001 = PLL1 010 = Output Q2, nQ2 011 = Output Q3, nQ3 100 = Input Reference 0 (CLK0) 101 = Input Reference 1 (CLK1) 110 = Input Reference 2 (CLK2) 111 = Crystal Input
CLK_SEL7[2:0]	R/W	101b	Clock Source Selection for output Q7, nQ7: Do not select Input Reference 0, 1 or 2 if that input is faster than 250MHz: 000 = PLL0 001 = PLL1 010 = Output Q2, nQ2 011 = Output Q3, nQ3 100 = Input Reference 0 (CLK0) 101 = Input Reference 1 (CLK1) 110 = Input Reference 2 (CLK2) 111 = Crystal Input
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7N. Analog PLL0 Control Register Bit Field Locations and Descriptions

Please contact IDT through one of the methods listed on the last page of this datasheet for details on how to set these fields for a particular user configuration.

Analog PLL0 Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
00AC	CPSET_0[2:0]			RS_0[1:0]		CP_0[1:0]		WPOST_0
00AD	Rsvd				SYN_MODE0	Rsvd	DLCNT_0	DBITM_0
00AE	Rsvd		VCOMAN_0	DBIT1_0[4:0]				
00AF	Rsvd			DBIT2_0[4:0]				

Analog PLL0 Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
CPSET_0[2:0]	R/W	100b	Charge Pump Current Setting for Analog PLL0: 000 = 110µA 001 = 220µA 010 = 330µA 011 = 440µA 100 = 550µA 101 = 660µA 110 = 770µA 111 = 880µA
RS_0[1:0]	R/W	01b	Internal Loop Filter Series Resistor Setting for Analog PLL0: 00 = 330Ω 01 = 640Ω 10 = 1.2kΩ 11 = 1.79kΩ
CP_0[1:0]	R/W	01b	Internal Loop Filter Parallel Capacitor Setting for Analog PLL0: 00 = 40pF 01 = 80pF 10 = 140pF 11 = 200pF
WPOST_0	R/W	1b	Internal Loop Filter 2nd Pole Setting for Analog PLL0: 0 = Rpost = 497Ω, Cpost = 40pF 1 = Rpost = 1.58kΩ, Cpost = 40pF
DLCNT_0	R/W	1b	Digital Lock Count Setting for Analog PLL0. Set to 0 if external capacitor (CAP0) for PLL0 is >95nF, otherwise set to 1: 0 = 1 ppm accuracy 1 = 16 ppm accuracy
DBITM_0	R/W	0b	Digital Lock Manual Override Setting for Analog PLL0: 0 = Automatic Mode 1 = Manual Mode
VCOMAN_0	R/W	1b	Manual Lock Mode VCO Selection Setting for Analog PLL0: 0 = VCO2 1 = VCO1
DBIT1_0[4:0]	R/W	01011b	Manual Mode Digital Lock Control Setting for VCO1 in Analog PLL0.
DBIT2_0[4:0]	R/W	00000b	Manual Mode Digital Lock Control Setting for VCO2 in Analog PLL0.
SYN_MODE0	R/W	0b	Frequency Synthesizer Mode Control for PLL0: 0 = PLL0 jitter attenuates and translates one or more input references 1 = PLL0 synthesizes output frequencies using only the crystal as a reference Note that the STATE0[1:0] field in the Digital PLL0 Control Register must be set to Force Freerun state.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7O. Analog PLL1 Control Register Bit Field Locations and Descriptions

Please contact IDT through one of the methods listed on the last page of this datasheet for details on how to set these fields for a particular user configuration.

Analog PLL1 Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
00B0	CPSET_1[2:0]			RS_1[1:0]		CP_1[1:0]		WPOST_1
00B1	Rsvd				SYN_MODE1	Rsvd	DLCNT_1	DBITM_1
00B2	Rsvd		VCOMAN_1	DBIT1_1[4:0]				
00B3	Rsvd			DBIT2_1[4:0]				

Analog PLL1 Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
CPSET_1[2:0]	R/W	100b	Charge Pump Current Setting for Analog PLL1: 000 = 110 µA 001 = 220 µA 010 = 330 µA 011 = 440 µA 100 = 550 µA 101 = 660 µA 110 = 770 µA 111 = 880 µA
RS_1[1:0]	R/W	01b	Internal Loop Filter Series Resistor Setting for Analog PLL1: 00 = 330 Ω 01 = 640 Ω 10 = 1.2 kΩ 11 = 1.79 kΩ
CP_1[1:0]	R/W	01b	Internal Loop Filter Parallel Capacitor Setting for Analog PLL1: 00 - 40 pF 01 = 80 pF 10 = 140 pF 11 = 200 pF
WPOST_1	R/W	1b	Internal Loop Filter 2nd Pole Setting for Analog PLL1: 0 = Rpost = 497 Ω, Cpost = 40pF 1 = Rpost = 1.58 kΩ, Cpost = 40pF
DLCNT_1	R/W	1b	Digital Lock Count Setting for Analog PLL1: Set to 0 if external capacitor (CAP1) for PLL1 is >95nF, otherwise set to 1: 0 = 1 ppm accuracy 1 = 16 ppm accuracy
DBITM_1	R/W	0b	Digital Lock Manual Override Setting for Analog PLL1: 0 = Automatic Mode 1 = Manual Mode
VCOMAN_1	R/W	1b	Manual Lock Mode VCO Selection Setting for Analog PLL1: 0 = VCO2 1 = VCO1
DBIT1_1[4:0]	R/W	01011b	Manual Mode Digital Lock Control Setting for VCO1 in Analog PLL1:
DBIT2_1[4:0]	R/W	00000b	Manual Mode Digital Lock Control Setting for VCO2 in Analog PLL1.
SYN_MODE1	R/W	0b	Frequency Synthesizer Mode Control for PLL1: 0 = PLL1 jitter attenuates and translates one or more input references. 1 = PLL1 synthesizes output frequencies using only the crystal as a reference. Note that the STATE1[1:0] field in the Digital PLL1 Control Register must be set to Force Freerun state.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7P. Power Down Control Register Bit Field Locations and Descriptions

<table>
<tr><th colspan="9">Power Down Control Register Block Field Locations</th></tr>
<tr><th>Address (Hex)</th><th>D7</th><th>D6</th><th>D5</th><th>D4</th><th>D3</th><th>D2</th><th>D1</th><th>D0</th></tr>
<tr><td>00B4</td><td colspan="7">Rsvd</td><td>DBL_DIS</td></tr>
<tr><td>00B5</td><td colspan="4">Rsvd</td><td>CLK3_DIS</td><td>CLK2_DIS</td><td>CLK1_DIS</td><td>CLK0_DIS</td></tr>
<tr><td>00B6</td><td colspan="3">Rsvd</td><td>PLL1_DIS</td><td colspan="4">Rsvd</td></tr>
<tr><td>00B7</td><td>Q7_DIS</td><td>Q6_DIS</td><td>Q5_DIS</td><td>Q4_DIS</td><td>Q3_DIS</td><td>Q2_DIS</td><td>Q1_DIS</td><td>Q0_DIS</td></tr>
<tr><td>00B8</td><td colspan="4">Rsvd</td><td>DPLL1_DIS</td><td>DPLL0_DIS</td><td>CALRST1</td><td>CALRST0</td></tr>
</table>

<table>
<tr><th colspan="4">Power Down Control Register Block Field Descriptions</th></tr>
<tr><th>Bit Field Name</th><th>Field Type</th><th>Default Value</th><th>Description</th></tr>
<tr><td>DBL_DIS</td><td>R/W</td><td>0b</td><td>Controls whether Crystal Input Frequency is doubled before being used in PLL0 or PLL1:
0 = 2x Actual Crystal Frequency Used
1 = Actual Crystal Frequency Used</td></tr>
<tr><td>CLKm_DIS</td><td>R/W</td><td>0b</td><td>Disable Control for Input Reference m:
0 = Input Reference m is Enabled
1 = Input Reference m is Disabled</td></tr>
<tr><td>PLL1_DIS</td><td>R/W</td><td>0b</td><td>Disable Control for Analog PLL1:
0 = PLL1 Enabled
1 = Analog PLL1 Disabled</td></tr>
<tr><td>Qm_DIS</td><td>R/W</td><td>0b</td><td>Disable Control for Output Qm, nQm:
0 = Output Qm, nQm functions normally
1 = All logic associated with Output Qm, nQm is Disabled & Driver in High-Impedance state</td></tr>
<tr><td>DPLLm_DIS</td><td>R/W</td><td>0b</td><td>Disable Control for Digital PLLm:
0 = Digital PLLm Enabled
1 = Digital PLLm Disabled</td></tr>
<tr><td>CALRSTm</td><td>R/W</td><td>0b</td><td>Reset Calibration Logic for Analog PLLm:
0 = Calibration Logic for Analog PLLm Enabled
1 = Calibration Logic for Analog PLLm Disabled</td></tr>
<tr><td>Rsvd</td><td>R/W</td><td>-</td><td>Reserved. Always write 0 to this bit location. Read values are not defined.</td></tr>
</table>

Table 7Q. Input Monitor Control Register Bit Field Locations and Descriptions

Input Monitor Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
00B9	Rsvd							LOS_0[16]
00BA	LOS_0[15:8]							
00BB	LOS_0[7:0]							
00BC	Rsvd							LOS_1[16]
00BD	LOS_1[15:8]							
00BE	LOS_1[7:0]							
00BF	Rsvd							LOS_2[16]
00C0	LOS_2[15:8]							
00C1	LOS_2[7:0]							
00C2	Rsvd							LOS_3[16]
00C3	LOS_3[15:8]							
00C4	LOS_3[7:0]							
00C5	Rsvd							
00C6	Rsvd							

Input Monitor Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
LOS_m[16:0]	R/W	1FFFFh	Number of Input Monitoring clock periods before Input Reference m is considered to be missed (soft alarm). Minimum setting is 3.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7R. Interrupt Enable Control Register Bit Field Locations and Descriptions

Interrupt Enable Control Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
00C7	LOL1_EN	LOL0_EN	HOLD1_EN	HOLD0_EN	LOS3_EN	LOS2_EN	LOS1_EN	LOS0_EN
00C8	Rsvd							

Interrupt Enable Control Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
LOLm_EN	R/W	0b	Interrupt Enable Control for Loss-of-Lock Interrupt Status Bit for PLLm: 0 = LOLm_INT register bit will not affect status of nINT output signal 1 = LOLm_INT register bit will affect status of nINT output signal
HOLDm_EN	R/W	0b	Interrupt Enable Control for Holdover Interrupt Status Bit for PLLm: 0 = HOLDm_INT register bit will not affect status of nINT output signal 1 = HOLDm_INT register bit will affect status of nINT output signal
LOSm_EN	R/W	0b	Interrupt Enable Control for Loss-of-Signal Interrupt Status Bit for Input Reference m: 0 = LOSm_INT register bit will not affect status of nINT output signal 1 = LOSm_INT register bit will affect status of nINT output signal
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7S. Interrupt Status Register Bit Field Locations and Descriptions

This register contains' sticky' bits for tracking the status of the various alarms. Whenever an alarm occurs, the appropriate Interrupt Status bit will be set. The Interrupt Status bit will remain asserted even after the original alarm goes away. The Interrupt Status bits remain asserted until explicitly cleared by a write of a '1' to the bit over the serial port. This type of functionality is referred to as Read / Write-1-to-Clear (R/W1C).

Interrupt Status Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0200	LOL1_INT	LOL0_INT	HOLD1_INT	HOLD0_INT	LOS3_INT	LOS2_INT	LOS1_INT	LOS0_INT
0201	Rsvd							
0202	Rsvd							
0203	Rsvd							

Interrupt Status Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
LOLm_INT	R/W1C	0b	Interrupt Status Bit for Loss-of-Lock on PLLm: 0 = No Loss-of-Lock alarm flag on PLLm has occurred since the last time this register bit was cleared. 1 = At least one Loss-of-Lock alarm flag on PLLm has occurred since the last time this register bit was cleared.
HOLDm_INT	R/W1C	0b	Interrupt Status Bit for Holdover on PLLm: 0 = No Holdover alarm flag on PLLm has occurred since the last time this register bit was cleared. 1 = At least one Holdover alarm flag on PLLm has occurred since the last time this register bit was cleared.
LOSm_INT	R/W1C	0b	Interrupt Status Bit for Loss-of-Signal on Input Reference m: 0 = No Loss-of-Signal alarm flag on Input Reference m has occurred since the last time this register bit was cleared. 1 = At least one Loss-of-Signal alarm flag on Input Reference m has occurred since the last time this register bit was cleared.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7T. Output Phase Adjustment Status Register Bit Field Locations and Descriptions

Output Phase Adjustment Status Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0204	PA_BUSY7	PA_BUSY6	PA_BUSY5	PA_BUSY4	PA_BUSY3	PA_BUSY2	PA_BUSY1	PA_BUSY0

Output Phase Adjustment Status Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
PA_BUSYm	R/O	-	Phase Adjustment Event Status for output Qm, nQm: 0 = No phase adjustment is currently in progress on output Qm, nQm 1 = Phase adjustment still in progress on output Qm, nQm. Do not initiate any new phase adjustment at this time.

Table 7U. Digital PLL0 Status Register Bit Field Locations and Descriptions

Digital PLL0 Status Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0205	Rsvd			EXTLOS0	Rsvd	CURR_REF0[2:0]		
0206	Rsvd			Rsvd	Rsvd	Rsvd	Rsvd	
0207	Rsvd							Rsvd

Digital PLL0 Status Register Block Field Locations

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0
0208	Rsvd							
0209	Rsvd							
020A	Rsvd							Rsvd
020B	Rsvd							
020C	Rsvd							
020D	Rsvd							
020E	Rsvd							

Digital PLL0 Status Register Block Field Descriptions

Bit Field Name	Field Type	Default Value	Description
CURR_REF0[2:0]	R/O	-	Currently Selected Reference Status for Digital PLL0: 000 - 011 = No reference currently selected 100 = Input Reference 0 (CLK0, nCLK0) selected 101 = Input Reference 1 (CLK1, nCLK1) selected 110 = Input Reference 2 (CLK2, nCLK2) selected 111 = Input Reference 3 (CLK3, nCLK3) selected
EXTLOS0	R/O	-	External Loopback signal lost for PLL0: 0 = PLL0 has a valid feedback reference signal 1 = PLL0 has lost the external feedback reference signal and is no longer locked
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7V. Digital PLL1 Status Register Bit Field Locations and Descriptions

Digital PLL1 Status Register Block Field Locations

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0
020F	Rsvd			EXTLOS1	Rsvd	CURR_REF1[2:0]		
0210	Rsvd			Rsvd	Rsvd	Rsvd	Rsvd	
0211	Rsvd							Rsvd
0212	Rsvd							
0213	Rsvd							
0214	Rsvd							Rsvd
0215	Rsvd							
0216	Rsvd							
0217	Rsvd							
0218	Rsvd							

Digital PLL1 Status Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
CURR_REF1[2:0]	R/O	-	Currently Selected Reference Status for Digital PLL1: 000 - 011 = No reference currently selected 100 = Input Reference 0 (CLK0, nCLK0) selected 101 = Input Reference 1 (CLK1, nCLK1) selected 110 = Input Reference 2 (CLK2, nCLK2) selected 111 = Input Reference 3 (CLK3, nCLK3) selected
EXTLOS1	R/O	-	External Loopback signal lost for PLL1 0 = PLL1 has a valid feedback reference signal 1 = PLL1 has lost the external feedback reference signal and is no longer locked
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Table 7W. General Purpose Input Status Register Bit Field Locations and Descriptions

Global Interrupt Status Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
0219	GPI[7]	GPI[6]	GPI[5]	GPI[4]	GPI[3]	GPI[2]	GPI[1]	GPI[0]

General Purpose Input Status Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
GPI[7:0]	R/O	-	Shows current values on GPIO[7:0] pins that are configured as General-Purpose Inputs.

Table 7X. Global Interrupt Status Register Bit Field Locations and Descriptions

Global Interrupt Status Register Block Field Locations								
Address (Hex)	**D7**	**D6**	**D5**	**D4**	**D3**	**D2**	**D1**	**D0**
021A	Rsvd				Rsvd			INT
021B	Rsvd							
021C	Rsvd		Rsvd					
021D	Rsvd		Rsvd					
021E	Rsvd					Rsvd	Rsvd	BOOTFAIL
021F	Rsvd	Rsvd	Rsvd	Rsvd	nEEP_CRC	Rsvd	Rsvd	EEPDONE

Global Interrupt Status Register Block Field Descriptions			
Bit Field Name	**Field Type**	**Default Value**	**Description**
INT	R/O	-	Device Interrupt Status: 0 = No Interrupt Status bits that are enabled are asserted (nINT pin released) 1 = At least one Interrupt Status bit that is enabled is asserted (nINT pin asserted low)
BOOTFAIL	R/O	-	Reading of Serial EEPROM failed. Once set this bit is only cleared by reset.
nEEP_CRC	R/O	-	EEPROM CRC Error (Active Low): 0 = EEPROM was detected and read, but CRC check failed - please reset the device via the nRST pin to retry (serial port is locked) 1 = No EEPROM CRC Error
EEPDONE	R/O	-	Serial EEPROM Read cycle has completed. Once set this bit is only cleared by reset.
Rsvd	R/W	-	Reserved. Always write 0 to this bit location. Read values are not defined.

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of the product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V_{CC}	3.63V
Inputs, V_I OSCI Other Input	 0V to 2V -0.5V to V_{CC} + 0.5V
Outputs, V_O (Q[0:7], nQ[0:7])	-0.5V to V_{CCOX} + 0.5V
Outputs, V_O (GPIO[0:7], SDATA, SCLK, nINT)	-0.5V to V_{CC} + 0.5V
Outputs, I_O (Q[0:7], nQ[0:7]) Continuous Current Surge Current	 40mA 65mA
Outputs, I_O (GPIO[0:7], SDATA, SCLK, nINT)) Continuous Current Surge Current	 8mA 13mA
Junction Temperature, T_J	125°C
Storage Temperature, T_{STG}	-65°C to 150°C

NOTE: V_{CCOX} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.

Supply Voltage Characteristics

Table 8A. Power Supply Characteristics, V_{CC} = 3.3V ±5%, V_{EE} = 0V, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{CC}	Core Supply Voltage		3.135	3.3	3.465	V
V_{CCA}	Analog Supply Voltage		V_{CC} – 0.13	3.3	V_{CC}	V
I_{CC}	Core Supply Current; NOTE 1			82	100	mA
I_{CCA}	Analog Supply Current; NOTE 1	PLL0 and PLL1 enabled		207	265	mA
		Analog PLL1, Digital PLL1, and Calibration Logic for Analog PLL1 Disabled		121	187	mA
I_{EE}	Power Supply Current; NOTE 2	Q0:Q7 Configured for LVPECL Logic Levels; Outputs Unloaded		575	735	mA

NOTE 1: I_{CC} and I_{CCA} are included in I_{EE} when Q[0:7] configured for LVPECL logic levels.
NOTE 2: Internal dynamic switching current at maximum f_{OUT} is included.

Table 8B. Power Supply Characteristics, V_{CC} = 2.5V ±5%, V_{EE} = 0V, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{CC}	Core Supply Voltage		2.375	2.5	2.625	V
V_{CCA}	Analog Supply Voltage		V_{CC} – 0.13	2.5	V_{CC}	V
I_{CC}	Core Supply Current; NOTE 1			79	95	mA
I_{CCA}	Analog Supply Current; NOTE 1	PLL0 and PLL1 enabled		201	260	mA
		Analog PLL1, Digital PLL1, and Calibration Logic for Analog PLL1 Disabled		116	182	mA
I_{EE}	Power Supply Current; NOTE 2	Q0:Q7 Configured for LVPECL Logic Levels; Outputs Unloaded		544	695	mA

NOTE 1: I_{CC} and I_{CCA} are included in I_{EE} when Q[0:7] configured for LVPECL logic levels.
NOTE 2: Internal dynamic switching current at maximum f_{OUT} is included.

Table 8C. Maximum Output Supply Current, V_{CC} = 3.3V ±5% or 2.5V ±5%, V_{EE} = 0V, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	V_{CCx} = 3.3V ±5%			V_{CCx} = 2.5V ±5%			V_{CCx} = 1.8V ±5%	Units
			LVPECL	LVDS	LVCMOS	LVPECL	LVDS	LVCMOS	LVCMOS	
I_{CCO0}	Q0, nQ0 Output Supply Current	Outputs Unloaded	50	60	55	40	50	45	35	mA
I_{CCO1}	Q1, nQ1 Output Supply Current	Outputs Unloaded	50	60	55	40	50	45	35	mA
I_{CCO2}	Q2, nQ2 Output Supply Current	Outputs Unloaded	80	90	80	70	80	70	60	mA
I_{CCO3}	Q3, nQ3 Output Supply Current	Outputs Unloaded	80	90	80	70	80	70	60	mA
I_{CCO4}	Q4, nQ4 Output Supply Current	Outputs Unloaded	55	65	55	45	55	45	40	mA
I_{CCO5}	Q5, nQ5 Output Supply Current	Outputs Unloaded	55	65	55	45	55	45	40	mA
I_{CCO6}	Q6, nQ6 Output Supply Current	Outputs Unloaded	55	65	55	45	55	45	40	mA
I_{CCO7}	Q7, nQ7 Output Supply Current	Outputs Unloaded	55	65	55	45	55	45	40	mA

NOTE: V_{CCOx} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.
NOTE: Internal dynamic switching current at maximum f_{OUT} is included.

DC Electrical Characteristics

Table 9A. LVCMOS/LVTTL DC Characteristics, V_{EE} = 0V, T_A = -40°C to 85°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage		V_{CC} = 3.3V	2		V_{CC} +0.3	V
			V_{CC} = 2.5V	1.7		V_{CC} +0.3	V
V_{IL}	Input Low Voltage		V_{CC} = 3.3V	-0.3		0.8	V
			V_{CC} = 2.5V	-0.3		0.7	V
I_{IH}	Input High Current	nI2C_SPI, PLL_BYP, S_A0/nCS, S_A1/SDI	V_{CC} = V_{IN} = 3.465V or 2.625V			150	µA
		nRST, SDATA/SDO, nWP, SCLK/SCLK	V_{CC} = V_{IN} = 3.465V or 2.625V			5	µA
		GPIO[7:0]	V_{CC} = V_{IN} = 3.465V or 2.625V			1	mA
I_{IL}	Input Low Current	nI2C_SPI, PLL_BYP, S_A0/nCS, S_A1/SDI	V_{CC} = 3.465V or 2.625V, V_{IN} = 0V	-5			µA
		nRST, SDATA/SDO, nWP, SCLK/SCLK	V_{CC} = 3.465V or 2.625V, V_{IN} = 0V	-150			µA
		GPIO[7:0]	V_{CC} = 3.465V or 2.625V, V_{IN} = 0V	-1			mA
V_{OH}	Output High Voltage	nINT, SDATA/SDO, SCLK/SCLK; NOTE 1	V_{CC} = 3.3V ±5%, I_{OH} = -5µA	2.6			V
		GPIO[7:0]	V_{CC} = 3.3V ±5%, I_{OH} = -50µA	2.6			V
		nINT, SDATA/SDO, SCLK/SCLK; NOTE 1	V_{CC} = 2.5V ±5%, I_{OH} = -5µA	1.8			V
		GPIO[7:0]	V_{CC} = 2.5V ±5%, I_{OH} = -50µA	1.8			V
V_{OL}	Output Low Voltage	nINT, SDATA/SDO, SCLK/SCLK; NOTE 1	V_{CC} = 3.3V ±5% or 2.5V ±5%, I_{OL} = 5mA			0.5	V
		GPIO[7:0]	V_{CC} = 3.3V ±5% or 2.5V ±5%, I_{OL} = 5mA			0.5	V

NOTE 1: Use of external pull-up resistors is recommended.

Table 9B. Differential Input DC Characteristics, V_{CC} = 3.3V ±5% or 2.5V ±5%, V_{EE} = 0V, T_A = -40°C to 85°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
I_{IH}	Input High Current	CLKx, nCLKx	V_{CC} = V_{IN} = 3.465V or 2.625V			150	µA
I_{IL}	Input Low Current	CLKx	V_{CC} = 3.465V or 2.625V, V_{IN} = 0V	-5			µA
		nCLKx	V_{CC} = 3.465V or 2.625V, V_{IN} = 0V	-150			µA
V_{PP}	Peak-to-Peak Voltage; NOTE 1			0.15		1.3	V
V_{CMR}	Common Mode Input Voltage; NOTE 1, 2			V_{EE}		V_{CC} -1.2	V

NOTE: CLKx denotes CLK0, CLK1, CLK2, CLK3. nCLKx denotes nCLK0, nCLK1, nCLK2, nCLK3.
NOTE 1: V_{IL} should not be less than -0.3V. V_{IH} should not be higher than V_{CC}.
NOTE 2: Common mode voltage is defined as the cross-point.

Table 9C. LVPECL DC Characteristics, V_{CC} = 3.3V ±5% or 2.5V ±5%, V_{EE} = 0V, T_A = -40°C to 85°C

Symbol	Parameter		Test Conditions	V_{CCOx} = 3.3V±5%			V_{CCOx} = 2.5V±5%			Units
				Minimum	Typical	Maximum	Minimum	Typical	Maximum	
V_{OH}	Output High Voltage; NOTE 1	Qx, nQx		V_{CCOx} - 1.3		V_{CCOx} - 0.8	V_{CCOx} - 1.35		V_{CCOx} - 0.9	V
V_{OL}	Output Low Voltage; NOTE 1	Qx, nQx		V_{CCOx} - 1.95		V_{CCOx} - 1.75	V_{CCOx} - 1.95		V_{CCOx} - 1.75	V

NOTE: V_{CCOx} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.
NOTE: Qx denotes Q0, Q1, Q2, Q3, Q4, Q5, Q6, Q7. nQx denotes nQ0, nQ1, nQ2, nQ3, nQ4, nQ5, nQ6, nQ7.
NOTE 1: Outputs terminated with 50Ω to V_{CCOx} – 2V.

Table 9D. LVDS DC Characteristics, V_{CC} = 3.3V ±5% or 2.5V ±5%, V_{CCOx} = 3.3V ±5% or 2.5V ±5%, V_{EE} = 0V, T_A = -40°C to 85°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V_{OD}	Differential Output Voltage	Qx, nQx		195		454	mV
ΔV_{OD}	V_{OD} Magnitude Change	Qx, nQx				50	mV
V_{OS}	Offset Voltage	Qx, nQx		1.1		1.375	V
ΔV_{OS}	V_{OS} Magnitude Change	Qx, nQx				50	mV

NOTE: V_{CCOx} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.
NOTE: Qx denotes Q0, Q1, Q2, Q3, Q4, Q5, Q6, Q7. nQx denotes nQ0, nQ1, nQ2, nQ3, nQ4, nQ5, nQ6, nQ7.
NOTE: Terminated 100Ω across Qx and nQx.

Table 9E. LVCMOS DC Characteristics, V_{CC} = 3.3V ±5% or 2.5V ±5%, V_{EE} = 0V, T_A = -40°C to 85°C

Symbol	Parameter		Test Conditions	V_{CCOx} = 3.3V±5%			V_{CCOx} = 2.5V±5%			V_{CCOx} = 1.8V ±5%			Units
				Minimum	Typical	Maximum	Minimum	Typical	Maximum	Minimum	Typical	Maximum	
V_{OH}	Output High Voltage	Qx, nQx	I_{OH} = -8mA	2.6			1.8			1.1			V
V_{OL}	Output Low Voltage	Qx, nQx	I_{OL} = 8mA			0.5			0.5			0.5	V

NOTE: V_{CCOx} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.
NOTE: Qx denotes Q0, Q1, Q2, Q3, Q4, Q5, Q6, Q7. nQx denotes nQ0, nQ1, nQ2, nQ3, nQ4, nQ5, nQ6, nQ7.

Table 10. Input Frequency Characteristics, V_{CC} = 3.3V±5% or 2.5V±5%, T_A = -40°C to 85°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f_{IN}	Input Frequency; NOTE 1	OSCI, OSCO		10		40	MHz
		CLKx, nCLKx		0.008		875	MHz
f_{SCLK}	Serial Port Clock SCLK (slave mode)	I^2C Operation		100		400	kHz
		SPI Operation				4.25	MHz

NOTE: CLKx denotes CLK0, CLK1, CLK2, CLK3. nCLKx denotes nCLK0, nCLK1, nCLK2, nCLK3.
NOTE 1: For the input reference frequency, the divider values must be set for the VCO to operate within its supported range.

Table 11. Crystal Characteristics

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation		Fundamental			
Frequency		10		40	MHz
Equivalent Series Resistance (ESR)			15		Ω
Load Capacitance (C_L)			12		pF
Frequency Stability (total)		-100		100	ppm

AC Electrical Characteristics

Table 12. AC Characteristics, V_{CC} = 3.3V ±5% or 2.5V ±5%, V_{CCOx} = 3.3V ±5%, 2.5V ±5% or 1.8V ±5% (1.8V only supported for LVCMOS outputs), T_A = -40°C to 85°C

Symbol	Parameter			Test Conditions	Minimum	Typical	Maximum	Units
f_{VCO}	VCO Operating Frequency				3000		4000	MHz
f_{OUT}	Output Frequency	LVPECL / LVDS		Q0, Q1, Q4, Q5, Q6, Q7 outputs	0.008		1000	MHz
				Q2, Q3 outputs Integer Divide Ratio & No Added Phase Delay			666.67	MHz
				Q2, Q3 outputs Non-integer divide and/or added phase delay			400	MHz
		LVCMOS					250	MHz
t_R / t_F	Output Rise and Fall Times	LVPECL		20% to 80%	145	340	600	ps
		LVDS		20% to 80%	100	250	500	ps
		LVCMOS		20% to 80%, V_{CCOx} = 3.3V	180	350	600	ps
				20% to 80%, V_{CCOx} = 2.5V	200	350	550	ps
				20% to 80%, V_{CCOx} = 1.8V	200	410	650	ps
SR	Output Slew Rate	LVPECL		measured on differential waveform, ±150mV from center	1		5	V/ns
		LVDS		measured on differential waveform, ±150mV from center	0.5		4	V/ns
*t*sk(b)	Bank Skew	LVPECL	Q0, nQ0, Q1, nQ1	NOTE 1, 2, 3, 5			75	ps
			Q4, nQ4, Q5, nQ5	NOTE 1, 2, 3, 5			75	ps
			Q6, nQ6, Q7, nQ7	NOTE 1, 2, 3, 5			75	ps
		LVDS	Q0, nQ0, Q1, nQ1	NOTE 1, 2, 3, 5			75	ps
			Q4, nQ4, Q5, nQ5	NOTE 1, 2, 3, 5			75	ps
			Q6/,nQ6, Q7,nQ7	NOTE 1, 2, 3, 5			75	ps
		LVCMOS	Q0, nQ0, Q1, nQ1	NOTE 1, 2, 4, 5, 6			80	ps
			Q4, nQ4, Q5, nQ5	NOTE 1, 2, 4, 5, 6			115	ps
			Q6, nQ6, Q7, nQ7	NOTE 1, 2, 4, 5, 6			115	ps

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
odc	Output Duty Cycle; NOTE 7	LVPECL	$f_{OUT} \le$ 666.667MHz	45	50	55	%
			$f_{OUT} >$ 666.667MHz	40	50	60	%
		LVDS	$f_{OUT} \le$ 666.667MHz	45	50	55	%
			$f_{OUT} >$ 666.667MHz	40	50	60	%
		LVCMOS		40	50	60	%
	Initial Frequency Offset		Switchover or entering / leaving Holdover state; NOTE 8, 13	-50		50	ppb
	Output Phase Change in Fully Hitless Switching		Switchover or entering / leaving Holdover state; NOTE 10, 13		5		ns
Φ_{SSB}(1k)	Single Sideband Phase Noise; NOTE 9	1kHz	122.88MHz output		-115		dBc/Hz
Φ_{SSB}(10k)		10kHz	122.88MHz output		-129		dBc/Hz
Φ_{SSB}(100k)		100kHz	122.88MHz output		-134		dBc/Hz
Φ_{SSB}(1M)		1MHz	122.88MHz output		-147		dBc/Hz
Φ_{SSB}(10M)		10MHz	122.88MHz output		-153		dBc/Hz
Φ_{SSB}(30M)		≥30MHz	122.88MHz output		-154		dBc/Hz
	Spurious Limit at offset	≥800kHz	122.88MHz output; NOTE 11		-85		dBc
tstartup	Startup time	Internal OTP Startup; NOTE 13	from V_{CC} >80% to first output clock edge		110	150	ms
		External EEPROM Startup; NOTE 12, 13	from V_{CC} >80% to first output clock edge (0 retries). I^2C frequency = 100kHz		150	200	ms
			from V_{CC} >80% to first output clock edge (0 retries). I^2C frequency = 400kHz		130	150	ms
			from V_{CC} >80% to first output clock edge (31 retries). I^2C frequency = 100kHz		925	1200	ms
			from V_{CC} >80% to first output clock edge (31 retries). I^2C frequency = 400kHz		360	500	ms

NOTE: V_{CCOx} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.
NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.
NOTE 1: This parameter is guaranteed by characterization. Not tested in production.
NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.
NOTE 3: Measured at the output differential crosspoints.
NOTE 4: Measured at $V_{CCOx}/2$ of the rising edge. All Qx and nQx outputs phase-aligned.
NOTE 5: Defined as skew within a bank of outputs at the same supply voltage and with equal load conditions running off the same PLL.
NOTE 6: Appropriate SE_MODE bit must be set to enable phase-aligned operation.
NOTE 7: Characterized in synthesizer mode. Duty cycle of bypassed signals (input reference clocks or crystal input) is not adjusted by the device.
NOTE 8: Tested in fast-lock operation after >20 minutes of locked operation to ensure holdover averaging logic is stable.
NOTE 9: Characterized with IDT8T49N282B-901NLGI units (synthesizer mode).
NOTE 10: Device programmed with SWMODEn = 0 (absorbs phase differences).
NOTE 11: Tested with all outputs operating at 122.88MHz.
NOTE 12: Assuming a clear I^2C bus.
NOTE 13: This parameter is guaranteed by design.

Table 13A. Typical RMS Phase Jitter (Synthesizer Mode), V_{CC} = 3.3V ±5% or 2.5V ±5%, V_{CCOx} = 3.3V ±5%, 2.5V ±5% or 1.8V ±5% (1.8V only supported for LVCMOS outputs), T_A = -40°C to 85°C

Symbol	Parameter		Test Conditions	LVPECL	LVDS	LVCMOS$^{NOTE\ 6}$	Units
tjit(ϕ)	RMS Phase Jitter (Random)	Q0, Q1	f_{OUT} = 122.88MHz, Integration Range: 12kHz - 20MHz; NOTE 1	281	286	273	fs
			f_{OUT} = 156.25MHz, Integration Range: 12kHz - 20MHz; NOTE 2	261	250	259	fs
			f_{OUT} = 622.08MHz, Integration Range: 12kHz - 20MHz; NOTE 3	220	209	N/A (NOTE 5)	fs
		Q2, Q3 Integer; NOTE 1	f_{OUT} = 122.88MHz, Integration Range: 12kHz - 20MHz	297	319	306	fs
		Q2, Q3 Fractional; NOTE 4	f_{OUT} = 122.88MHz, Integration Range: 12kHz - 20MHz	288	263	254	fs
		Q4, Q5, Q6, Q7; NOTE 1	f_{OUT} = 122.88MHz, Integration Range: 12kHz - 20MHz	293	332	296	fs

NOTE: V_{CCOx} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.
NOTE: Fox part numbers: 277LF-40-18 and 277LF-38.88-2 used for 40MHz and 38.88MHz crystals, respectively.
NOTE: All outputs configured for the specific output type, as shown in the table.
NOTE 1: Characterized with IDT8T49N282B-901NLGI.
NOTE 2: Characterized with IDT8T49N282B-902NLGI.
NOTE 3: Characterized with IDT8T49N282B-903NLGI.
NOTE 4: Characterized with IDT8T49N282B-900NLGI.
NOTE 5: This frequency is not supported for LVCMOS operation.
NOTE 6: Qx and nQx are 180° out of phase.

Table 13B. Typical RMS Phase Jitter (Jitter Attenuator Mode), V_{CC} = 3.3V ±5% or 2.5V ±5%, V_{CCOx} = 3.3V ±5%, 2.5V ±5% or 1.8V ±5% (1.8V only supported for LVCMOS outputs), T_A = -40°C to 85°C

Symbol	Parameter		Test Conditions	LVPECL	LVDS	LVCMOS$^{NOTE\ 6}$	Units
tjit(ϕ)	RMS Phase Jitter (Random)	Q0, Q1	f_{OUT} = 122.88MHz, Integration Range: 12kHz - 20MHz; NOTE 1	283	287	282	fs
			f_{OUT} = 156.25MHz, Integration Range: 12kHz - 20MHz; NOTE 2	260	261	272	fs
			f_{OUT} = 622.08MHz, Integration Range: 12kHz - 20MHz; NOTE 3	256	255	N/A (NOTE 5)	fs
		Q2, Q3 Integer; NOTE 1	f_{OUT} = 122.88MHz, Integration Range: 12kHz - 20MHz	311	315	317	fs
		Q2, Q3 Fractional; NOTE 4	f_{OUT} = 122.88MHz, Integration Range: 12kHz - 20MHz	259	266	262	fs
		Q4, Q5, Q6, Q7; NOTE 1	f_{OUT} = 122.88MHz, Integration Range: 12kHz - 20MHz	298	308	302	fs

NOTE: V_{CCOx} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.
NOTE: Measured using a Rohde & Schwarz SMA100A as the input source.
NOTE: Fox part numbers: 277LF-40-18 and 277LF-38.88-2 used for 40MHz and 38.88MHz crystals, respectively.
NOTE: All outputs configured for the specific output type, as shown in the table.
NOTE 1: Characterized with IDT8T49N282B-905NLGI.
NOTE 2: Characterized with IDT8T49N282B-906NLGI.
NOTE 3: Characterized with IDT8T49N282B-907NLGI.
NOTE 4: Characterized with IDT8T49N282B-904NLGI.
NOTE 5: This frequency is not supported for LVCMOS operation.
NOTE 6: Qx and nQx are 180° out of phase.

Table 14A. PCI Express Jitter Specifications, $V_{CC} = V_{CCOx}$ = 3.3V ±5%, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	PCIe Industry Specification	Units
tj (PCIe Gen 1)	Phase Jitter Peak-to-Peak; NOTE 1, 4, 5	f = 100MHz, 40MHz Crystal Input, Evaluation Band: 0Hz - Nyquist (clock frequency/2)		8	30	86	ps
$t_{REFCLK\_HF\_RMS}$ (PCIe Gen 2)	Phase Jitter RMS; NOTE 2, 4, 5	f = 100MHz, 40MHz Crystal Input, High Band: 1.5MHz - Nyquist (clock frequency/2)		0.5	2	3.10	ps
$t_{REFCLK\_LF\_RMS}$ (PCIe Gen 2)	Phase Jitter RMS; NOTE 2, 4, 5	f = 100MHz, 40MHz Crystal Input, Low Band: 10kHz - 1.5MHz		0.04	0.2	3.0	ps
t_{REFCLK_RMS} (PCIe Gen 3)	Phase Jitter RMS; NOTE 3, 4, 5	f = 100MHz, 40MHz Crystal Input, Evaluation Band: 0Hz - Nyquist (clock frequency/2)		0.1	0.4	0.8	ps

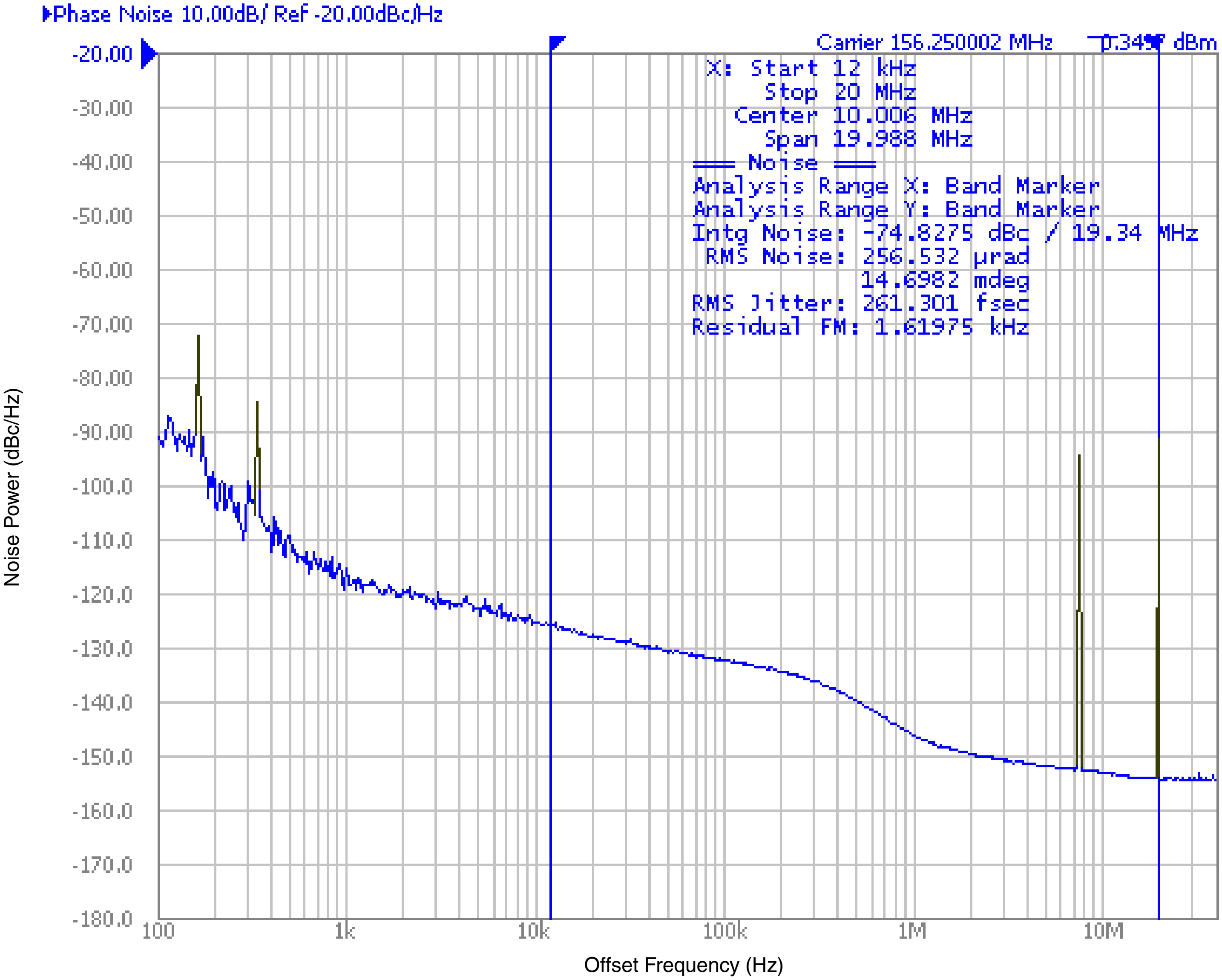
NOTE: V_{CCOx} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.
NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.
NOTE 1: Peak-to-Peak jitter after applying system transfer function for the Common Clock Architecture. Maximum limit for PCI Express Gen 1
NOTE 2: RMS jitter after applying the two evaluation bands to the two transfer functions defined in the Common Clock Architecture and reporting the worst case results for each evaluation band. Maximum limit for PCI Express Generation 2 is 3.1ps RMS for tREFCLK_HF_RMS (High Band) and 3.0ps RMS for tREFCLK_LF_RMS (Low Band).
NOTE 3: RMS jitter after applying system transfer function for the common clock architecture. This specification is based on the PCI Express Base Specification Revision 0.7, October 2009 and is subject to change pending the final release version of the specification.
NOTE 4: This parameter is guaranteed by characterization. Not tested in production.
NOTE 5: Outputs configured for LVPECL mode. Fox 277LF-40-18 crystal used with doubler logic enabled.

Table 14B. PCI Express Jitter Specifications, $V_{CC} = V_{CCOx}$ = 2.5V ±5%, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	PCIe Industry Specification	Units
tj (PCIe Gen 1)	Phase Jitter Peak-to-Peak; NOTE 1, 4, 5	f = 100MHz, 40MHz Crystal Input, Evaluation Band: 0Hz - Nyquist (clock frequency/2)		12	65	86	ps
$t_{REFCLK\_HF\_RMS}$ (PCIe Gen 2)	Phase Jitter RMS; NOTE 2, 4, 5	f = 100MHz, 40MHz Crystal Input, High Band: 1.5MHz - Nyquist (clock frequency/2)		0.8	3.10	3.10	ps
$t_{REFCLK\_LF\_RMS}$ (PCIe Gen 2)	Phase Jitter RMS; NOTE 2, 4, 5	f = 100MHz, 40MHz Crystal Input, Low Band: 10kHz - 1.5MHz		0.05	0.4	3.0	ps
t_{REFCLK_RMS} (PCIe Gen 3)	Phase Jitter RMS; NOTE 3, 4, 5	f = 100MHz, 40MHz Crystal Input, Evaluation Band: 0Hz - Nyquist (clock frequency/2)		0.2	0.8	0.8	ps

NOTE: V_{CCOx} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.
NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.
NOTE 1: Peak-to-Peak jitter after applying system transfer function for the Common Clock Architecture. Maximum limit for PCI Express Gen 1
NOTE 2: RMS jitter after applying the two evaluation bands to the two transfer functions defined in the Common Clock Architecture and reporting the worst case results for each evaluation band. Maximum limit for PCI Express Generation 2 is 3.1ps RMS for tREFCLK_HF_RMS (High Band) and 3.0ps RMS for tREFCLK_LF_RMS (Low Band).
NOTE 3: RMS jitter after applying system transfer function for the common clock architecture. This specification is based on the PCI Express Base Specification Revision 0.7, October 2009 and is subject to change pending the final release version of the specification.
NOTE 4: This parameter is guaranteed by characterization. Not tested in production.
NOTE 5: Outputs configured for LVPECL mode. Fox 277LF-40-18 crystal used with doubler logic enabled.

Typical Phase Noise at 156.25MHz



```
 X: Start 12 kHz
    Stop 20 MHz
  Center 10.006 MHz
    Span 19.988 MHz
=== Noise ===
Analysis Range X: Band Marker
Analysis Range Y: Band Marker
Intg Noise: -74.8275 dBc / 19.34 MHz
 RMS Noise: 256.532 µrad
            14.6982 mdeg
RMS Jitter: 261.301 fsec
Residual FM: 1.61975 kHz
```

Applications Information

Overdriving the XTAL Interface

The OSCI input can be overdriven by an LVCMOS driver or by one side of a differential driver through an AC coupling capacitor. The OSCO pin can be left floating. The amplitude of the input signal should be between 500mV and 1.8V and the slew rate should not be less than 0.2V/ns. For 3.3V LVCMOS inputs, the amplitude must be reduced from full swing to at least half the swing in order to prevent signal interference with the power rail and to reduce internal noise. *Figure 8A* shows an example of the interface diagram for a high speed 3.3V LVCMOS driver. This configuration requires that the sum of the output impedance of the driver (Ro) and the series resistance (Rs) equals the transmission line impedance. In addition, matched termination at the crystal input will attenuate the signal in half. This can be done in one of two ways. First, R1 and R2 in parallel should equal the transmission line impedance. For most 50Ω applications, R1 and R2 can be 100Ω. This can also be accomplished by removing R1 and changing R2 to 50Ω. The values of the resistors can be increased to reduce the loading for a slower and weaker LVCMOS driver. *Figure 8B* shows an example of the interface diagram for an LVPECL driver. This is a standard LVPECL termination with one side of the driver feeding the OSCI input. It is recommended that all components in the schematics be placed in the layout. Though some components might not be used, they can be utilized for debugging purposes. The datasheet specifications are characterized and guaranteed by using a quartz crystal as the input.

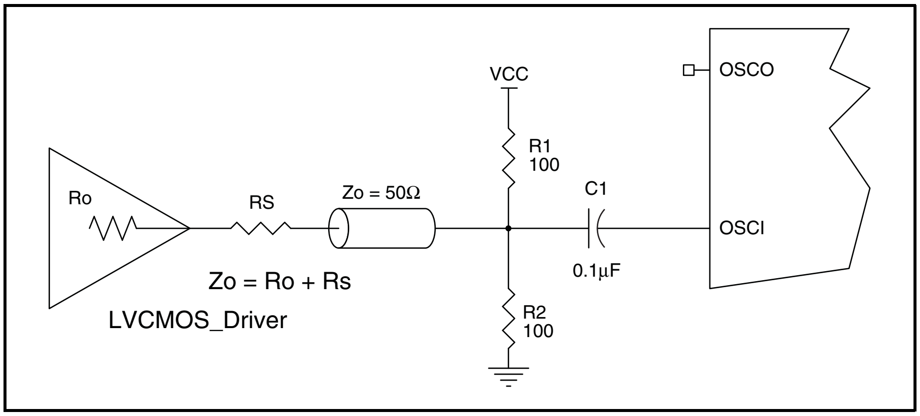


Figure 8A. General Diagram for LVCMOS Driver to XTAL Input Interface

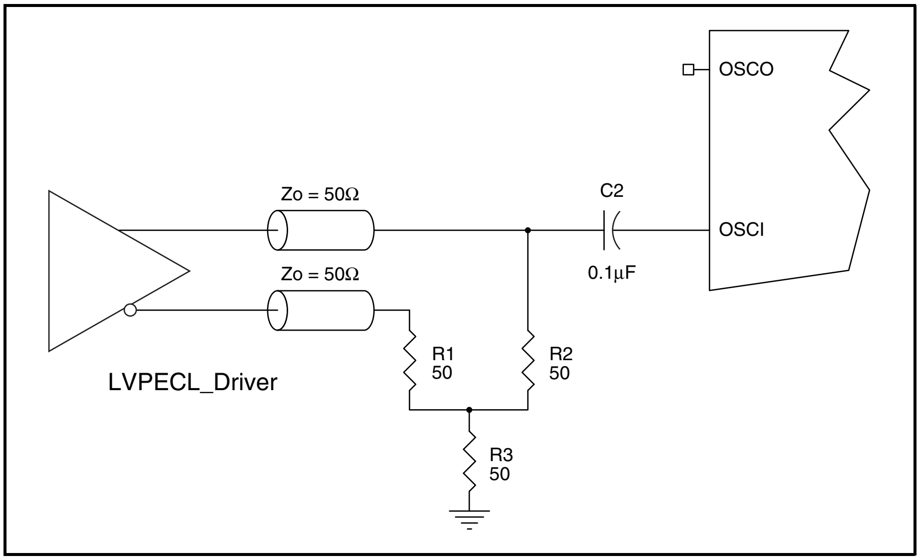


Figure 8B. General Diagram for LVPECL Driver to XTAL Input Interface

Wiring the Differential Input to Accept Single-Ended Levels

Figure 9 shows how a differential input can be wired to accept single ended levels. The reference voltage $V_1 = V_{CC}/2$ is generated by the bias resistors R1 and R2. The bypass capacitor (C1) is used to help filter noise on the DC bias. This bias circuit should be located as close to the input pin as possible. The ratio of R1 and R2 might need to be adjusted to position the V_1 in the center of the input voltage swing. For example, if the input clock swing is 2.5V and V_{CC} = 3.3V, R1 and R2 value should be adjusted to set V_1 at 1.25V. Similarly, if the input clock swing is 1.8V and V_{CC} = 3.3V, R1 and R2 value should be adjusted to set V_1 at 0.9V. It is recommended to always use R1 and R2 to provide a known V_1 voltage. The values below are for when both the single ended swing and V_{CC} are at the same voltage. This configuration requires that the sum of the output impedance of the driver (Ro) and the series resistance (Rs) equals the transmission line impedance. In addition, matched termination at the input will attenuate the signal in half. This can be done in one of two ways. First, R3 and R4 in parallel should equal the transmission line impedance. For most 50Ω applications, R3 and R4 can be 100Ω. The values of the resistors can be increased to reduce the loading for slower and weaker LVCMOS driver. When using single-ended signaling, the noise rejection benefits of differential signaling are reduced. Even though the differential input can handle full rail LVCMOS signaling, it is recommended that the amplitude be reduced. The datasheet specifies a lower differential amplitude, however this only applies to differential signals. For single-ended applications, the swing can be larger, however V_{IL} cannot be less than -0.3V and V_{IH} cannot be more than V_{CC} + 0.3V. Though some of the recommended components might not be used, the pads should be placed in the layout. They can be utilized for debugging purposes. The datasheet specifications are characterized and guaranteed by using a differential signal.

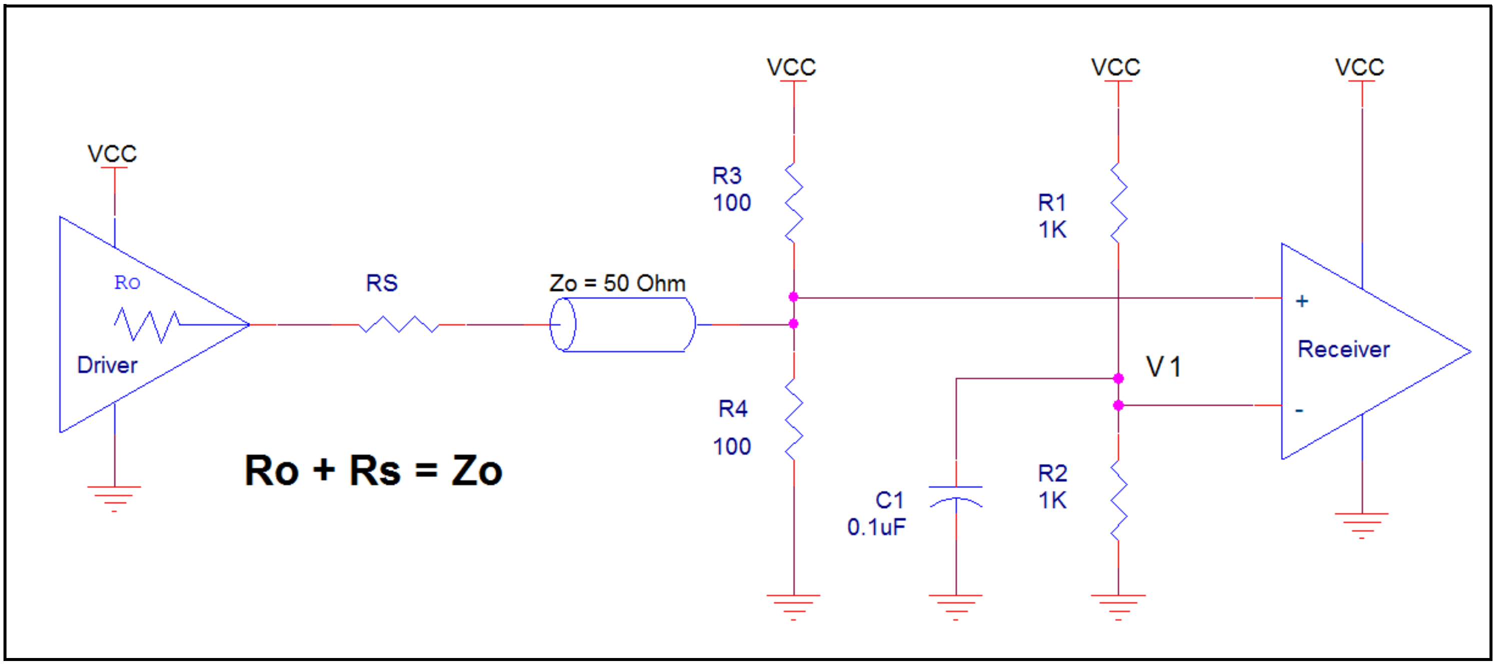


Figure 9. Recommended Schematic for Wiring a Differential Input to Accept Single-ended Levels

3.3V Differential Clock Input Interface

CLKx/nCLKx accepts LVDS, LVPECL, LVHSTL, HCSL and other differential signals. Both V_{SWING} and V_{OH} must meet the V_{PP} and V_{CMR} input requirements. *Figure 10A* to *Figure 10E* show interface examples for the CLKx/nCLKx input driven by the most common driver types. The input interfaces suggested here are examples only. Please consult with the vendor of the driver component to confirm the driver termination requirements. For example, in *Figure 10A*, the input termination applies for IDT open emitter LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

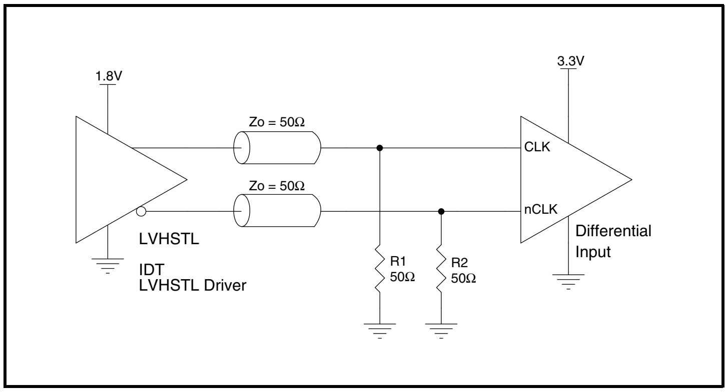


Figure 10A. CLKx/nCLKx Input Driven by an IDT Open Emitter LVHSTL Driver

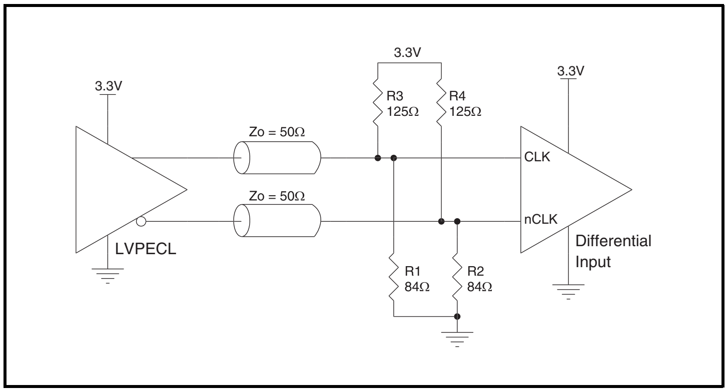


Figure 10B. CLKx/nCLKx Input Driven by a 3.3V LVPECL Driver

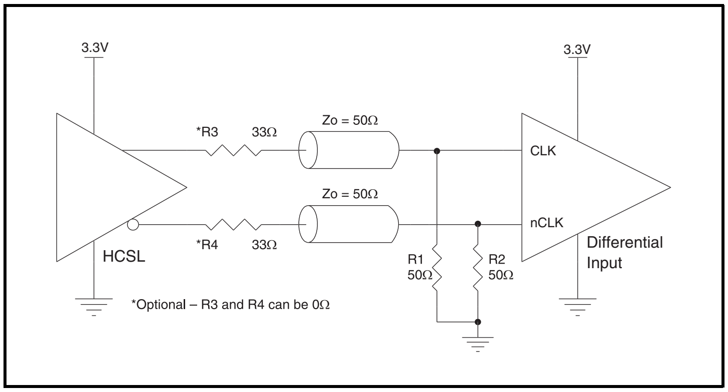


Figure 10C. CLKx/nCLKx Input Driven by a 3.3V HCSL Driver

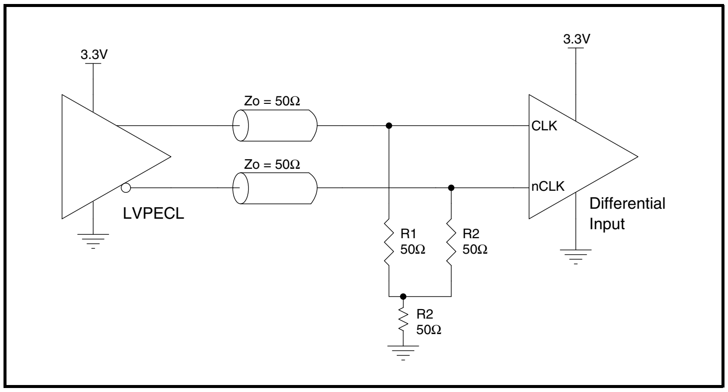


Figure 10D. CLKx/nCLKx Input Driven by a 3.3V LVPECL Driver

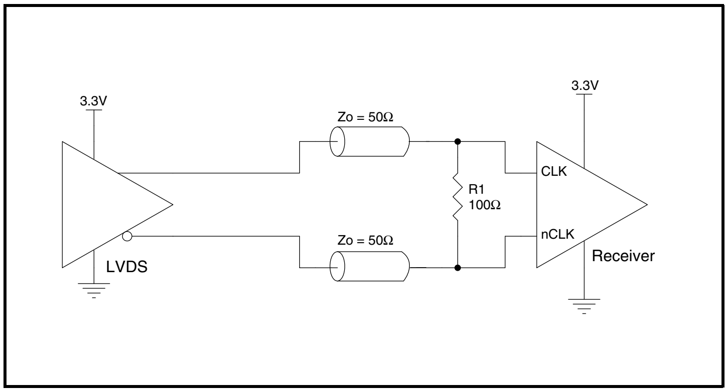


Figure 10E. CLKx/nCLKx Input Driven by a 3.3V LVDS Driver

2.5V Differential Clock Input Interface

CLKx/nCLKx accepts LVDS, LVPECL, LVHSTL and other differential signals. Both V_{SWING} and V_{OH} must meet the V_{PP} and V_{CMR} input requirements. *Figure 11A* to *Figure 11D* show interface examples for the CLKx/nCLKx input driven by the most common driver types. The input interfaces suggested here are examples only. Please consult with the vendor of the driver component to confirm the driver termination requirements. For example, in *Figure 11A*, the input termination applies for IDT open emitter LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

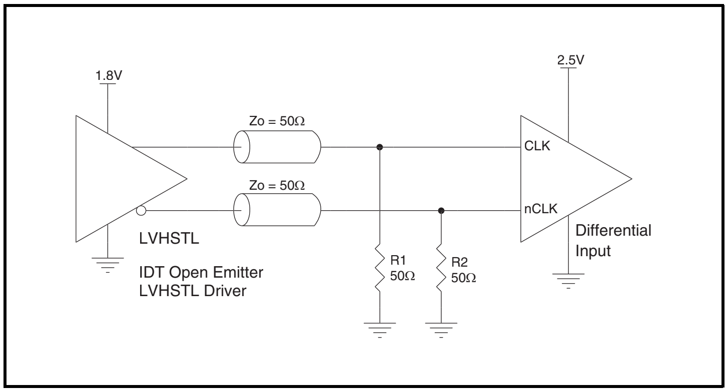


Figure 11A. CLKx/nCLKx Input Driven by an IDT Open Emitter LVHSTL Driver

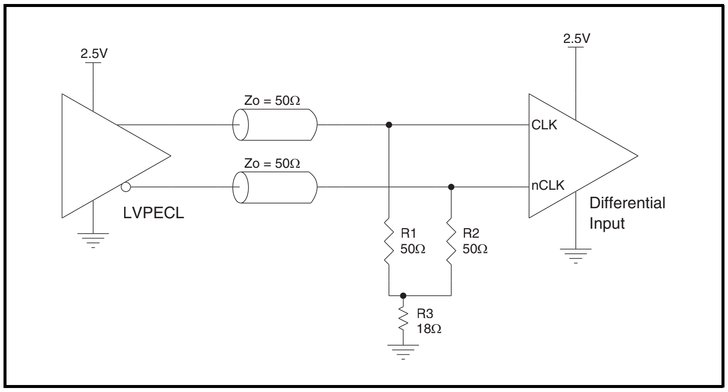


Figure 11C. CLKx/nCLKx Input Driven by a 2.5V LVPECL Driver

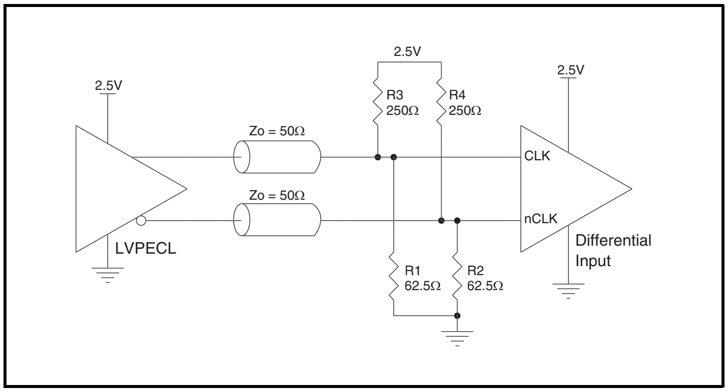


Figure 11B. CLKx/nCLKx Input Driven by a 2.5V LVPECL Driver

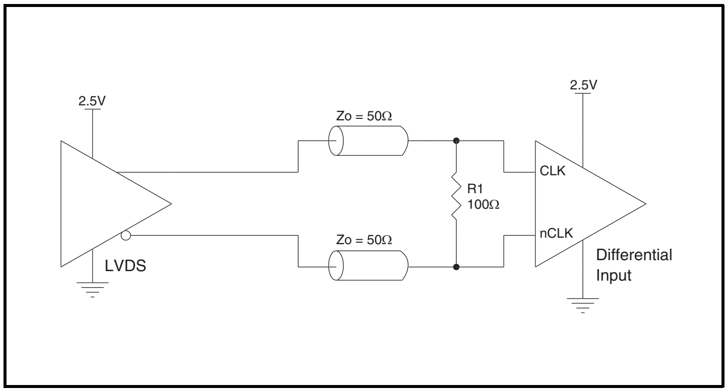


Figure 11D. CLKx/nCLKx Input Driven by a 2.5V LVDS Driver

Recommendations for Unused Input and Output Pins

Inputs:

CLKx/nCLKx Input

For applications not requiring the use of one or more reference clock inputs, both CLKx and nCLKx can be left floating. Though not required, but for additional protection, a 1kΩ resistor can be tied from CLKx to ground. It is recommended that CLKx, nCLKx not be driven with active signals when not enabled for use by either PLL.

LVCMOS Control Pins

All control pins have internal pullup or pulldown resistors; additional resistance is not required but can be added for additional protection. A 1kΩ resistor can be used.

Outputs:

LVPECL Outputs

Any unused LVPECL output pair can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.

LVDS Outputs

Any unused LVDS output pair can be either left floating or terminated with 100Ω across. If they are left floating there should be no trace attached.

LVCMOS Outputs

Any LVCMOS output can be left floating if unused. There should be no trace attached.

LVDS Driver Termination

For a general LVDS interface, the recommended value for the termination impedance (Z_T) is between 90Ω and 132Ω. The actual value should be selected to match the differential impedance (Z_0) of your transmission line. A typical point-to-point LVDS design uses a 100Ω parallel resistor at the receiver and a 100Ω differential transmission-line environment. In order to avoid any transmission-line reflection issues, the components should be surface mounted and must be placed as close to the receiver as possible. IDT offers a full line of LVDS compliant devices with two types of output structures: current source and voltage source. The standard termination schematic as shown in *Figure 12A* can be used with either type of output structure. *Figure 12B*, which can also be used with both output types, is an optional termination with center tap capacitance to help filter common mode noise. The capacitor value should be approximately 50pF. If using a non-standard termination, it is recommended to contact IDT and confirm if the output structure is current source or voltage source type. In addition, since these outputs are LVDS compatible, the input receiver's amplitude and common-mode input range should be verified for compatibility with the output.

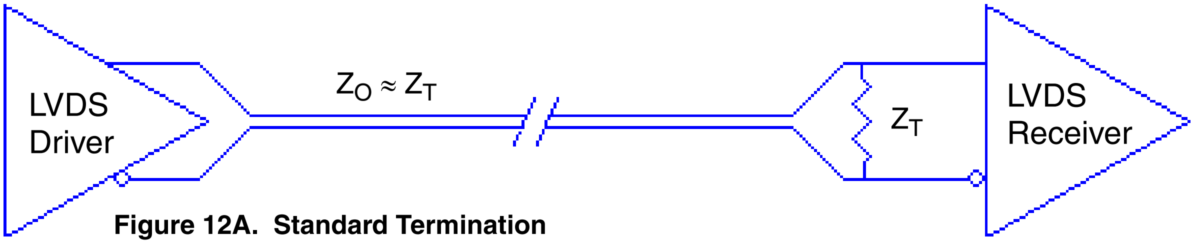


Figure 12A. Standard Termination

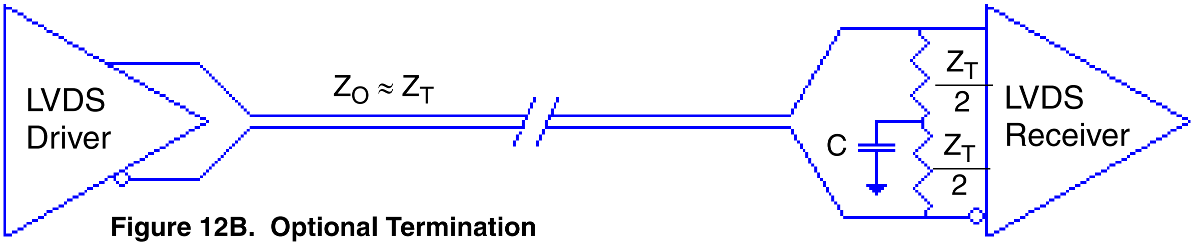


Figure 12B. Optional Termination

Termination for 3.3V LVPECL Outputs

The clock layout topology shown below is a typical termination for LVPECL outputs. The two different layouts mentioned are recommended only as guidelines.

The differential outputs generate ECL/LVPECL compatible outputs. Therefore, terminating resistors (DC current path to ground) or current sources must be used for functionality. These outputs are designed to drive 50Ω transmission lines. Matched impedance techniques should be used to maximize operating frequency and minimize signal distortion. *Figure 13A* and *Figure 13B* show two different layouts which are recommended only as guidelines. Other suitable clock layouts may exist and it would be recommended that the board designers simulate to guarantee compatibility across all printed circuit and clock component process variations.

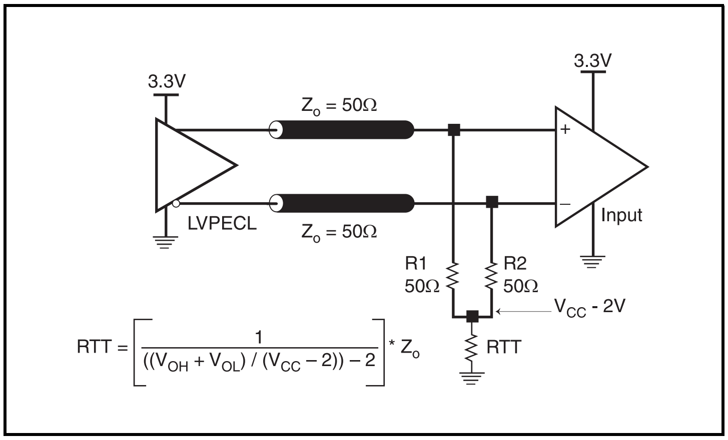


Figure 13A. 3.3V LVPECL Output Termination

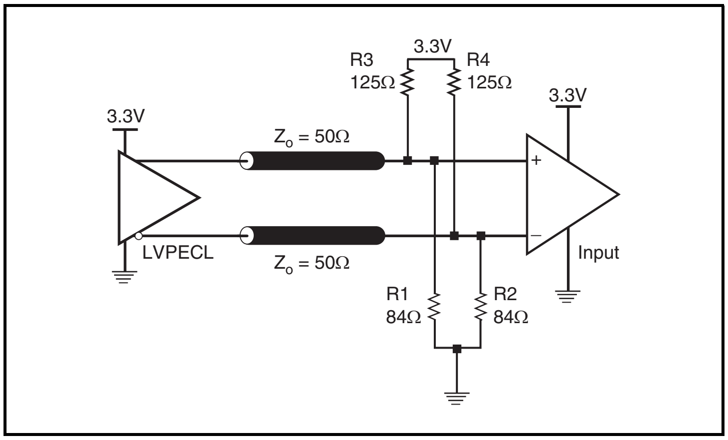


Figure 13B. 3.3V LVPECL Output Termination

Termination for 2.5V LVPECL Outputs

Figure 14A and *Figure 14C* show examples of termination for 2.5V LVPECL driver. These terminations are equivalent to terminating 50Ω to V_{CCO} – 2V. For V_{CCO} = 2.5V, the V_{CCO} – 2V is very close to ground level. The R3 in *Figure 14C* can be eliminated and the termination is shown in *Figure 14B.*

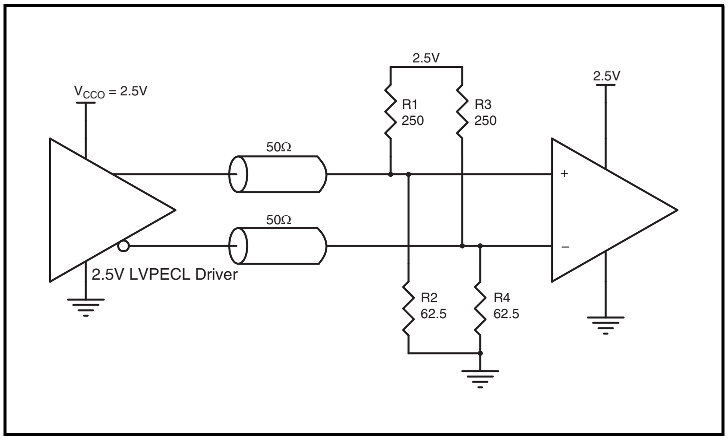


Figure 14A. 2.5V LVPECL Driver Termination Example

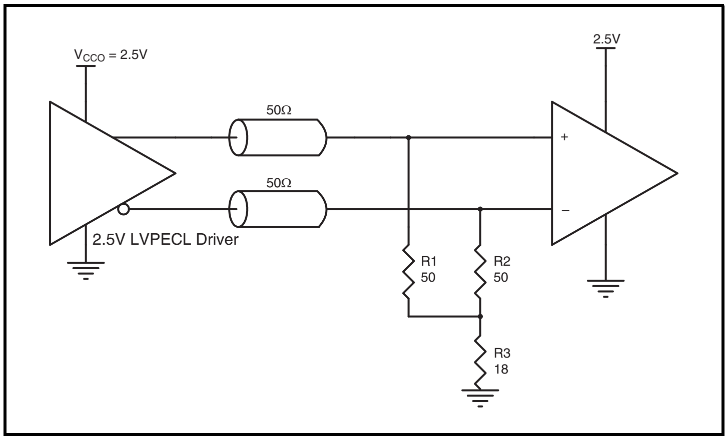


Figure 14C. 2.5V LVPECL Driver Termination Example

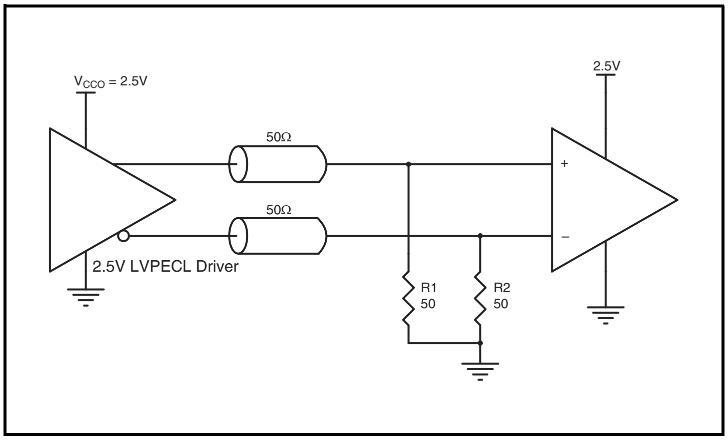


Figure 14B. 2.5V LVPECL Driver Termination Example

VFQFN EPAD Thermal Release Path

In order to maximize both the removal of heat from the package and the electrical performance, a land pattern must be incorporated on the Printed Circuit Board (PCB) within the footprint of the package corresponding to the exposed metal pad or exposed heat slug on the package, as shown in *Figure 15*. The solderable area on the PCB, as defined by the solder mask, should be at least the same size/shape as the exposed pad/slug area on the package to maximize the thermal/electrical performance. Sufficient clearance should be designed on the PCB between the outer edges of the land pattern and the inner edges of pad pattern for the leads to avoid any shorts.

While the land pattern on the PCB provides a means of heat transfer and electrical grounding from the package to the board through a solder joint, thermal vias are necessary to effectively conduct from the surface of the PCB to the ground plane(s). The land pattern must be connected to ground through these vias. The vias act as "heat pipes". The number of vias (i.e. "heat pipes") are application specific and dependent upon the package power dissipation as well as electrical conductivity requirements. Thus, thermal and electrical analysis and/or testing are recommended to determine the minimum number needed. Maximum thermal and electrical performance is achieved when an array of vias is incorporated in the land pattern. It is recommended to use as many vias connected to ground as possible. It is also recommended that the via diameter should be 12 to 13mils (0.30 to 0.33mm) with 1oz copper via barrel plating. This is desirable to avoid any solder wicking inside the via during the soldering process which may result in voids in solder between the exposed pad/slug and the thermal land. Precautions should be taken to eliminate any solder voids between the exposed heat slug and the land pattern. Note: These recommendations are to be used as a guideline only. For further information, please refer to the Application Note on the Surface Mount Assembly of Amkor's Thermally/ Electrically Enhance Lead frame Base Package, Amkor Technology.

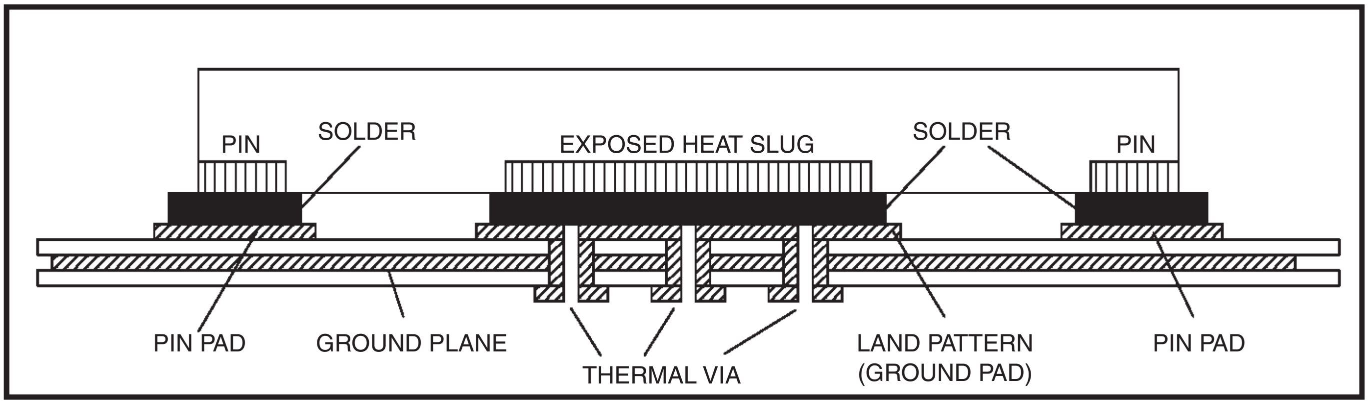


Figure 15. P.C. Assembly for Exposed Pad Thermal Release Path – Side View (drawing not to scale)

Schematic and Layout Information

Schematics for IDT8T49N282I can be found on IDT.com. Please search for the IDT8T49N282I device and click on the link for evaluation board schematics.

Crystal Recommendation

This device was characterized using FOX 277LF series through-hole crystals including part #277LF-40-18 (40MHz) and 277LF-38.88-2 (38.88MHz). If a surface mount crystal is desired, the FOX FX325BS series of crystals may be used, such as part #603-40-48 (40MHz) or 603-38.88-7 (38.88MHz).

I^{2}C Serial EEPROM Recommendation

The IDT8T49N282I was designed to operate with most standard I^{2}C serial EEPROMs of 256 bytes or larger. Atmel AT24C04C was used during device characterization and is recommended for use. Please contact IDT for review of any other I^{2}C EEPROM's compatibility with the IDT8T49N282I.

PCI Express Application Note

PCI Express jitter analysis methodology models the system response to reference clock jitter. The block diagram below shows the most frequently used *Common Clock Architecture* in which a copy of the reference clock is provided to both ends of the PCI Express Link.

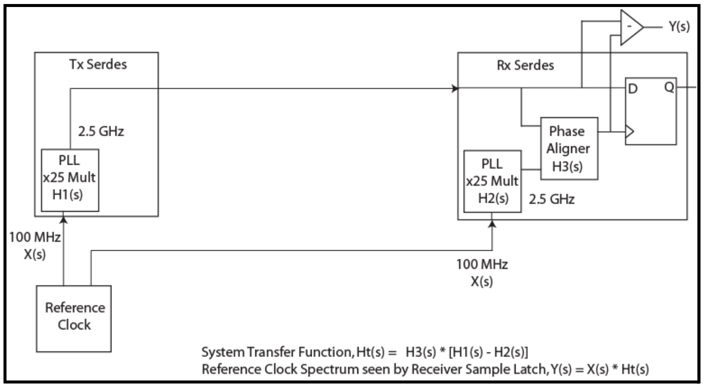
In the jitter analysis, the transmit (Tx) and receive (Rx) serdes PLLs are modeled as well as the phase interpolator in the receiver. These transfer functions are called H1, H2, and H3 respectively. The overall system transfer function at the receiver is:

$$Ht(s) = H3(s) \times [H1(s) - H2(s)]$$

The jitter spectrum seen by the receiver is the result of applying this system transfer function to the clock spectrum X(s) and is:

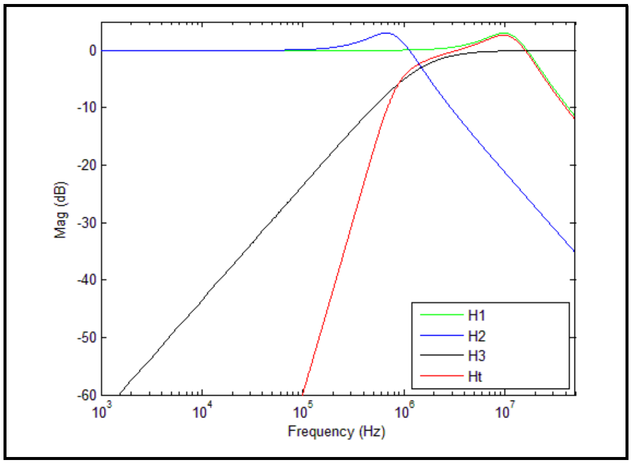
$$Y(s) = X(s) \times H3(s) \times [H1(s) - H2(s)]$$

In order to generate time domain jitter numbers, an inverse Fourier Transform is performed on X(s)*H3(s) * [H1(s) - H2(s)].



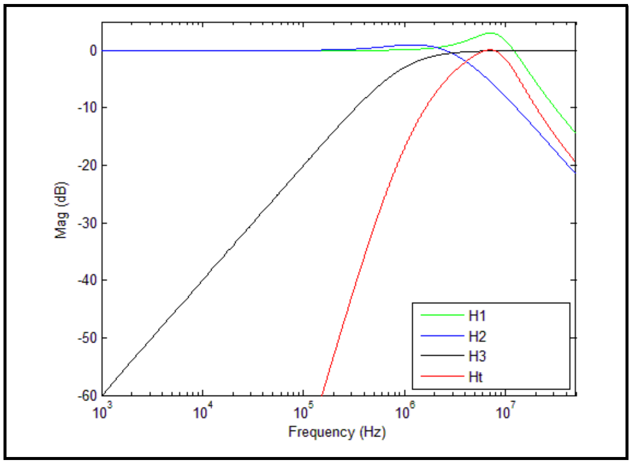
PCI Express Common Clock Architecture

For **PCI Express Gen 1**, one transfer function is defined and the evaluation is performed over the entire spectrum: DC to Nyquist (e.g for a 100MHz reference clock: 0Hz – 50MHz) and the jitter result is reported in peak-peak.

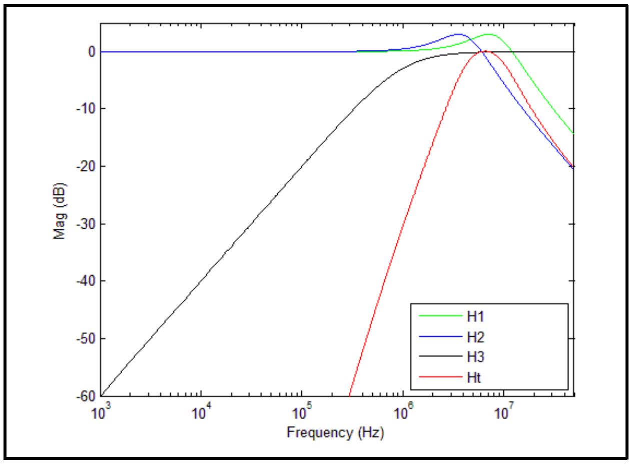


PCIe Gen 1 Magnitude of Transfer Function

For **PCI Express Gen 2**, two transfer functions are defined with 2 evaluation ranges and the final jitter number is reported in rms. The two evaluation ranges for PCI Express Gen 2 are 10kHz – 1.5MHz (Low Band) and 1.5MHz – Nyquist (High Band). The plots show the individual transfer functions as well as the overall transfer function Ht.

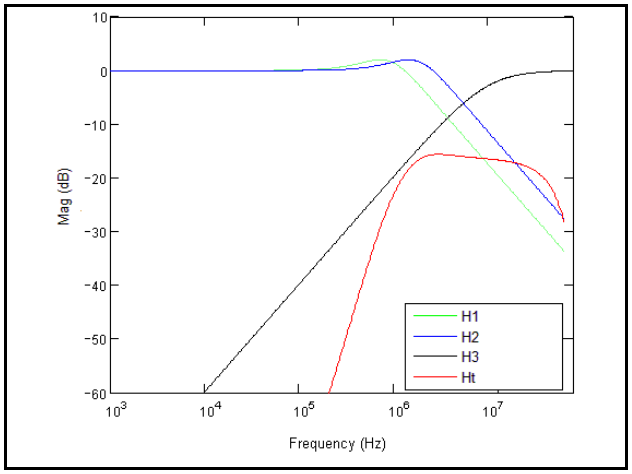


PCIe Gen 2A Magnitude of Transfer Function



PCIe Gen 2B Magnitude of Transfer Function

For **PCI Express Gen 3**, one transfer function is defined and the evaluation is performed over the entire spectrum. The transfer function parameters are different from Gen 1 and the jitter result is reported in RMS.



PCIe Gen 3 Magnitude of Transfer Function

For a more thorough overview of PCI Express jitter analysis methodology, please refer to IDT Application Note *PCI Express Reference Clock Requirements.*

Power Dissipation and Thermal Considerations

The IDT8T49N282I is a multi-functional, high speed device that targets a wide variety of clock frequencies and applications. Since this device is highly programmable with a broad range of features and functionality, the power consumption will vary as each of these features and functions is enabled.

The IDT8T49N282I device was designed and characterized to operate within the ambient industrial temperature range of -40°C to +85°C. The ambient temperature represents the temperature around the device, not the junction temperature. When using the device in extreme cases, such as maximum operating frequency and high ambient temperature, external air flow may be required in order to ensure a safe and reliable junction temperature. Extreme care must be taken to avoid exceeding 125°C junction temperature.

The power calculation examples below were generated using a maximum ambient temperature and supply voltage. For many applications, the power consumption will be much lower. Please contact IDT technical support for any concerns on calculating the power dissipation for your own specific configuration.

Power Domains

The IDT8T49N282I device has a number of separate power domains that can be independently enabled and disabled via register accesses (all power supply pins must still be connected to a valid supply voltage). *Figure 16* below indicates the individual domains and the associated power pins.

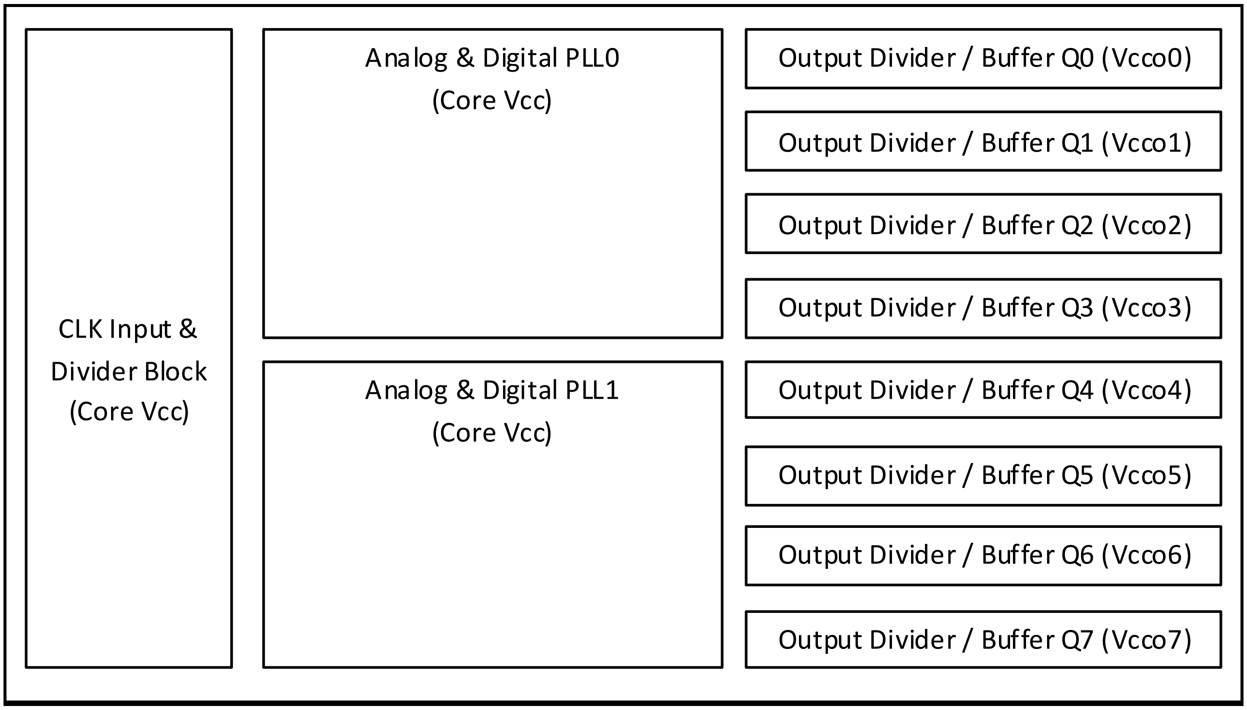


Figure 16. IDT8T49N282I Power Domains

For the output paths shown above, there are three different structures that are used. Q0 and Q1 use one output path structure, Q2 and Q3 use a second structure and Q4 – Q7 use a 3rd structure. Power consumption data will vary slightly depending on the structure used as shown in the appropriate tables below.

Power Consumption Calculation

Determining total power consumption involves several steps:

1. Determine the power consumption using maximum current values for core and analog voltage supplies from Tables 8A and 8B.
2. Determine the nominal power consumption of each enabled output path.
   a. This consists of a base amount of power that is independent of operating frequency, as shown in *Table 16A* through *Table 16G* (depending on the chosen output protocol).
   b. Then there is a variable amount of power that is related to the output frequency. This can be determined by multiplying the output frequency by the FQ_Factor shown in *Table 16A* through *Table 16G*.
3. All of the above totals are then summed.

Thermal Considerations

Once the total power consumption has been determined, it is necessary to calculate the maximum operating junction temperature for the device under the environmental conditions it will operate in. Thermal conduction paths, air flow rate and ambient air temperature are factors that can affect this. The thermal conduction path refers to whether heat is to be conducted away via a heatsink, via airflow or via conduction into the PCB through the device pads (including the ePAD). Thermal conduction data is provided for typical scenarios in *Table 15* below. Please contact IDT for assistance in calculating results under other scenarios.

Table 15. Thermal Resistance θ_{JA} for 72-Lead VFQFN, Forced Convection

θ_{JA} by Velocity			
Meters per Second	**0**	**1**	**2**
Multi-Layer PCB, JEDEC Standard Test Boards	16.1°C/W	12.4°C/W	11.1°C/W

Current Consumption Data and Equations

Table 16A. 3.3V LVPECL Output Calculation Table

LVPECL	FQ_Factor (mA/MHz)	Base_Current (mA)
Q0	0.00624	40.3
Q1		
Q2	0.01445	63.6
Q3		
Q4	0.00609	42.2
Q5		
Q6		
Q7		

Table 16B. 2.5V LVPECL Output Calculation Table

LVPECL	FQ_Factor (mA/MHz)	Base_Current (mA)
Q0	0.00409	33.0
Q1		
Q2	0.01179	56.4
Q3		
Q4	0.00369	35.4
Q5		
Q6		
Q7		

Table 16C. 3.3V LVDS Output Calculation Table

LVDS	FQ_Factor (mA/MHz)	Base_Current (mA)
Q0	0.00664	49.6
Q1		
Q2	0.01479	73.0
Q3		
Q4	0.00646	51.5
Q5		
Q6		
Q7		

Table 16D. 2.5V LVDS Output Calculation Table

LVDS	FQ_Factor (mA/MHz)	Base_Current (mA)
Q0	0.00412	41.9
Q1		
Q2	0.01217	65.3
Q3		
Q4	0.00425	43.6
Q5		
Q6		
Q7		

Table 16E. 3.3V LVCMOS Output Calculation Table

LVCMOS	Base_Current (mA)
Q0	37.5
Q1	
Q2	61.1
Q3	
Q4	40.1
Q5	
Q6	
Q7	

Table 16F. 2.5V LVCMOS Output Calculation Table

LVCMOS	Base_Current (mA)
Q0	31.0
Q1	
Q2	54.6
Q3	
Q4	33.2
Q5	
Q6	
Q7	

Table 16G. 1.8V LVCMOS Output Calculation Table

LVCMOS	Base_Current (mA)
Q0	26.8
Q1	
Q2	50.4
Q3	
Q4	29.0
Q5	
Q6	
Q7	

Applying the values to the following equation will yield output current by frequency:

Qx Current (mA) = FQ_Factor * Frequency (MHz) + Base_Current

where:

Qx Current is the specific output current according to output type and frequency

FQ_Factor is used for calculating current increase due to output frequency

Base_Current is the base current for each output path independent of output frequency

The second step is to multiply the power dissipated by the thermal impedance to determine the maximum power gradient, using the following equation:

$T_J = T_A + (\theta_{JA} * Pd_{total})$

where:

T_J is the junction temperature (°C)

T_A is the ambient temperature (°C)

θ_{JA} is the thermal resistance value from Table 15, dependent on ambient airflow (°C/W)

Pd_{total} is the total power dissipation of the IDT8T49N282I under usage conditions, including power dissipated due to loading (W)

Note that for LVPECL outputs the power dissipation through the load is assumed to be 27.95mW. When selecting LVCMOS outputs, power dissipation through the load will vary based on a variety of factors including termination type and trace length. For these examples, power dissipation through loading will be calculated using C_{PD} (found in *Table 2*) and output frequency:

$Pd_{OUT} = C_{PD} * F_{OUT} * V_{CCO}^2$

where:

Pd_{OUT} is the power dissipation of the output (W)

C_{PD} is the power dissipation capacitance (pF)

F_{OUT} is the output frequency of the selected output (MHz)

V_{CCO} is the voltage supplied to the appropriate output (V)

Example Calculations

Example 1. Common Customer Configuration (3.3V Core Voltage)

Output	Output Type	Frequency (MHz)	V_{CCO}
Q0	LVPECL	245.76	3.3
Q1	LVPECL	245.76	3.3
Q2	LVPECL	33.333	3.3
Q3	LVPECL	33.333	3.3
Q4	LVDS	125	3.3
Q5	LVDS	125	3.3
Q6	LVCMOS	25	3.3
Q7	LVCMOS	25	3.3
PLL0	Enabled		
PLL1	Enabled		

- Core Supply Current, I_{CC} = **100mA (max)**
- Analog Supply Current, I_{CCA} = **265mA (max)**

  Q0 Current = 0.00624x245.76 + 40.3 = 41.83mA

  Q1 Current = 0.00624x245.76 + 40.3 = 41.83mA

  Q2 Current = 0.01445x33.333 + 63.6 = 64.08mA

  Q3 Current = 0.01445x33.333 + 63.6 = 64.08mA

  Q4 Current = 0.00646x125 + 51.5 = 52.3mA

  Q5 Current = 0.00646x125 + 51.5 = 52.3mA

  Q6 Current = 40.1mA

  Q7 Current = 40.1mA

- Total Output Current = **396.62mA (max)**

  Total Device Current = 100mA + 265mA + 396.6mA = **761.6mA**

  Total Device Power = 3.465V * 761.6mA = **2639mW**

- Power dissipated through output loading:

  LVPECL = 27.95mW * 4 = **111.8mW**

  LVDS = already accounted for in device power

  LVCMOS = 14.5pF * 25MHz * 3.465V^2 * 2 output pairs = **8.7mW**

- Total Power = 2639mW + 111.8mW + 8.7mW = **2759.5mW or 2.76W**

With an ambient temperature of 85°C and no airflow, the junction temperature is:

T_J = 85°C + 16.1°C/W * 2.76W = **129.4°C**

This junction temperature is above the maximum allowable. In instances where maximum junction temperature is exceeded adjustments need to be made to either airflow or ambient temperature. In this case, adjusting airflow to 1m/s (θ_{JA} = 12.4°C/W) will reduce junction temperature to 119.2°C. If no airflow adjustments can be made, the maximum ambient operating temperature must be reduced by a minimum of 4.4°C.

Example 2. High-Frequency Customer Configuration (3.3V Core Voltage)

Output	Output Type	Frequency (MHz)	V_{CCO}
Q0	LVDS	625.00	2.5
Q1	LVDS	625.00	2.5
Q2	LVPECL	161.133	2.5
Q3	LVPECL	161.133	2.5
Q4	LVDS	25	3.3
Q5	LVDS	25	3.3
Q6	LVPECL	125	2.5
Q7	LVDS	156.25	2.5
PLL0	Enabled		
PLL1	Disabled		

- Core Supply Current, I_{CC} = **100mA (max)**
- Analog Supply Current, I_{CCA} = **187mA (max, PLL0 path only)**

  Q0 Current = 0.00412x625 + 41.9 = 44.48mA

  Q1 Current = 0.00412x625 + 41.9 = 44.48mA

  Q2 Current = 0.01179x161.133 + 56.4 = 58.3mA

  Q3 Current = 0.01179x161.133 + 56.4 = 58.3mA

  Q4 Current = 0.00646x25 + 51.5 = 51.66mA

  Q5 Current = 0.00646x25 + 51.5 = 51.66mA

  Q6 Current = 0.00369x125 + 35.4 = 35.86mA

  Q7 Current = 0.00425x156.25 + 43.6 = 44.26mA

- Total Output Current = **285.68mA** (V_{CCO} = 2.5V), **103.3mA** (V_{CCO} = 3.3V)

  Total Device Power = 3.465V *(100mA + 187mA + 103.3mA) + 2.625V * 285.68mA = **2102.3mW**

- Power dissipated through output loading:

  LVPECL = 27.95mW * 3 = **83.9mW**

  LVDS = already accounted for in device power

  LVCMOS = n/a

  Total Power = 2102.3mW + 83.9mW = **2186.2mW or 2.19W**

With an ambient temperature of 85°C, the junction temperature is:

T_J = 85°C + 16.1°C/W *2.19W = **120.3°C**

This junction temperature is below the maximum allowable.

Example 3. Low Power Customer Configuration (2.5V Core Voltage)

Output	Output Type	Frequency (MHz)	V_{CCO}
Q0	LVDS	156.25	2.5
Q1	LVDS	156.25	2.5
Q2	LVDS	161.133	2.5
Q3	LVCMOS	33.333	1.8
Q4	LVCMOS	25	1.8
Q5	LVCMOS	25	1.8
Q6	LVCMOS	25	1.8
Q7	LVDS	156.25	2.5
PLL0	Enabled		
PLL1	Enabled		

- Core Supply Current, I_{CC} = **95mA (max)**
- Analog Supply Current, I_{CCA} = **260mA (max)**

  Q0 Current = 0.00412x156.25 + 41.9 = 42.54mA

  Q1 Current = 0.00412x156.25 + 41.9 = 42.54mA

  Q2 Current = 0.01217x161.133 + 65.3 = 67.26mA

  Q3 Current = 50.4mA

  Q4 Current = 29mA

  Q5 Current = 29mA

  Q6 Current = 29mA

  Q7 Current = 0.00425x156.25 + 43.6 = 44.26mA

- Total Output Current = **196.6mA** (V_{CCO} = 2.5V), **137.4mA** (V_{CCO} = 1.8V)

  Total Device Power = 2.625V *(95mA + 260mA + 196.6mA) + 1.89V * 137.4mA = **1707.6mW**

- Power dissipated through output loading:

  LVPECL = n/a

  LVDS = already accounted for in device power

  LVCMOS_33.3MHz = 17pF * 33.3MHz * 1.89V^2 * 1 output pair = **2.02mW**

  LVCMOS_25MHz = 12.5pF * 25MHz * 1.89V^2 * 3 output pairs = **3.35mW**

  Total Power = 1707.6mW + 2.02mW + 3.35mW = **1713mW or 1.7W**

With an ambient temperature of 85°C, the junction temperature is:

T_J = 85°C + 16.1°C/W *1.7W = **112.4°C**

This junction temperature is below the maximum allowable.

Reliability Information

Table 17. θ_{JA} vs. Air Flow Table for a 72-Lead VFQFN

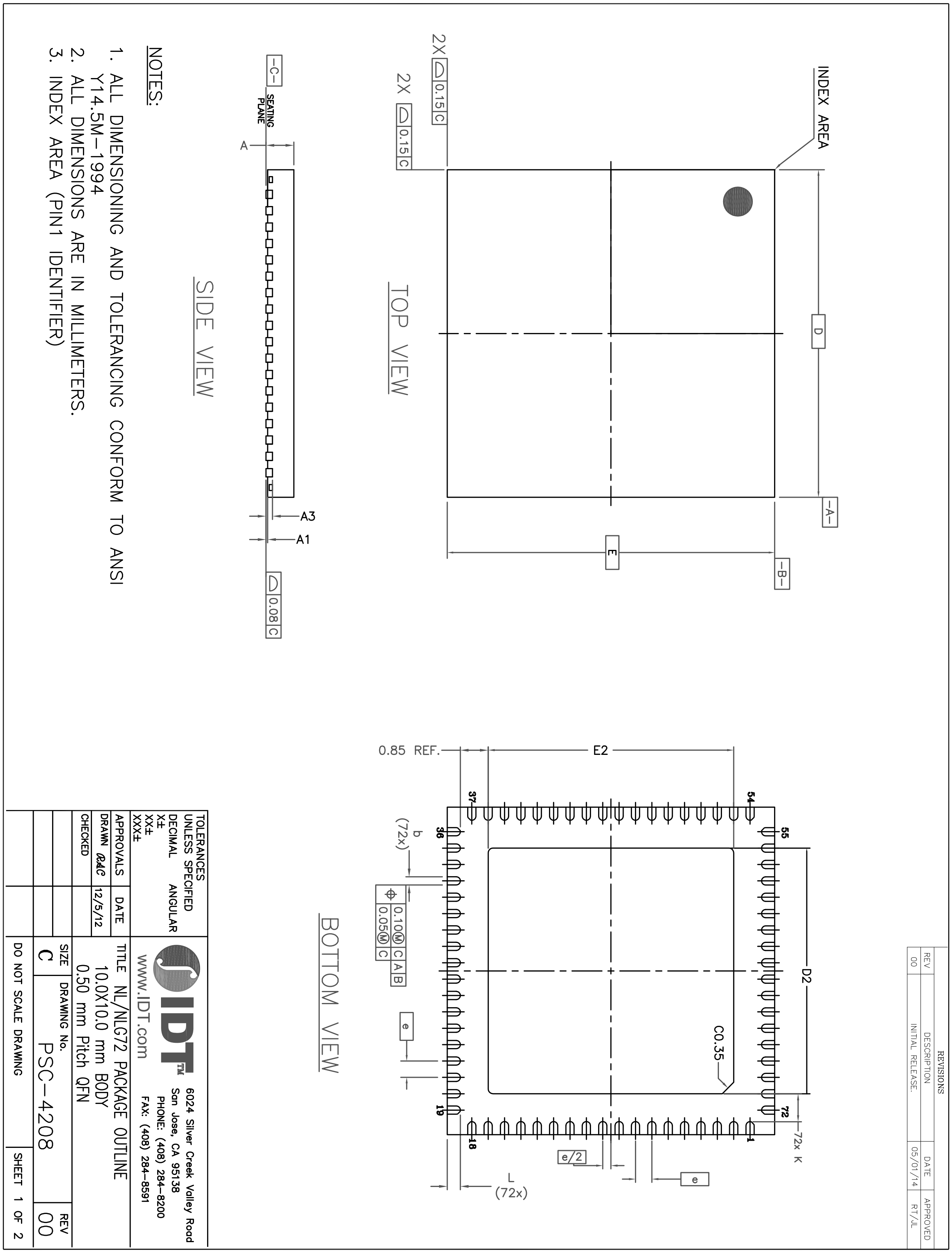
θ_{JA} vs. Air Flow			
Meters per Second	**0**	**1**	**2**
Multi-Layer PCB, JEDEC Standard Test Boards	16.1°C/W	12.4°C/W	11.1°C/W

NOTE: Theta JA (θ_{JA})values calculated using a 4-layer JEDEC PCB (114.3mm x 101.6mm), with 2oz. (70um) copper plating on all 4 layers.

Transistor Count

The transistor count for IDT8T49N282I is: 959,346

72-Lead VFQFN Package Outline



NOTES:

1. ALL DIMENSIONING AND TOLERANCING CONFORM TO ANSI Y14.5M-1994
2. ALL DIMENSIONS ARE IN MILLIMETERS.
3. INDEX AREA (PIN1 IDENTIFIER)

TOLERANCES UNLESS SPECIFIED
DECIMAL ANGULAR
X±
XX±
XXX±

APPROVALS	DATE
DRAWN RAC	12/5/12
CHECKED	

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TITLE NL/NLG72 PACKAGE OUTLINE
10.0X10.0 mm BODY
0.50 mm Pitch QFN

SIZE C DRAWING No. PSC-4208 REV 00

DO NOT SCALE DRAWING SHEET 1 OF 2

REVISIONS

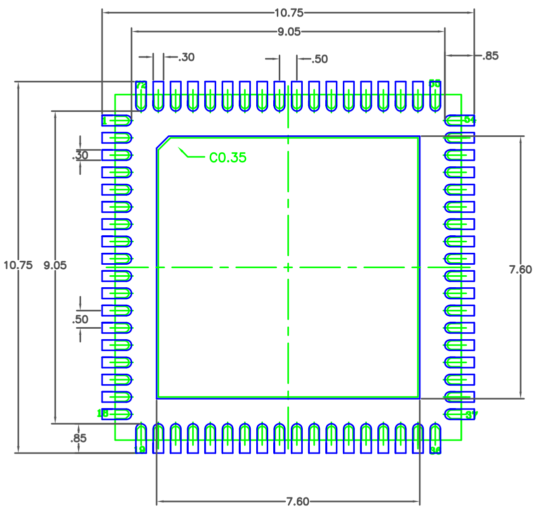
REV	DESCRIPTION	DATE	APPROVED
00	INITIAL RELEASE.	05/01/14	RT/JL

72-Lead VFQFN Package Outline, continued

REVISIONS			
REV	DESCRIPTION	DATE	APPROVED
00	INITIAL RELEASE.	05/01/14	RT/JL

SYMBOL	DIMENSION			NOTE
	MIN.	NOM.	MAX.	
A	0.80	0.90	1.00	
A1	0	0.02	0.05	
A3 REF	–	0.20 ref	–	
b	0.18	0.25	0.30	
e		0.50 BSC		
D2	7.40	7.50	7.60	
E2	7.40	7.50	7.60	
D		10.00 BSC		
E		10.00 BSC		
K	0.20	–	–	
L	0.30	0.40	0.50	

RECOMMENDED LAND PATTERN



P2 EPAD 7.5 mm SQ

NOTES:

1. ALL DIMENSION ARE IN mm. ANGLES IN DEGREES.
2. TOP DOWN VIEW. AS VIEWED ON PCB.
3. COMPONENT OUTLINE SHOW FOR REFERENCE IN GREEN.
4. LAND PATTERN IN BLUE. NSMD PATTERN ASSUMED.
5. LAND PATTERN RECOMMENDATION PER IPC-7351B GENERIC REQUIREMENT FOR SURFACE MOUNT DESIGN AND LAND PATTERN.

TOLERANCES
UNLESS SPECIFIED
DECIMAL ANGULAR
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XXX±
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DRAWN RAC	12/5/12
CHECKED	

TITLE NL/NLG72 PACKAGE OUTLINE
10.0 X 10.0 mm BODY
0.50 mm Pitch QFN

SIZE	DRAWING No.	REV
C	PSC-4208	00

DO NOT SCALE DRAWING
SHEET 2 OF 2

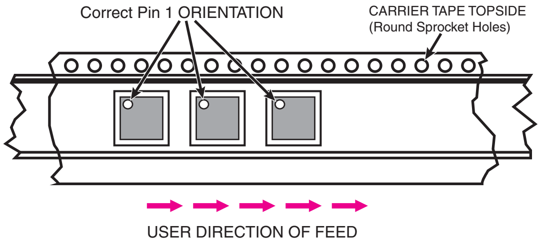
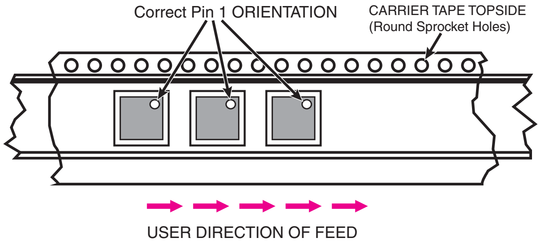
Ordering Information

Table 18. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
8T49N282B-dddNLGI	IDT8T49N282B-dddNLGI	"Lead-Free" 72-Lead VFQFN	Tray	-40°C to +85°C
8T49N282B-dddNLGI8	IDT8T49N282B-dddNLGI	"Lead-Free" 72-Lead VFQFN	Tape & Reel, Pin 1 Orientation: EIA-481-C	-40°C to +85°C
8T49N282B-dddNLGI#	IDT8T49N282B-dddNLGI	"Lead-Free" 72-Lead VFQFN	Tape & Reel, Pin 1 Orientation: EIA-481-D	-40°C to +85°C

NOTE: For the specific -ddd order codes, refer to *FemtoClock NG Universal Frequency Translator Ordering Product Information* document.

Table 19. Pin 1 Orientation in Tape and Reel Packaging

Part Number Suffix	Pin 1 Orientation	Illustration
NLGI8	Quadrant 1 (EIA-481-C)	
NLGI#	Quadrant 2 (EIA-481-D)	

ERRATA

Errata # 1: EEPROM CRC Check Failure

Errata: if the UFT++ attempts to load its initial configuration from an external EEPROM and the CRC check fails, the serial port will not complete write operations and will only respond to reads with values of 0 until device is reset via nRST pin.
- if no EEPROM access is attempted, no EEPROM is found or the EEPROM read succeeds there are no issues
- The CRC failure condition can be detected by reading the Global Interrupt Status Register at address 21Fh. If the nEEP_CRC bit is low, then the device's serial port is now in the failed state
- if the device is also programmed to load its registers from the internal One-Time Programmable memory, those register settings will be correctly loaded and used.

Work-Around: by reading the nEEP_CRC bit, this condition can be detected. Once detected, the user may attempt to retry the EEPROM load operation by asserting then releasing the nRST input pin. If the retry attempt continues to fail, then no further recovery is possible. Note that a persistent EEPROM CRC failure indicates a corrupted configuration is present and the device could not be correctly configured anyway.

Fix Plan: None

Errata # 2: GPIOs Can't Use Input Mode if V_{CCO} = 1.8V

Errata: When the V_{CCO} pin adjacent to a GPIO pin is set to 1.8V and the core V_{CC} of the chip is at 3.3V, the
GPIO pin will not behave as an input, either a General-Purpose Input or an Output Enable. Mappings are according to the following relationships
GPIO0 / V_{CCO3}
GPIO1 / V_{CCO3}
GPIO2 / V_{CCO4}
GPIO3 / V_{CCO7}
GPIO4 / V_{CCO4}
GPIO5 / V_{CCO5}
GPIO6 / V_{CCO6}
GPIO7 / V_{CCO7}

Work-Around: Ensure that voltage used on V_{CCO} pins is no less than V_{CC} - 1.6V.
Fix Plan: None

Revision History Sheet

Rev	Table	Page	Description of Change	Date
B		1	Applications - updated bullets.	3/5/14
		1	Features - added *Power Down Mode bullet.*	
		2	Deleted *Compliance section.*	
	T9A	54	3.3V Power Supply Table - added test condition to original I_{CCA} spec. Added second spec to I_{CCA}. Updated Note 2.	
	T9B	55	2.5V Power Supply Table - added test condition to original I_{CCA} spec. Added second spec to I_{CCA}. Updated Note 2.	
	T10A	56	Renumbered Tables starting with Table 9D, and changed to Table 10A.	
		75	Applications Information, Crystal Recommendation Note - updated Fox part numbers.	
		77 - 82	Revised *Power Dissipation and Thermal Considerations section.*	
B		5	Move Pin Assignment from page 9 to page 5.	3/7/14
		71 - 72	Fixed package drawings on page.	
B		4-76	Renumbered figures with the Block Diagram as Figure 1.	4/17/14
	T2	8	Added NOTE 1 to C_{IN}.	
		14	General-Purpose I/Os & Interrupts section: replaced '0x006E' and '0x0076' with '006Eh' and '0076h'.	
			General-Purpose I/Os & Interrupts section: added last paragraph.	
			SPI Mode Operation: replaced text (3 paragraphs).	
		15	Figure 1: replaced figure.	
			Figure 1 Title: replaced text ‘SPI Read Timing Diagram’ with ‘SPI Read Sequencing Diagram’.	
			Figure 2: replaced figure.	
			Figure 3: replaced figure.	
		16	Figure 4: replaced figure.	
			I^{2}C Master Mode, 3rd bullet: replaced '0xE0' with 'E0h'.	
		18	I^{2}C Master Mode, 4th bullet: replaced '0x05' with '05h'.	
			Text section; replaced '0xE0' with 'E0h'. and ‘0x006’ with ‘006h’.	
		19	I^{2}C Boot-up Initialization Mode, second paragraph; replaced “The BOOTFAIL bit in the Status Control register will also be set in this event.” with “The BOOTFAIL bit (021Eh) in the Global Interrupt Status register will also be set in this event”.	
			EEPROM Offset (Hex) column; deleted ‘0x’ of 0x## (15 instances).	
	T6	19	Table Header: deleted ‘(Binary)’ from ‘Default Value”.	
	T7B–T8D	21–52	Replaced values formatting for Default Value column.	
	T7B–T8D	21–52	Outputs, V_O (Q[0:7], nQ[0:7]): Changed V_{CCO} to V_{CCOX}.	
	T-AMR	53	Outputs, V_O (GPIO, SDATA, SCLK, nINT): changed GPIO to GPIO[0:7].	
			Added Note: NOTE: V_{CCOX} denotes V_{CCO0}, V_{CCO1}, V_{CCO2}, V_{CCO3}, V_{CCO4}, V_{CCO5}, V_{CCO6}, V_{CCO7}.	
			Table Header: Changed V_{CCOX} to V_{CC}.	
	T9C	54	ERRATA; 1st paragraph; replaced '0x21F' with '21Fh'.	
	90			
B		7	Second column, last paragraph; replaced last sentence.	6/3/14
		10	Output Phase Alignment; replaced fourth paragraph.	
			Second column, first bullet; changed “VCO period (TVCO)” to “source clock period”. Changed “1 x TVCO” to “250ps”.	
		10	LVCMOS operation; replaced last sentence.	
		16-17	Corrected typo “Femto NG” to FemtoClock NG” (4 places).	
	T7C	17	REV_ID[3:0], fixed typo in default value “00010b” to “0010b”.	
	T7D	17	UFTADD[6:2]; replaced description.	
	T7D	17	UFTADD[1], changed Default Value from “-” to “0b”. Replaced description.	
	T7D	17	UFTADD[0], changed Default Value from “-” to “0b”. Replaced description.	
	T7M	33	00AB row, replaced “Rsvd” with “10” for D7:D6 and D5:D4.	
	T13A-13B	49	Replaced “tjit(θ)” with “tjit(ϕ)”.	
		52	Replaced XTAL_IN and XTAL_OUT with OSCI and OSCO respectively.	
	E2	65	Changed Q6 Frequency to 125MHz. Changed Q4, Q5 V_{CCO} to 3.3V. Updated calculations.	
		68-69	Updated Package Outline drawings.	
	T18	70	Ordering Information; added pin orientation info.	
	T19	70	Added Pin 1 Orientation table.	
		73	Updated Contact Information	

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